

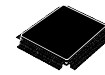


# STM32F105xx STM32F107xx

Connectivity line, ARM-based 32-bit MCU with 64/256 KB Flash, USB OTG, Ethernet, 10 timers, 2 CANs, 2 ADCs, 14 communication interfaces

## Features

- Core: ARM 32-bit Cortex™-M3 CPU
  - 72 MHz maximum frequency, 1.25 DMIPS/MHz (Dhrystone 2.1) performance at 0 wait state memory access
  - Single-cycle multiplication and hardware division
- Memories
  - 64 to 256 Kbytes of Flash memory
  - up to 64 Kbytes of general-purpose SRAM
- Clock, reset and supply management
  - 2.0 to 3.6 V application supply and I/Os
  - POR, PDR, and programmable voltage detector (PVD)
  - 3-to-25 MHz crystal oscillator
  - Internal 8 MHz factory-trimmed RC
  - Internal 40 kHz RC with calibration
  - 32 kHz oscillator for RTC with calibration
- Low power
  - Sleep, Stop and Standby modes
  - V<sub>BAT</sub> supply for RTC and backup registers
- 2 × 12-bit, 1 μs A/D converters (16 channels)
  - Conversion range: 0 to 3.6 V
  - Sample and hold capability
  - Temperature sensor
  - up to 2 MSPS in interleaved mode
- 2 × 12-bit D/A converters
- DMA: 12-channel DMA controller
  - Supported peripherals: timers, ADCs, DAC, I<sup>2</sup>Ss, SPIs, I<sup>2</sup>Cs and USARTs
- Debug mode
  - Serial wire debug (SWD) & JTAG interfaces
  - Cortex-M3 Embedded Trace Macrocell™
- Up to 80 fast I/O ports
  - 51/80 I/Os, all mappable on 16 external interrupt vectors and almost all 5 V-tolerant
- CRC calculation unit, 96-bit unique ID



LQFP100 14 × 14 mm  
LQFP64 10 × 10 mm

- Up to 10 timers with pinout remap capability
  - Up to four 16-bit timers, each with up to 4 IC/OC/PWM or pulse counter and quadrature (incremental) encoder input
  - 1 × 16-bit motor control PWM timer with dead-time generation and emergency stop
  - 2 × watchdog timers (Independent and Window)
  - SysTick timer: a 24-bit downcounter
  - 2 × 16-bit basic timers to drive the DAC
- Up to 14 communication interfaces with pinout remap capability
  - Up to 2 × I<sup>2</sup>C interfaces (SMBus/PMBus)
  - Up to 5 USARTs (ISO 7816 interface, LIN, IrDA capability, modem control)
  - Up to 3 SPIs (18 Mbit/s), 2 with a multiplexed I<sup>2</sup>S interface that offers audio class accuracy via advanced PLL schemes
  - 2 × CAN interfaces (2.0B Active) with 512 bytes of dedicated SRAM
  - USB 2.0 full-speed device/host/OTG controller with on-chip PHY that supports HNP/SRP/ID with 1.25 Kbytes of dedicated SRAM
  - 10/100 Ethernet MAC with dedicated DMA and SRAM (4 Kbytes): IEEE1588 hardware support, MII/RMII available on all packages

Table 1. Device summary

| Reference   | Part number  |
|-------------|--|
| STM32F105xx | STM32F105R8, STM32F105V8<br>STM32F105RB, STM32F105VB<br>STM32F105RC, STM32F105VC |
| STM32F107xx | STM32F107RB, STM32F107VB<br>STM32F107RC, STM32F107VC                             |

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# 1 Introduction

This datasheet provides the description of the STM32F105xx and STM32F107xx connectivity line microcontrollers. For more details on the whole STMicroelectronics STM32F10xxx family, please refer to [Section 2.2: Full compatibility throughout the family](#).

The STM32F105xx and STM32F107xx datasheet should be read in conjunction with the STM32F10xxx reference manual.

For information on programming, erasing and protection of the internal Flash memory please refer to the STM32F10xxx Flash programming manual.

The reference and Flash programming manuals are both available from the STMicroelectronics website [www.st.com](http://www.st.com).

For information on the Cortex™-M3 core please refer to the Cortex™-M3 Technical Reference Manual, available from the [www.arm.com](http://www.arm.com) website at the following address: <http://infocenter.arm.com/help/index.jsp?topic=/com.arm.doc.ddi0337e/>.



# 2 Description

The STM32F105xx and STM32F107xx connectivity line family incorporates the high-performance ARM® Cortex™-M3 32-bit RISC core operating at a 72 MHz frequency, high-speed embedded memories (Flash memory up to 256 Kbytes and SRAM up to 64 Kbytes), and an extensive range of enhanced I/Os and peripherals connected to two APB buses. All devices offer two 12-bit ADCs, four general-purpose 16-bit timers plus a PWM timer, as well as standard and advanced communication interfaces: up to two I<sup>2</sup>Cs, three SPIs, two I2Ss, five USARTs, an USB OTG FS and two CANs. Ethernet is available on the STM32F107xx only.

The STM32F105xx and STM32F107xx connectivity line family operates in the –40 to +105 °C temperature range, from a 2.0 to 3.6 V power supply. A comprehensive set of power-saving mode allows the design of low-power applications.

The STM32F105xx and STM32F107xx connectivity line family offers devices in two different package types: from 64 pins to 100 pins. Depending on the device chosen, different sets of peripherals are included, the description below gives an overview of the complete range of peripherals proposed in this family.

These features make the STM32F105xx and STM32F107xx connectivity line microcontroller family suitable for a wide range of applications:

- Motor drive and application control
- Medical and handheld equipment
- Industrial applications: PLC, inverters, printers, and scanners
- Alarm systems, Video intercom, and HVAC
- Home audio equipment

[Figure 1](#) shows the general block diagram of the device family.

## 2.1 Device overview

**Table 2. STM32F105xx and STM32F107xx features and peripheral counts**

| Peripherals <sup>(1)</sup> |                                      | STM32F105Rx   |     |     | STM32F107Rx |     | STM32F105Vx |     |     | STM32F107Vx |     |
|----------------------------|--------------------------------------|---|-----|-----|-------------|-----|-------------|-----|-----|-------------|-----|
| Flash memory in Kbytes     |                                      | 64  | 128 | 256 | 128         | 256 | 64          | 128 | 256 | 128         | 256 |
| SRAM in Kbytes             |                                      | 20  | 32  | 64  | 48          | 64  | 20          | 32  | 64  | 48          | 64  |
| Ethernet                   |                                      | No  |     |     | Yes         |     | No          |     |     | Yes         |     |
| Timers                     | General-purpose                      | 4   |     |     |             |     |             |     |     |             |     |
|                            | Advanced-control                     | 1   |     |     |             |     |             |     |     |             |     |
|                            | Basic                                | 2   |     |     |             |     |             |     |     |             |     |
| Communication interfaces   | SPI(I <sup>2</sup> S) <sup>(2)</sup> | 3(2)  |     |     | 3(2)        |     | 3(2)        |     |     | 3(2)        |     |
|                            | I <sup>2</sup> C                     | 2   |     |     | 1           |     | 2           |     |     | 1           |     |
|                            | USART                                | 5   |     |     |             |     |             |     |     |             |     |
|                            | USB OTG FS                           | Yes   |     |     |             |     |             |     |     |             |     |
|                            | CAN                                  | 2   |     |     |             |     |             |     |     |             |     |
| GPIOs                      |                                      | 51  |     |     |             |     | 80          |     |     |             |     |
| 12-bit ADC                 |                                      | 2   |     |     |             |     |             |     |     |             |     |
| Number of channels         |                                      | 16  |     |     |             |     |             |     |     |             |     |
| 12-bit DAC                 |                                      | 2   |     |     |             |     |             |     |     |             |     |
| Number of channels         |                                      | 2   |     |     |             |     |             |     |     |             |     |
| CPU frequency              |                                      | 72 MHz  |     |     |             |     |             |     |     |             |     |
| Operating voltage          |                                      | 2.0 to 3.6 V  |     |     |             |     |             |     |     |             |     |
| Operating temperatures     |                                      | Ambient temperatures: –40 to +85 °C / –40 to +105 °C<br>Junction temperature: –40 to + 125 °C |     |     |             |     |             |     |     |             |     |
| Package                    |                                      | LQFP64  |     |     |             |     | LQFP100     |     |     |             |     |

1. Please refer to [Table 5: Pin definitions](#) for peripheral availability when the I/O pins are shared by the peripherals required by the application.

2. The SPI2 and SPI3 interfaces give the flexibility to work in either the SPI mode or the I<sup>2</sup>S audio mode.

## 2.2 Full compatibility throughout the family

The STM32F105xx and STM32F107xx constitute the connectivity line family whose members are fully pin-to-pin, software and feature compatible.

The STM32F105xx and STM32F107xx are a drop-in replacement for the low-density (STM32F103x4/6), medium-density (STM32F103x8/B) and high-density (STM32F103xC/D/E) performance line devices, allowing the user to try different memory densities and peripherals providing a greater degree of freedom during the development cycle.

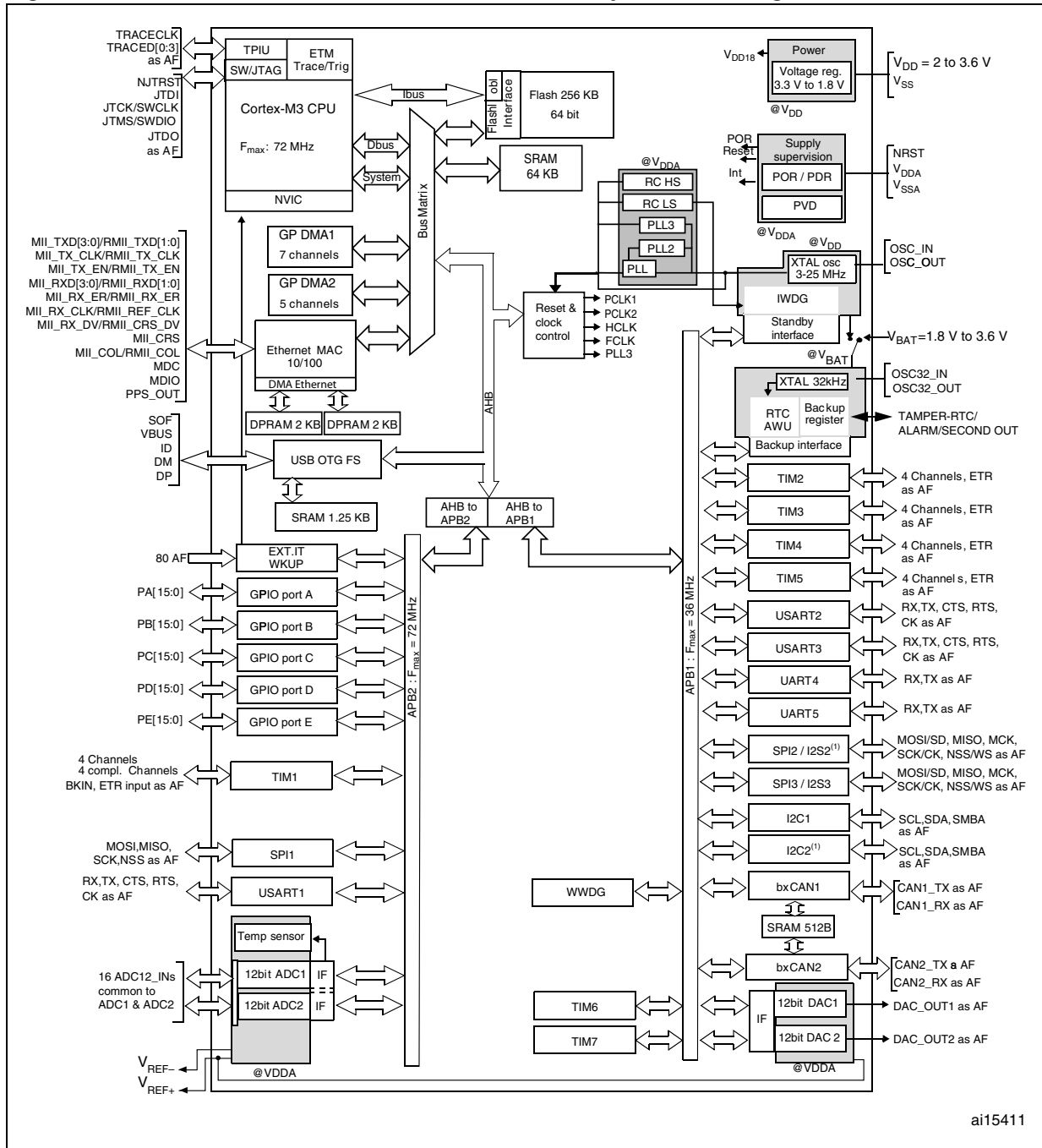
**Table 3. STM32F105xx and STM32F107xx family versus STM32F103xx family<sup>(1)</sup>**

| STM32 device    | Low-density STM32F103xx devices  |    | Medium-density STM32F103xx devices   |    |     | High-density STM32F103xx devices  |     |     | STM32F105xx  |     |     | STM32F107xx  |     |  |   |  |
|-----------------|--|----|--|----|-----|---|-----|-----|--|-----|-----|--|-----|--|---|--|
|                 | 16   | 32 | 32   | 64 | 128 | 256   | 384 | 512 | 64   | 128 | 256 | 128  | 256 |  |   |  |
| Flash size (KB) | 16   | 32 | 32   | 64 | 128 | 256   | 384 | 512 | 64   | 128 | 256 | 128  | 256 |  |   |  |
| RAM size (KB)   | 6  | 10 | 10   | 20 | 20  | 48  | 64  | 64  | 20   | 32  | 64  | 48   | 64  |  |   |  |
| 144 pins        |  |    |  |    |     |   |     |     |  |     |     |  |     |  |   |  |
| 100 pins        |  |    |  |    |     |   |     |     |  |     |     |  |     |  |   |  |
| 64 pins         | 2 × USARTs<br>2 × 16-bit timers<br>1 × SPI, 1 × I <sup>2</sup> C, USB, CAN,<br>1 × PWM timer<br>2 × ADCs |    | 2 × USARTs<br>2 × 16-bit timers<br>1 × SPI,<br>1 × I <sup>2</sup> C,<br>USB, CAN,<br>1 × PWM timer<br>2 × ADCs |    |     | 3 × USARTs<br>3 × 16-bit timers<br>2 × SPIs,<br>2 × I <sup>2</sup> Cs, USB, CAN,<br>1 × PWM timer<br>2 × ADCs |     |     | 5 × USARTs<br>4 × 16-bit timers,<br>2 × basic timers, 3 × SPIs,<br>2 × I <sup>2</sup> Ss, 2 × I <sup>2</sup> Cs, USB, CAN, 2 × PWM timers<br>3 × ADCs, 2 × DACs,<br>1 × SDIO, FSMC (100- and 144-pin packages <sup>(2)</sup> ) |     |     | 5 × USARTs,<br>4 × 16-bit timers,<br>2 × basic timers,<br>3 × SPIs,<br>2 × I <sup>2</sup> Ss,<br>2 × I <sup>2</sup> Cs,<br>USB OTG FS,<br>2 × CANs,<br>1 × PWM timer,<br>2 × ADCs,<br>2 × DACs |     |  | 5 × USARTs,<br>4 × 16-bit timers,<br>2 × basic timers,<br>3 × SPIs,<br>2 × I <sup>2</sup> S,<br>1 × I <sup>2</sup> C,<br>USB OTG FS,<br>2 × CANs,<br>1 × PWM timer,<br>2 × ADCs,<br>2 × DACs,<br>Ethernet |  |
| 48 pins         |  |    |  |    |     |   |     |     |  |     |     |  |     |  |   |  |
| 36 pins         |  |    |  |    |     |   |     |     |  |     |     |  |     |  |   |  |

1. Please refer to [Table 5: Pin definitions](#) for peripheral availability when the I/O pins are shared by the peripherals required by the application.
2. Ports F and G are not available in devices delivered in 100-pin packages.

## 2.3 Overview

Figure 1. STM32F105xx and STM32F107xx connectivity line block diagram



1.  $T_A = -40\text{ }^\circ\text{C}$  to  $+85\text{ }^\circ\text{C}$  (suffix 6, see [Table 60](#)) or  $-40\text{ }^\circ\text{C}$  to  $+105\text{ }^\circ\text{C}$  (suffix 7, see [Table 60](#)), junction temperature up to  $105\text{ }^\circ\text{C}$  or  $125\text{ }^\circ\text{C}$ , respectively.
2. AF = alternate function on I/O port pin.

### 2.3.1 ARM® Cortex™-M3 core with embedded Flash and SRAM

The ARM Cortex™-M3 processor is the latest generation of ARM processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM Cortex™-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

With its embedded ARM core, STM32F105xx and STM32F107xx connectivity line family is compatible with all ARM tools and software.

*Figure 1* shows the general block diagram of the device family.

### 2.3.2 Embedded Flash memory

64 to 256 Kbytes of embedded Flash is available for storing programs and data.

### 2.3.3 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

### 2.3.4 Embedded SRAM

20 to 64 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states.

### 2.3.5 Nested vectored interrupt controller (NVIC)

The STM32F105xx and STM32F107xx connectivity line embeds a nested vectored interrupt controller able to handle up to 67 maskable interrupt channels (not including the 16 interrupt lines of Cortex™-M3) and 16 priority levels.

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of *late arriving* higher priority interrupts
- Support for tail-chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimal interrupt latency.

### 2.3.6 External interrupt/event controller (EXTI)

The external interrupt/event controller consists of 20 edge detector lines used to generate interrupt/event requests. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the Internal APB2 clock period. Up to 80 GPIOs can be connected to the 16 external interrupt lines.

### 2.3.7 Clocks and startup

System clock selection is performed on startup, however, the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 3-25 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example with failure of an indirectly used external oscillator).

A single 25 MHz crystal can clock the entire system including the ethernet and USB OTG FS peripherals. Several prescalers and PLLs allow the configuration of the AHB frequency, the high speed APB (APB2) and the low speed APB (APB1) domains. The maximum frequency of the AHB and the high speed APB domains is 72 MHz. The maximum allowed frequency of the low speed APB domain is 36 MHz. Refer to [Figure 48: USB OTG FS + Ethernet solution on page 89](#).

The advanced clock controller clocks the core and all peripherals using a single crystal or oscillator. In order to achieve audio class performance, an audio crystal can be used. In this case, the I<sup>2</sup>S master clock can generate all standard sampling frequencies from 8 kHz to 96 kHz with less than 0.5% accuracy error. Refer to [Figure 49: USB OTG FS + I<sup>2</sup>S \(Audio\) solution on page 89](#).

To configure the PLLs, please refer to [Table 61 on page 90](#), which provides PLL configurations according to the application type.

### 2.3.8 Boot modes

At startup, boot pins are used to select one of three boot options:

- Boot from User Flash
- Boot from System Memory
- Boot from embedded SRAM

The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART1, USART2 (remapped), CAN2 (remapped) or USB OTG FS in device mode (DFU: device firmware upgrade). For remapped signals refer to [Table 5: Pin definitions](#).

The USART peripheral operates with the internal 8 MHz oscillator (HSI), however the CAN and USB OTG FS can only function if an external 8 MHz, 14.7456 MHz or 25 MHz clock (HSE) is present.

For full details about the boot loader, please refer to AN2662.

### 2.3.9 Power supply schemes

- $V_{DD} = 2.0$  to  $3.6$  V: external power supply for I/Os and the internal regulator. Provided externally through  $V_{DD}$  pins.
- $V_{SSA}$ ,  $V_{DDA} = 2.0$  to  $3.6$  V: external analog power supplies for ADC, Reset blocks, RCs and PLL (minimum voltage to be applied to  $V_{DDA}$  is  $2.4$  V when the ADC is used).  $V_{DDA}$  and  $V_{SSA}$  must be connected to  $V_{DD}$  and  $V_{SS}$ , respectively.
- $V_{BAT} = 1.8$  to  $3.6$  V: power supply for RTC, external clock  $32$  kHz oscillator and backup registers (through power switch) when  $V_{DD}$  is not present.

### 2.3.10 Power supply supervisor

The device has an integrated power-on reset (POR)/power-down reset (PDR) circuitry. It is always active, and ensures proper operation starting from/down to  $2$  V. The device remains in reset mode when  $V_{DD}$  is below a specified threshold,  $V_{POR/PDR}$ , without the need for an external reset circuit.

The device features an embedded programmable voltage detector (PVD) that monitors the  $V_{DD}/V_{DDA}$  power supply and compares it to the  $V_{PVD}$  threshold. An interrupt can be generated when  $V_{DD}/V_{DDA}$  drops below the  $V_{PVD}$  threshold and/or when  $V_{DD}/V_{DDA}$  is higher than the  $V_{PVD}$  threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

### 2.3.11 Voltage regulator

The regulator has three operation modes: main (MR), low power (LPR) and power down.

- MR is used in the nominal regulation mode (Run)
- LPR is used in the Stop modes.
- Power down is used in Standby mode: the regulator output is in high impedance: the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost)

This regulator is always enabled after reset. It is disabled in Standby mode.

### 2.3.12 Low-power modes

The STM32F105xx and STM32F107xx connectivity line supports three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**  
In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.
- **Stop mode**  
Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the  $1.8$  V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.  
The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the  $16$  external lines, the PVD output, the RTC alarm or the USB OTG FS wakeup.

- **Standby mode**

The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

*Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.*

### 2.3.13 DMA

The flexible 12-channel general-purpose DMAs (7 channels for DMA1 and 5 channels for DMA2) are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. The two DMA controllers support circular buffer management, removing the need for user code intervention when the controller reaches the end of the buffer.

Each channel is connected to dedicated hardware DMA requests, with support for software trigger on each channel. Configuration is made by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI, I<sup>2</sup>C, USART, general-purpose, basic and advanced control timers TIMx, DAC, I<sup>2</sup>S and ADC.

In the STM32F107xx, there is a DMA controller dedicated for use with the Ethernet (see [Section 2.3.20: Ethernet MAC interface with dedicated DMA and IEEE 1588 support](#) for more information).

### 2.3.14 RTC (real-time clock) and backup registers

The RTC and the backup registers are supplied through a switch that takes power either on V<sub>DD</sub> supply when present or through the V<sub>BAT</sub> pin. The backup registers are forty-two 16-bit registers used to store 84 bytes of user application data when V<sub>DD</sub> power is not present. They are not reset by a system or power reset, and they are not reset when the device wakes up from the Standby mode.

The real-time clock provides a set of continuously running counters which can be used with suitable software to provide a clock calendar function, and provides an alarm interrupt and a periodic interrupt. It is clocked by a 32.768 kHz external crystal, resonator or oscillator, the internal low power RC oscillator or the high-speed external clock divided by 128. The internal low-speed RC has a typical frequency of 40 kHz. The RTC can be calibrated using an external 512 Hz output to compensate for any natural quartz deviation. The RTC features a 32-bit programmable counter for long term measurement using the Compare register to generate an alarm. A 20-bit prescaler is used for the time base clock and is by default configured to generate a time base of 1 second from a clock at 32.768 kHz.

For more information, please refer to AN2604: “*STM32F101xx and STM32F103xx RTC calibration*”, available from [www.st.com](http://www.st.com).



### 2.3.15 Timers and watchdogs

The STM32F105xx and STM32F107xx devices include an advanced-control timer, four general-purpose timers, two basic timers, two watchdog timers and a SysTick timer.

[Table 4](#) compares the features of the general-purpose and basic timers.

**Table 4. Timer feature comparison**

| Timer                         | Counter resolution | Counter type      | Prescaler factor                | DMA request generation | Capture/compare channels | Complementary outputs |
|-------------------------------|--------------------|-------------------|---------------------------------|------------------------|--------------------------|-----------------------|
| TIM1                          | 16-bit             | Up, down, up/down | Any integer between 1 and 65536 | Yes                    | 4                        | Yes                   |
| TIMx (TIM2, TIM3, TIM4, TIM5) | 16-bit             | Up, down, up/down | Any integer between 1 and 65536 | Yes                    | 4                        | No                    |
| TIM6, TIM7                    | 16-bit             | Up                | Any integer between 1 and 65536 | Yes                    | 0                        | No                    |

#### Advanced-control timer (TIM1)

The advanced control timer (TIM1) can be seen as a three-phase PWM multiplexed on 6 channels. It has complementary PWM outputs with programmable inserted dead-times. It can also be seen as a complete general-purpose timer. The 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (edge or center-aligned modes)
- One-pulse mode output

If configured as a standard 16-bit timer, it has the same features as the TIMx timer. If configured as the 16-bit PWM generator, it has full modulation capability (0-100%).

The counter can be frozen in debug mode.

Many features are shared with those of the standard TIM timers which have the same architecture. The advanced control timer can therefore work together with the TIM timers via the Timer Link feature for synchronization or event chaining.

#### General-purpose timers (TIMx)

There are up to 4 synchronizable standard timers (TIM2, TIM3, TIM4 and TIM5) embedded in the STM32F105xx and STM32F107xx connectivity line devices. These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture/output compare, PWM or one pulse mode output. This gives up to 16 input captures / output compares / PWMs on the largest packages. They can work together with the Advanced Control timer via the Timer Link feature for synchronization or event chaining.

The counter can be frozen in debug mode.

Any of the standard timers can be used to generate PWM outputs. Each of the timers has independent DMA request generations.

### Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger generation. They can also be used as a generic 16-bit time base.

### Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

### Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

### SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

## 2.3.16 I<sup>2</sup>C bus

Up to two I<sup>2</sup>C bus interfaces can operate in multimaster and slave modes. They can support standard and fast modes.

They support 7/10-bit addressing mode and 7-bit dual addressing mode (as slave). A hardware CRC generation/verification is embedded.

They can be served by DMA and they support SMBus 2.0/PMBus.

## 2.3.17 Universal synchronous/asynchronous receiver transmitters (USARTs)

The STM32F105xx and STM32F107xx connectivity line embeds three universal synchronous/asynchronous receiver transmitters (USART1, USART2 and USART3) and two universal asynchronous receiver transmitters (UART4 and UART5).

These five interfaces provide asynchronous communication, IrDA SIR ENDEC support, multiprocessor communication mode, single-wire half-duplex communication mode and have LIN Master/Slave capability.

The USART1 interface is able to communicate at speeds of up to 4.5 Mbit/s. The other available interfaces communicate at up to 2.25 Mbit/s.

USART1, USART2 and USART3 also provide hardware management of the CTS and RTS signals, Smart Card mode (ISO 7816 compliant) and SPI-like communication capability. All interfaces can be served by the DMA controller except for UART5.

### 2.3.18 Serial peripheral interface (SPI)

Up to three SPIs are able to communicate up to 18 Mbits/s in slave and master modes in full-duplex and simplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC/SDHC<sup>(a)</sup> modes.

All SPIs can be served by the DMA controller.

### 2.3.19 Inter-integrated sound (I<sup>2</sup>S)

Two standard I<sup>2</sup>S interfaces (multiplexed with SPI2 and SPI3) are available, that can be operated in master or slave mode. These interfaces can be configured to operate with 16/32 bit resolution, as input or output channels. Audio sampling frequencies from 8 kHz up to 96 kHz are supported. When either or both of the I<sup>2</sup>S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency with less than 0.5% accuracy error owing to the advanced clock controller (see [Section 2.3.7: Clocks and startup](#)).

Please refer to the “Audio frequency precision” tables provided in the “Serial peripheral interface (SPI)” section of the STM32F10xxx reference manual.

### 2.3.20 Ethernet MAC interface with dedicated DMA and IEEE 1588 support

Peripheral not available on STM32F105xx devices.

The STM32F107xx devices provide an IEEE-802.3-2002-compliant media access controller (MAC) for ethernet LAN communications through an industry-standard media-independent interface (MII) or a reduced media-independent interface (RMII). The STM32F107xx requires an external physical interface device (PHY) to connect to the physical LAN bus (twisted-pair, fiber, etc.). the PHY is connected to the STM32F107xx MII port using as many as 17 signals (MII) or 9 signals (RMII) and can be clocked using the 25 MHz (MII) or 50 MHz (RMII) output from the STM32F107xx.

The STM32F107xx includes the following features:

- Supports 10 and 100 Mbit/s rates
- Dedicated DMA controller allowing high-speed transfers between the dedicated SRAM and the descriptors (see the STM32F105xx/STM32F107xx reference manual for details)
- Tagged MAC frame support (VLAN support)
- Half-duplex (CSMA/CD) and full-duplex operation
- MAC control sublayer (control frames) support

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a. SDHC = Secure digital high capacity.

- 32-bit CRC generation and removal
- Several address filtering modes for physical and multicast address (multicast and group addresses)
- 32-bit status code for each transmitted or received frame
- Internal FIFOs to buffer transmit and receive frames. The transmit FIFO and the receive FIFO are both 2 Kbytes, that is 4 Kbytes in total
- Supports hardware PTP (precision time protocol) in accordance with IEEE 1588 with the timestamp comparator connected to the TIM2 trigger input
- Triggers interrupt when system time becomes greater than target time

### 2.3.21 Controller area network (CAN)

The two CANs are compliant with the 2.0A and B (active) specifications with a bitrate up to 1 Mbit/s. They can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers. Each CAN has three transmit mailboxes, two receive FIFOs with 3 stages and 28 shared scalable filter banks (all of them can be used even if one CAN is used). The 256 bytes of SRAM which are allocated for each CAN (512 bytes in total) are not shared with any other peripheral.

### 2.3.22 Universal serial bus on-the-go full-speed (USB OTG FS)

The STM32F105xx and STM32F107xx connectivity line devices embed a USB OTG full-speed (12 Mb/s) device/host/OTG peripheral with integrated transceivers. The USB OTG FS peripheral is compliant with the USB 2.0 specification and with the OTG 1.0 specification. It has software-configurable endpoint setting and supports suspend/resume. The USB OTG full-speed controller requires a dedicated 48 MHz clock that is generated by a PLL connected to the HSE oscillator. The major features are:

- 1.25 KB of SRAM used exclusively by the endpoints (not shared with any other peripheral)
- 4 bidirectional endpoints
- HNP/SNP/IP inside (no need for any external resistor)
- for OTG/Host modes, a power switch is needed in case bus-powered devices are connected
- the SOF output can be used to synchronize the external audio DAC clock in isochronous mode
- in accordance with the USB 2.0 Specification, the supported transfer speeds are:
  - in Host mode: full speed and low speed
  - in Device mode: full speed

### 2.3.23 GPIOs (general-purpose inputs/outputs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high current-capable except for analog inputs.

The I/Os alternate function configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

I/Os on APB2 with up to 18 MHz toggling speed

### 2.3.24 Remap capability

This feature allows the use of a maximum number of peripherals in a given application. Indeed, alternate functions are available not only on the default pins but also on other specific pins onto which they are remappable. This has the advantage of making board design and port usage much more flexible.

For details refer to [Table 5: Pin definitions](#); it shows the list of remappable alternate functions and the pins onto which they can be remapped. See the STM32F10xxx reference manual for software considerations.

### 2.3.25 ADCs (analog-to-digital converters)

Two 12-bit analog-to-digital converters are embedded into STM32F105xx and STM32F107xx connectivity line devices and each ADC shares up to 16 external channels, performing conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

Additional logic functions embedded in the ADC interface allow:

- Simultaneous sample and hold
- Interleaved sample and hold
- Single shunt

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

The events generated by the standard timers (TIMx) and the advanced-control timer (TIM1) can be internally connected to the ADC start trigger and injection trigger, respectively, to allow the application to synchronize A/D conversion and timers.

### 2.3.26 DAC (digital-to-analog converter)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in inverting configuration.

This dual digital Interface supports the following features:

- two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- left or right data alignment in 12-bit mode
- synchronized update capability
- noise-wave generation
- triangular-wave generation
- dual DAC channel independent or simultaneous conversions
- DMA capability for each channel
- external triggers for conversion
- input voltage reference  $V_{REF+}$

Eight DAC trigger inputs are used in the STM32F105xx and STM32F107xx connectivity line family. The DAC channels are triggered through the timer update outputs that are also connected to different DMA channels.

### 2.3.27 Temperature sensor

The temperature sensor has to generate a voltage that varies linearly with temperature. The conversion range is between  $2\text{ V} < V_{\text{DDA}} < 3.6\text{ V}$ . The temperature sensor is internally connected to the ADC1\_IN16 input channel which is used to convert the sensor output voltage into a digital value.

### 2.3.28 Serial wire JTAG debug port (SWJ-DP)

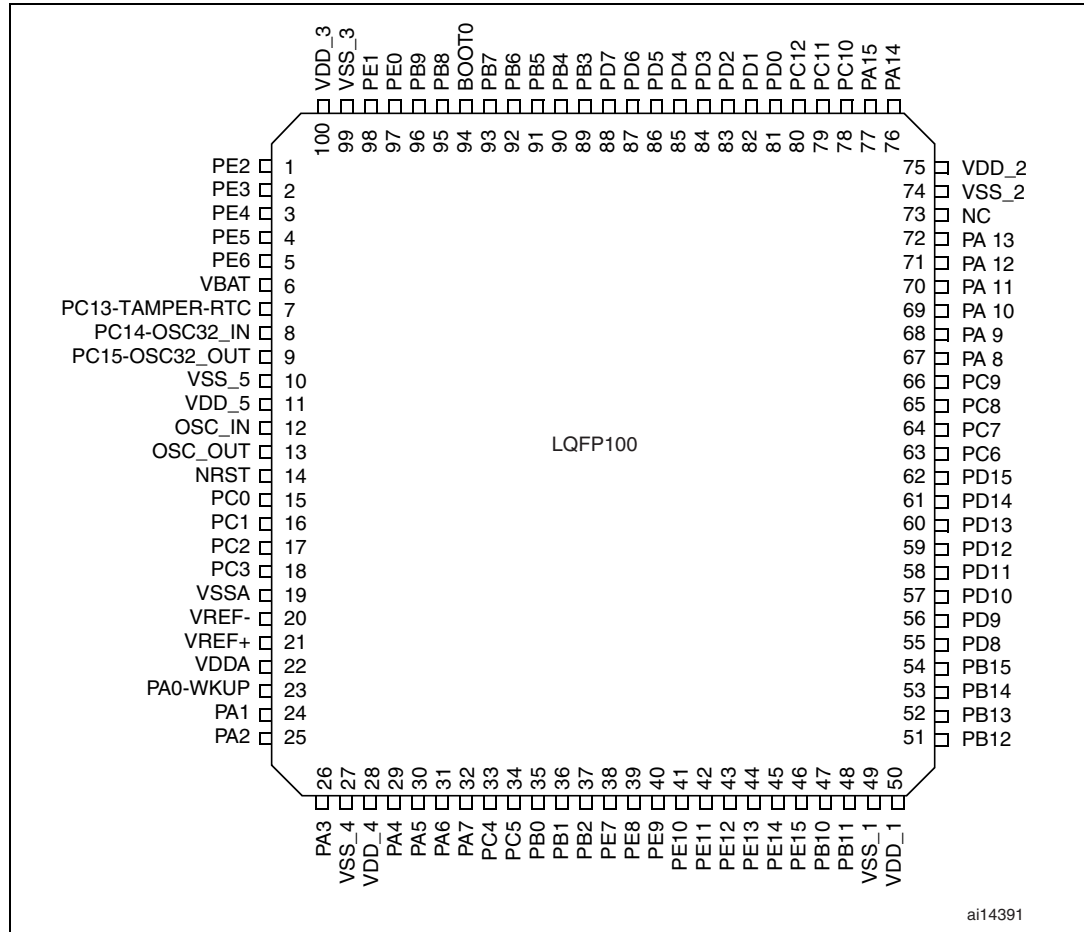
The ARM SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target. The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

### 2.3.29 Embedded Trace Macrocell™

The ARM® Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F10xxx through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer running debugger software. TPA hardware is commercially available from common development tool vendors. It operates with third party debugger software tools.

### 3 Pinouts and pin description

Figure 2. STM32F105xxx and STM32F107xxx connectivity line LQFP100 pinout



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Figure 3. STM32F105xxx and STM32F107xxx connectivity line LQFP64 pinout

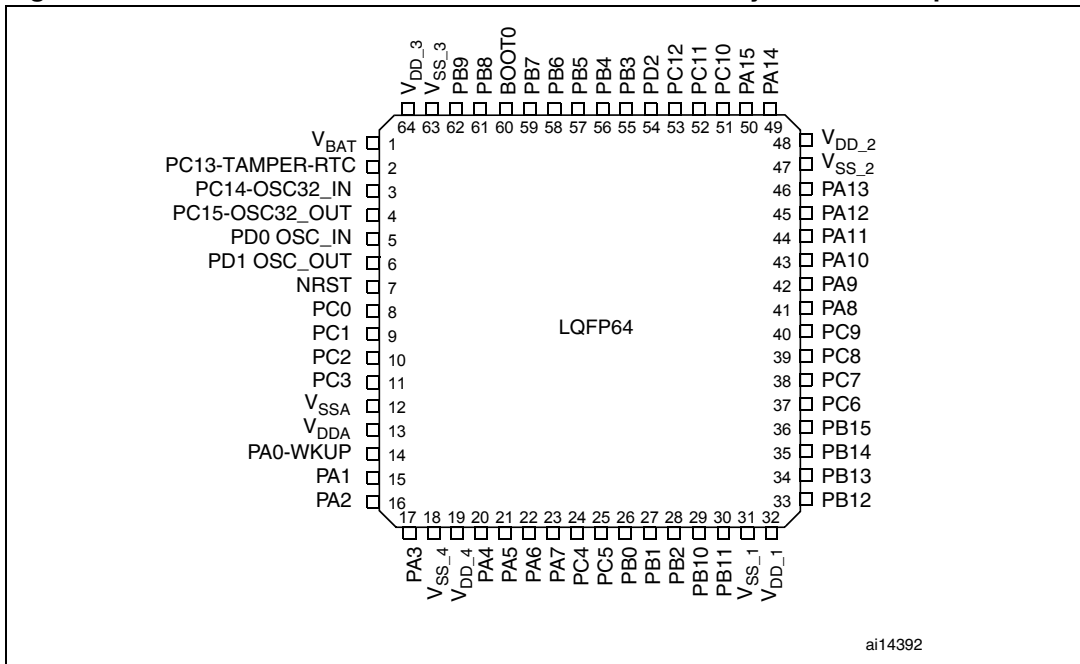




Table 5. Pin definitions

| Pins    |        | Pin name                       | Type <sup>(1)</sup> | I/O level <sup>(2)</sup> | Main function <sup>(3)</sup><br>(after reset) | Alternate functions <sup>(4)</sup>   |       |
|---------|--------|--------------------------------|---------------------|--------------------------|---|--|-------|
| LQFP100 | LQFP64 |                                |                     |                          |   | Default  | Remap |
| 1       | -      | PE2                            | I/O                 | FT                       | PE2   | TRACECK  |       |
| 2       | -      | PE3                            | I/O                 | FT                       | PE3   | TRACED0  |       |
| 3       | -      | PE4                            | I/O                 | FT                       | PE4   | TRACED1  |       |
| 4       | -      | PE5                            | I/O                 | FT                       | PE5   | TRACED2  |       |
| 5       | -      | PE6                            | I/O                 | FT                       | PE6   | TRACED3  |       |
| 6       | 1      | V <sub>BAT</sub>               | S                   |                          | V <sub>BAT</sub>                              |  |       |
| 7       | 2      | PC13-TAMPER-RTC <sup>(5)</sup> | I/O                 |                          | PC13 <sup>(6)</sup>                           | TAMPER-RTC   |       |
| 8       | 3      | PC14-OSC32_IN <sup>(5)</sup>   | I/O                 |                          | PC14 <sup>(6)</sup>                           | OSC32_IN   |       |
| 9       | 4      | PC15-OSC32_OUT <sup>(5)</sup>  | I/O                 |                          | PC15 <sup>(6)</sup>                           | OSC32_OUT  |       |
| 10      | -      | V <sub>SS_5</sub>              | S                   |                          | V <sub>SS_5</sub>                             |  |       |
| 11      | -      | V <sub>DD_5</sub>              | S                   |                          | V <sub>DD_5</sub>                             |  |       |
| 12      | 5      | OSC_IN                         | I                   |                          | OSC_IN  |  |       |
| 13      | 6      | OSC_OUT                        | O                   |                          | OSC_OUT                                       |  |       |
| 14      | 7      | NRST                           | I/O                 |                          | NRST  |  |       |
| 15      | 8      | PC0                            | I/O                 |                          | PC0   | ADC12_IN10   |       |
| 16      | 9      | PC1                            | I/O                 |                          | PC1   | ADC12_IN11/ ETH_MDC  |       |
| 17      | 10     | PC2                            | I/O                 |                          | PC2   | ADC12_IN12/ ETH_MII_TXD2   |       |
| 18      | 11     | PC3                            | I/O                 |                          | PC3   | ADC12_IN13/ ETH_MII_TX_CLK   |       |
| 19      | 12     | V <sub>SSA</sub>               | S                   |                          | V <sub>SSA</sub>                              |  |       |
| 20      | -      | V <sub>REF-</sub>              | S                   |                          | V <sub>REF-</sub>                             |  |       |
| 21      | -      | V <sub>REF+</sub>              | S                   |                          | V <sub>REF+</sub>                             |  |       |
| 22      | 13     | V <sub>DDA</sub>               | S                   |                          | V <sub>DDA</sub>                              |  |       |
| 23      | 14     | PA0-WKUP                       | I/O                 |                          | PA0   | WKUP/USART2_CTS <sup>(7)</sup><br>ADC12_IN0/TIM2_CH1_ETR<br>TIM5_CH1/<br>ETH_MII_CRS_WKUP                            |       |
| 24      | 15     | PA1                            | I/O                 |                          | PA1   | USART2_RTS <sup>(7)</sup> / ADC12_IN1/<br>TIM5_CH2 /TIM2_CH2 <sup>(7)</sup> /<br>ETH_MII_RX_CLK/<br>ETH_RMII_REF_CLK |       |
| 25      | 16     | PA2                            | I/O                 |                          | PA2   | USART2_TX <sup>(7)</sup> /<br>TIM5_CH3/ADC12_IN2/<br>TIM2_CH3 <sup>(7)</sup> / ETH_MDIO                              |       |

Table 5. Pin definitions (continued)

| Pins    |        | Pin name          | Type <sup>(1)</sup> | I/O level <sup>(2)</sup> | Main function <sup>(3)</sup><br>(after reset) | Alternate functions <sup>(4)</sup>   |           |
|---------|--------|-------------------|---------------------|--------------------------|---|--|-----------|
| LQFP100 | LQFP64 |                   |                     |                          |   | Default  | Remap     |
| 26      | 17     | PA3               | I/O                 |                          | PA3   | USART2_RX <sup>(7)</sup> /<br>TIM5_CH4/ADC12_IN3 /<br>TIM2_CH4 <sup>(7)</sup> / ETH_MII_COL          |           |
| 27      | 18     | V <sub>SS_4</sub> | S                   |                          | V <sub>SS_4</sub>                             |  |           |
| 28      | 19     | V <sub>DD_4</sub> | S                   |                          | V <sub>DD_4</sub>                             |  |           |
| 29      | 20     | PA4               | I/O                 |                          | PA4   | SPI1_NSS <sup>(7)</sup> /DAC_OUT1 /<br>USART2_CK <sup>(7)</sup> / ADC12_IN4                          | SPI3_NSS  |
| 30      | 21     | PA5               | I/O                 |                          | PA5   | SPI1_SCK <sup>(7)</sup> /<br>DAC_OUT2 / ADC12_IN5  |           |
| 31      | 22     | PA6               | I/O                 |                          | PA6   | SPI1_MISO <sup>(7)</sup> /ADC12_IN6 /<br>TIM3_CH1 <sup>(7)</sup>                                     | TIM1_BKIN |
| 32      | 23     | PA7               | I/O                 |                          | PA7   | SPI1_MOSI <sup>(7)</sup> /ADC12_IN7 /<br>TIM3_CH2 <sup>(7)</sup> / ETH_MII_RX_DV/<br>ETH_RMII_CRS_DV | TIM1_CH1N |
| 33      | 24     | PC4               | I/O                 |                          | PC4   | ADC12_IN14 / ETH_MII_RXD0 /<br>ETH_RMII_RXD0   |           |
| 34      | 25     | PC5               | I/O                 |                          | PC5   | ADC12_IN15 / ETH_MII_RXD1 /<br>ETH_RMII_RXD1   |           |
| 35      | 26     | PB0               | I/O                 |                          | PB0   | ADC12_IN8/TIM3_CH3/<br>ETH_MII_RXD2  | TIM1_CH2N |
| 36      | 27     | PB1               | I/O                 |                          | PB1   | ADC12_IN9 / TIM3_CH4 <sup>(7)</sup> /<br>ETH_MII_RXD3  | TIM1_CH3N |
| 37      | 28     | PB2               | I/O                 | FT                       | PB2/BOOT1                                     |  |           |
| 38      | -      | PE7               | I/O                 | FT                       | PE7   |  | TIM1_ETR  |
| 39      | -      | PE8               | I/O                 | FT                       | PE8   |  | TIM1_CH1N |
| 40      | -      | PE9               | I/O                 | FT                       | PE9   |  | TIM1_CH1  |
| 41      | -      | PE10              | I/O                 | FT                       | PE10  |  | TIM1_CH2N |
| 42      | -      | PE11              | I/O                 | FT                       | PE11  |  | TIM1_CH2  |
| 43      | -      | PE12              | I/O                 | FT                       | PE12  |  | TIM1_CH3N |
| 44      | -      | PE13              | I/O                 | FT                       | PE13  |  | TIM1_CH3  |
| 45      | -      | PE14              | I/O                 | FT                       | PE14  |  | TIM1_CH4  |
| 46      | -      | PE15              | I/O                 | FT                       | PE15  |  | TIM1_BKIN |
| 47      | 29     | PB10              | I/O                 | FT                       | PB10  | I2C2_SCL/USART3_TX <sup>(7)</sup> /<br>ETH_MII_RX_ER   | TIM2_CH3  |
| 48      | 30     | PB11              | I/O                 | FT                       | PB11  | I2C2_SDA/USART3_RX <sup>(7)</sup> /<br>ETH_MII_TX_EN/<br>ETH_RMII_TX_EN                              | TIM2_CH4  |

Table 5. Pin definitions (continued)

| Pins    |        | Pin name          | Type <sup>(1)</sup> | I/O level <sup>(2)</sup> | Main function <sup>(3)</sup><br>(after reset) | Alternate functions <sup>(4)</sup>   |  |
|---------|--------|-------------------|---------------------|--------------------------|---|--|--|
| LQFP100 | LQFP64 |                   |                     |                          |   | Default  | Remap                                      |
| 49      | 31     | V <sub>SS_1</sub> | S                   |                          | V <sub>SS_1</sub>                             |  |  |
| 50      | 32     | V <sub>DD_1</sub> | S                   |                          | V <sub>DD_1</sub>                             |  |  |
| 51      | 33     | PB12              | I/O                 | FT                       | PB12  | SPI2_NSS/I2S2_WS/<br>I2C2_SMBA / USART3_CK <sup>(7)</sup> /<br>TIM1_BKIN <sup>(7)</sup> / CAN2_RX/<br>ETH_MII_TXD0/<br>ETH_RMII_TXD0 |  |
| 52      | 34     | PB13              | I/O                 | FT                       | PB13  | SPI2_SCK / I2S2_CK /<br>USART3_CTS <sup>(7)</sup> / TIM1_CH1N /<br>CAN2_TX / ETH_MII_TXD1/<br>ETH_RMII_TXD1                          |  |
| 53      | 35     | PB14              | I/O                 | FT                       | PB14  | SPI2_MISO / TIM1_CH2N /<br>USART3_RTS <sup>(7)</sup>   |  |
| 54      | 36     | PB15              | I/O                 | FT                       | PB15  | SPI2_MOSI / I2S2_SD /<br>TIM1_CH3N <sup>(7)</sup>  |  |
| 55      | -      | PD8               | I/O                 | FT                       | PD8   |  | USART3_TX/<br>ETH_MII_RX_DV                |
| 56      | -      | PD9               | I/O                 | FT                       | PD9   |  | USART3_RX/<br>ETH_MII_RX_D0                |
| 57      | -      | PD10              | I/O                 | FT                       | PD10  |  | USART3_CK/<br>ETH_MII_RX_D1                |
| 58      | -      | PD11              | I/O                 | FT                       | PD11  |  | USART3_CTS/<br>ETH_MII_RX_D2               |
| 59      | -      | PD12              | I/O                 | FT                       | PD12  |  | TIM4_CH1 /<br>USART3_RTS/<br>ETH_MII_RX_D3 |
| 60      | -      | PD13              | I/O                 | FT                       | PD13  |  | TIM4_CH2                                   |
| 61      | -      | PD14              | I/O                 | FT                       | PD14  |  | TIM4_CH3                                   |
| 62      | -      | PD15              | I/O                 | FT                       | PD15  |  | TIM4_CH4                                   |
| 63      | 37     | PC6               | I/O                 | FT                       | PC6   | I2S2_MCK/  | TIM3_CH1                                   |
| 64      | 38     | PC7               | I/O                 | FT                       | PC7   | I2S3_MCK   | TIM3_CH2                                   |
| 65      | 39     | PC8               | I/O                 | FT                       | PC8   |  | TIM3_CH3                                   |
| 66      | 40     | PC9               | I/O                 | FT                       | PC9   |  | TIM3_CH4                                   |
| 67      | 41     | PA8               | I/O                 | FT                       | PA8   | USART1_CK/OTG_FS_SOF /<br>TIM1_CH1 <sup>(7)</sup> /MCO   |  |
| 68      | 42     | PA9               | I/O                 | FT                       | PA9   | USART1_TX <sup>(7)</sup> / TIM1_CH2 <sup>(7)</sup> /<br>OTG_FS_VBUS  |  |
| 69      | 43     | PA10              | I/O                 | FT                       | PA10  | USART1_RX <sup>(7)</sup> /<br>TIM1_CH3 <sup>(7)</sup> /OTG_FS_ID   |  |

Table 5. Pin definitions (continued)

| Pins    |        | Pin name          | Type <sup>(1)</sup> | I/O level <sup>(2)</sup> | Main function <sup>(3)</sup><br>(after reset) | Alternate functions <sup>(4)</sup>   |  |  |
|---------|--------|-------------------|---------------------|--------------------------|---|--|--|--|
| LQFP100 | LQFP64 |                   |                     |                          |   | Default  | Remap                                  |  |
| 70      | 44     | PA11              | I/O                 | FT                       | PA11  | USART1_CTS / CAN1_RX /<br>TIM1_CH4 <sup>(7)</sup> /OTG_FS_DM                 |  |  |
| 71      | 45     | PA12              | I/O                 | FT                       | PA12  | USART1_RTS / OTG_FS_DP /<br>CAN1_TX <sup>(7)</sup> / TIM1_ETR <sup>(7)</sup> |  |  |
| 72      | 46     | PA13              | I/O                 | FT                       | JTMS-SWDIO                                    |  | PA13                                   |  |
| 73      | -      | Not connected     |                     |                          |   |  |  |  |
| 74      | 47     | V <sub>SS_2</sub> | S                   |                          | V <sub>SS_2</sub>                             |  |  |  |
| 75      | 48     | V <sub>DD_2</sub> | S                   |                          | V <sub>DD_2</sub>                             |  |  |  |
| 76      | 49     | PA14              | I/O                 | FT                       | JTCK-SWCLK                                    |  | PA14                                   |  |
| 77      | 50     | PA15              | I/O                 | FT                       | JTDI  | SPI3_NSS / I2S3_WS   | TIM2_CH1_ETR / PA15<br>SPI1_NSS        |  |
| 78      | 51     | PC10              | I/O                 | FT                       | PC10  | UART4_TX   | USART3_TX/ SPI3_SCK                    |  |
| 79      | 52     | PC11              | I/O                 | FT                       | PC11  | UART4_RX   | USART3_RX/<br>SPI3_MISO                |  |
| 80      | 53     | PC12              | I/O                 | FT                       | PC12  | UART5_TX   | USART3_CK/<br>SPI3_MOSI                |  |
| 81      | 5      | PD0               | I/O                 | FT                       | OSC_IN <sup>(8)</sup>                         |  | CAN1_RX                                |  |
| 82      | 6      | PD1               | I/O                 | FT                       | OSC_OUT <sup>(8)</sup>                        |  | CAN1_TX                                |  |
| 83      | 54     | PD2               | I/O                 | FT                       | PD2   | TIM3_ETR / UART5_RX  |  |  |
| 84      | -      | PD3               | I/O                 | FT                       | PD3   |  | USART2_CTS                             |  |
| 85      | -      | PD4               | I/O                 | FT                       | PD4   |  | USART2_RTS                             |  |
| 86      | -      | PD5               | I/O                 | FT                       | PD5   |  | USART2_TX                              |  |
| 87      | -      | PD6               | I/O                 | FT                       | PD6   |  | USART2_RX                              |  |
| 88      | -      | PD7               | I/O                 | FT                       | PD7   |  | USART2_CK                              |  |
| 89      | 55     | PB3               | I/O                 | FT                       | JTDO  | SPI3_SCK / I2S3_CK   | PB3 / TRACESWO/<br>TIM2_CH2 / SPI1_SCK |  |
| 90      | 56     | PB4               | I/O                 | FT                       | NJTRST  | SPI3_MISO  | PB4 / TIM3_CH1/<br>SPI1_MISO           |  |
| 91      | 57     | PB5               | I/O                 |                          | PB5   | I2C1_SMBA / SPI3_MOSI /<br>ETH_PPS_OUT / I2S3_SD                             | TIM3_CH2/SPI1_MOSI/<br>CAN2_RX         |  |
| 92      | 58     | PB6               | I/O                 | FT                       | PB6   | I2C1_SCL <sup>(7)</sup> /TIM4_CH1 <sup>(7)</sup>                             | USART1_TX/CAN2_TX                      |  |
| 93      | 59     | PB7               | I/O                 | FT                       | PB7   | I2C1_SDA <sup>(7)</sup> /TIM4_CH2 <sup>(7)</sup>                             | USART1_RX                              |  |
| 94      | 60     | BOOT0             | I                   |                          | BOOT0   |  |  |  |
| 95      | 61     | PB8               | I/O                 | FT                       | PB8   | TIM4_CH3 <sup>(7)</sup> / ETH_MII_TXD3                                       | I2C1_SCL/CAN1_RX                       |  |
| 96      | 62     | PB9               | I/O                 | FT                       | PB9   | TIM4_CH4 <sup>(7)</sup>  | I2C1_SDA / CAN1_TX                     |  |

**Table 5. Pin definitions (continued)**

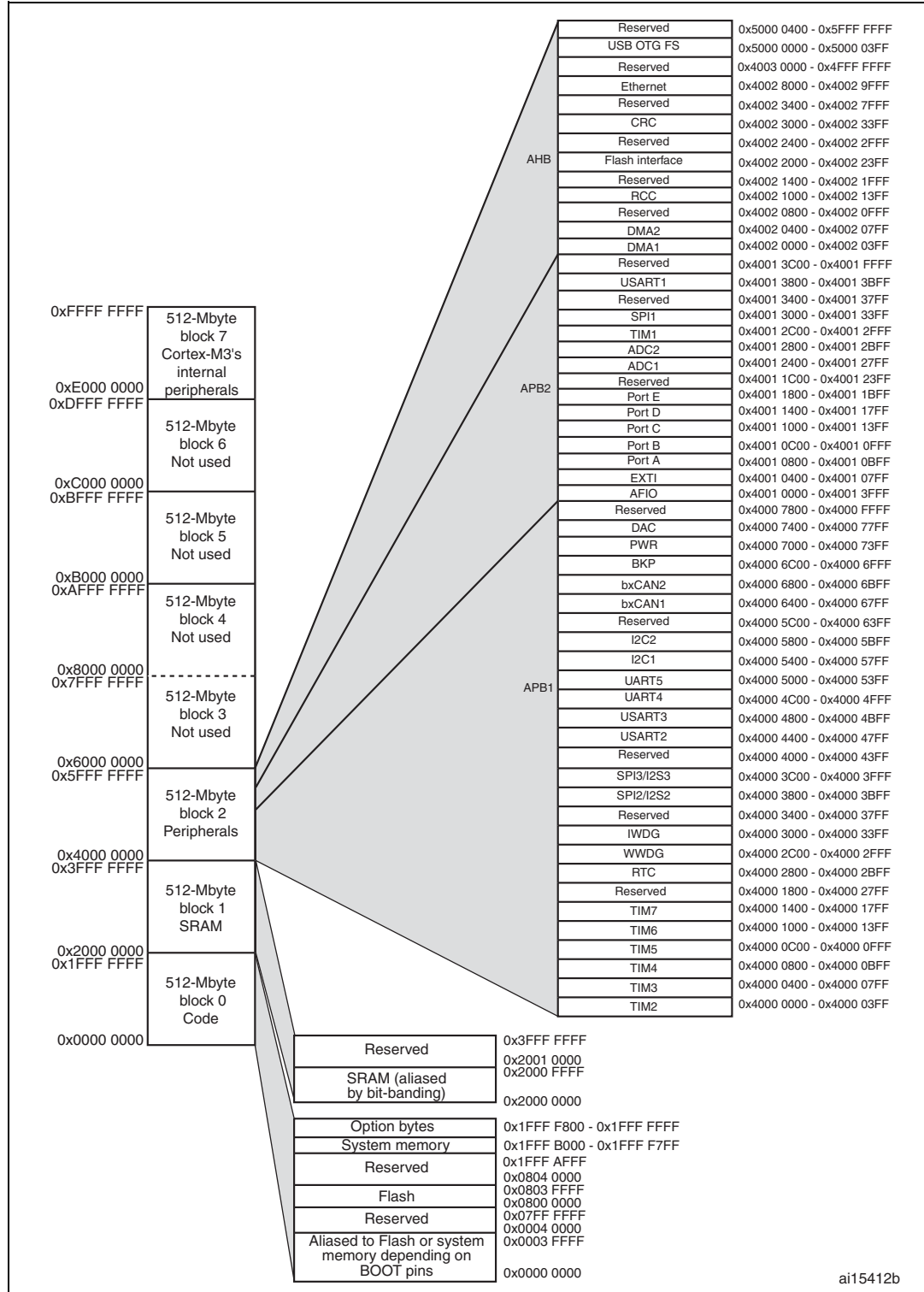
| Pins    |        | Pin name          | Type <sup>(1)</sup> | I/O level <sup>(2)</sup> | Main function <sup>(3)</sup><br>(after reset) | Alternate functions <sup>(4)</sup> |       |
|---------|--------|-------------------|---------------------|--------------------------|---|------------------------------------|-------|
| LQFP100 | LQFP64 |                   |                     |                          |   | Default                            | Remap |
| 97      | -      | PE0               | I/O                 | FT                       | PE0   | TIM4_ETR                           |       |
| 98      | -      | PE1               | I/O                 | FT                       | PE1   |                                    |       |
| 99      | 63     | V <sub>SS_3</sub> | S                   |                          | V <sub>SS_3</sub>                             |                                    |       |
| 100     | 64     | V <sub>DD_3</sub> | S                   |                          | V <sub>DD_3</sub>                             |                                    |       |

1. I = input, O = output, S = supply.
2. FT = 5 V tolerant. All I/Os are V<sub>DD</sub> capable.
3. Function availability depends on the chosen device.
4. If several peripherals share the same I/O pin, to avoid conflict between these alternate functions only one peripheral should be enabled at a time through the peripheral clock enable bit (in the corresponding RCC peripheral clock enable register).
5. PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited: the speed should not exceed 2 MHz with a maximum load of 30 pF and these IOs must not be used as a current source (e.g. to drive an LED).
6. Main function after the first backup domain power-up. Later on, it depends on the contents of the Backup registers even after reset (because these registers are not reset by the main reset). For details on how to manage these IOs, refer to the Battery backup domain and BKP register description sections in the STM32F10xxx reference manual, available from the STMicroelectronics website: [www.st.com](http://www.st.com).
7. This alternate function can be remapped by software to some other port pins (if available on the used package). For more details, refer to the Alternate function I/O and debug configuration section in the STM32F10xxx reference manual, available from the STMicroelectronics website: [www.st.com](http://www.st.com).
8. For the LQFP64 package, the pins number 5 and 6 are configured as OSC\_IN/OSC\_OUT after reset, however the functionality of PD0 and PD1 can be remapped by software on these pins. For the LQFP100 package, PD0 and PD1 are available by default, so there is no need for remapping. For more details, refer to Alternate function I/O and debug configuration section in the STM32F10xxx reference manual.

# 4 Memory mapping

The memory map is shown in *Figure 4*.

**Figure 4. Memory map**



ai15412b

## 5 Electrical characteristics

### 5.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to  $V_{SS}$ .

#### 5.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at  $T_A = 25\text{ °C}$  and  $T_A = T_{A\text{max}}$  (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation ( $\text{mean} \pm 3\sigma$ ).

#### 5.1.2 Typical values

Unless otherwise specified, typical data are based on  $T_A = 25\text{ °C}$ ,  $V_{DD} = 3.3\text{ V}$  (for the  $2\text{ V} \leq V_{DD} \leq 3.6\text{ V}$  voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated ( $\text{mean} \pm 2\sigma$ ).

#### 5.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

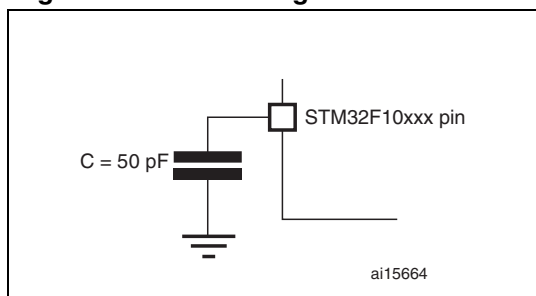
#### 5.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 5](#).

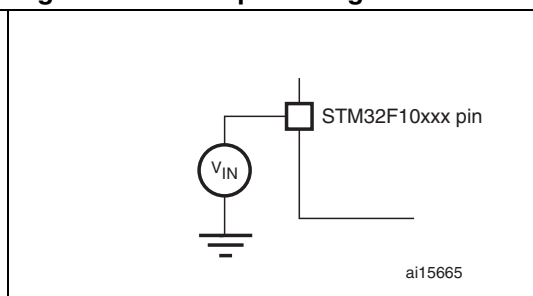
#### 5.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 6](#).

**Figure 5. Pin loading conditions**

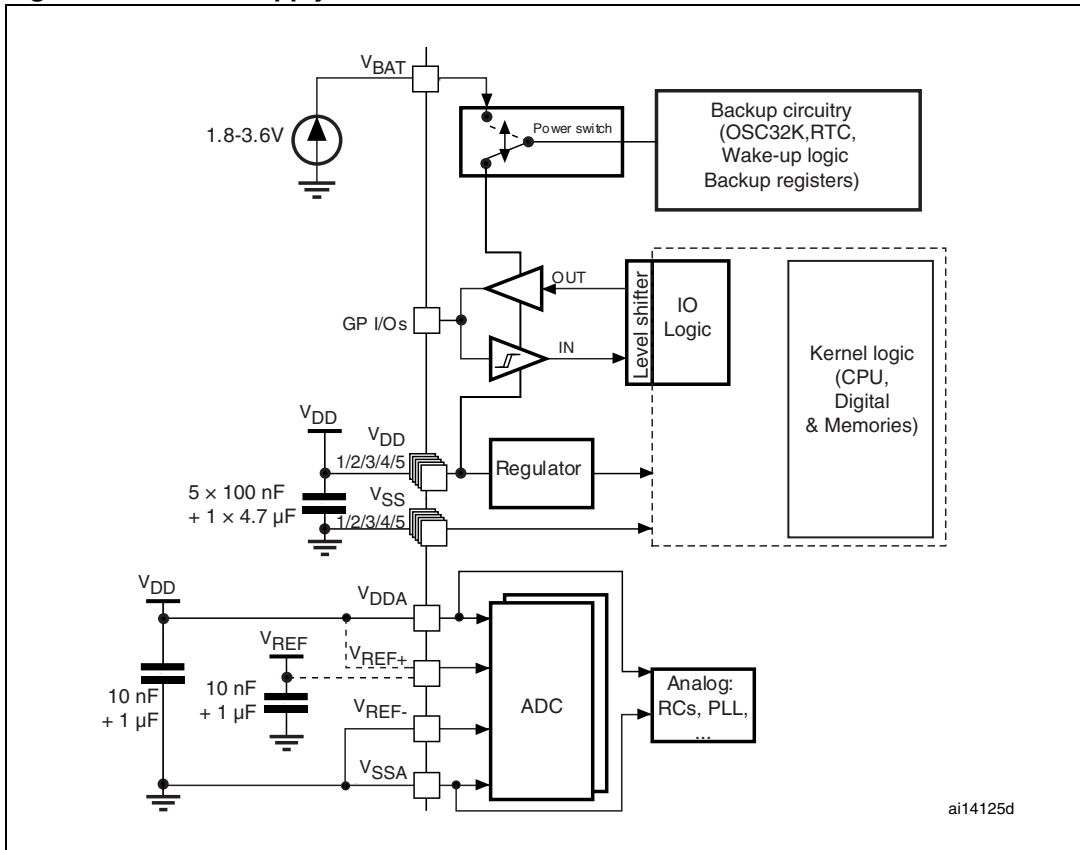


**Figure 6. Pin input voltage**



### 5.1.6 Power supply scheme

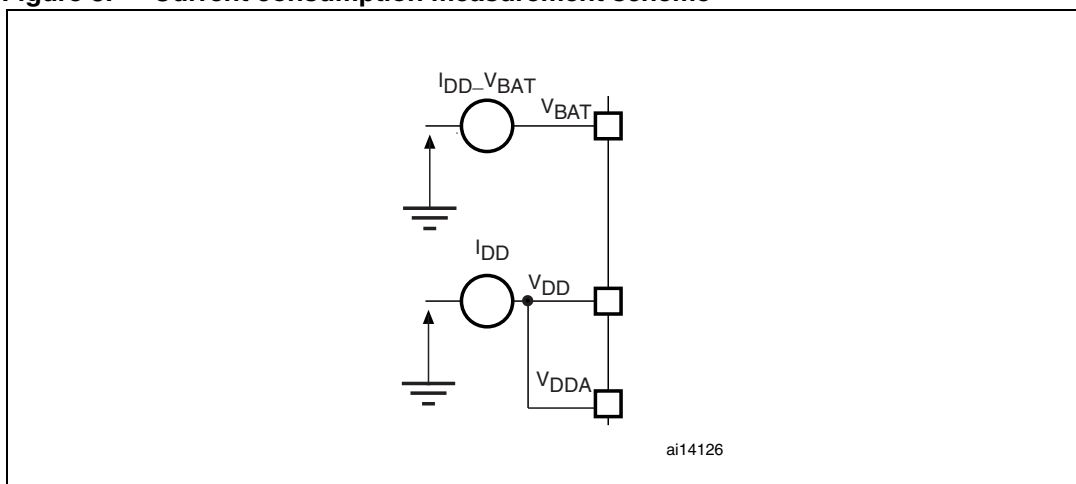
Figure 7. Power supply scheme



**Caution:** In [Figure 7](#), the 4.7 μF capacitor must be connected to V<sub>DD3</sub>.

### 5.1.7 Current consumption measurement

Figure 8. Current consumption measurement scheme





## 5.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 6: Voltage characteristics](#), [Table 7: Current characteristics](#), and [Table 8: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

**Table 6. Voltage characteristics**

| Symbol               | Ratings   | Min   | Max          | Unit |
|----------------------|---|---|--------------|------|
| $V_{DD}-V_{SS}$      | External main supply voltage (including $V_{DDA}$ and $V_{DD}$ ) <sup>(1)</sup> | -0.3  | 4.0          | V    |
| $V_{IN}$             | Input voltage on five volt tolerant pin <sup>(2)</sup>                          | $V_{SS} - 0.3$  | +5.5         |      |
|                      | Input voltage on any other pin <sup>(2)</sup>                                   | $V_{SS} - 0.3$  | $V_{DD}+0.3$ |      |
| $ \Delta V_{DDX} $   | Variations between different $V_{DD}$ power pins                                |   | 50           | mV   |
| $ V_{SSX} - V_{SS} $ | Variations between all the different ground pins                                |   | 50           |      |
| $V_{ESD(HBM)}$       | Electrostatic discharge voltage (human body model)                              | see <a href="#">Section 5.3.11: Absolute maximum ratings (electrical sensitivity)</a> |              |      |

- All main power ( $V_{DD}$ ,  $V_{DDA}$ ) and ground ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supply, in the permitted range.
- $I_{INJ(PIN)}$  must never be exceeded (see [Table 7: Current characteristics](#)). This is implicitly insured if  $V_{IN}$  maximum is respected. If  $V_{IN}$  maximum cannot be respected, the injection current must be limited externally to the  $I_{INJ(PIN)}$  value. A positive injection is induced by  $V_{IN} > V_{INmax}$  while a negative injection is induced by  $V_{IN} < V_{SS}$ .

**Table 7. Current characteristics**

| Symbol                               | Ratings   | Max. | Unit |
|--------------------------------------|---|------|------|
| $I_{VDD}$                            | Total current into $V_{DD}/V_{DDA}$ power lines (source) <sup>(1)</sup> | 150  | mA   |
| $I_{VSS}$                            | Total current out of $V_{SS}$ ground lines (sink) <sup>(1)</sup>        | 150  |      |
| $I_{IO}$                             | Output current sunk by any I/O and control pin                          | 25   |      |
|                                      | Output current source by any I/Os and control pin                       | - 25 |      |
| $I_{INJ(PIN)}$ <sup>(2)(3)</sup>     | Injected current on NRST pin  | ± 5  |      |
|                                      | Injected current on HSE OSC_IN and LSE OSC_IN pins                      | ± 5  |      |
|                                      | Injected current on any other pin <sup>(4)</sup>                        | ± 5  |      |
| $\Sigma I_{INJ(PIN)}$ <sup>(2)</sup> | Total injected current (sum of all I/O and control pins) <sup>(4)</sup> | ± 25 |      |

- All main power ( $V_{DD}$ ,  $V_{DDA}$ ) and ground ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supply, in the permitted range.
- $I_{INJ(PIN)}$  must never be exceeded. This is implicitly insured if  $V_{IN}$  maximum is respected. If  $V_{IN}$  maximum cannot be respected, the injection current must be limited externally to the  $I_{INJ(PIN)}$  value. A positive injection is induced by  $V_{IN} > V_{DD}$  while a negative injection is induced by  $V_{IN} < V_{SS}$ .
- Negative injection disturbs the analog performance of the device. See note in [Section 5.3.16: 12-bit ADC characteristics](#).
- When several inputs are submitted to a current injection, the maximum  $\Sigma I_{INJ(PIN)}$  is the absolute sum of the positive and negative injected currents (instantaneous values). These results are based on characterization with  $\Sigma I_{INJ(PIN)}$  maximum current injection on four I/O port pins of the device.

**Table 8. Thermal characteristics**

| Symbol    | Ratings                      | Value       | Unit |
|-----------|------------------------------|-------------|------|
| $T_{STG}$ | Storage temperature range    | -65 to +150 | °C   |
| $T_J$     | Maximum junction temperature | 150         | °C   |

## 5.3 Operating conditions

### 5.3.1 General operating conditions

**Table 9. General operating conditions**

| Symbol          | Parameter   | Conditions                                   | Min | Max | Unit |
|-----------------|---|--|-----|-----|------|
| $f_{HCLK}$      | Internal AHB clock frequency  |  | 0   | 72  | MHz  |
| $f_{PCLK1}$     | Internal APB1 clock frequency   |  | 0   | 36  |      |
| $f_{PCLK2}$     | Internal APB2 clock frequency   |  | 0   | 72  |      |
| $V_{DD}$        | Standard operating voltage  |  | 2   | 3.6 | V    |
| $V_{DDA}^{(1)}$ | Analog operating voltage (ADC not used)   | Must be the same potential as $V_{DD}^{(2)}$ | 2   | 3.6 | V    |
|                 | Analog operating voltage (ADC used)   |  | 2.4 | 3.6 |      |
| $V_{BAT}$       | Backup operating voltage  |  | 1.8 | 3.6 | V    |
| $P_D$           | Power dissipation at $T_A = 85\text{ °C}$ for suffix 6 or $T_A = 105\text{ °C}$ for suffix 7 <sup>(3)</sup> | LQFP100                                      |     | 434 | mW   |
|                 |   | LQFP64                                       |     | 444 |      |
| $T_A$           | Ambient temperature for 6 suffix version  | Maximum power dissipation                    | -40 | 85  | °C   |
|                 |   | Low power dissipation <sup>(4)</sup>         | -40 | 105 |      |
|                 | Ambient temperature for 7 suffix version  | Maximum power dissipation                    | -40 | 105 | °C   |
|                 |   | Low power dissipation <sup>(4)</sup>         | -40 | 125 |      |
| $T_J$           | Junction temperature range  | 6 suffix version                             | -40 | 105 | °C   |
|                 |   | 7 suffix version                             | -40 | 125 |      |

- When the ADC is used, refer to [Table 51: ADC characteristics](#).
- It is recommended to power  $V_{DD}$  and  $V_{DDA}$  from the same source. A maximum difference of 300 mV between  $V_{DD}$  and  $V_{DDA}$  can be tolerated during power-up and operation.
- If  $T_A$  is lower, higher  $P_D$  values are allowed as long as  $T_J$  does not exceed  $T_{Jmax}$ .
- In low power dissipation state,  $T_A$  can be extended to this range as long as  $T_J$  does not exceed  $T_{Jmax}$ .

### 5.3.2 Operating conditions at power-up / power-down

Subject to general operating conditions for  $T_A$ .

**Table 10. Operating conditions at power-up / power-down**

| Symbol    | Parameter               | Conditions | Min | Max      | Unit            |
|-----------|-------------------------|------------|-----|----------|-----------------|
| $t_{VDD}$ | $V_{DD}$ rise time rate |            | 0   | $\infty$ | $\mu\text{s/V}$ |
|           | $V_{DD}$ fall time rate |            | 20  | $\infty$ |                 |

### 5.3.3 Embedded reset and power control block characteristics

The parameters given in [Table 11](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

**Table 11. Embedded reset and power control block characteristics**

| Symbol                      | Parameter                                     | Conditions                  | Min                | Typ  | Max  | Unit |
|-----------------------------|---|-----------------------------|--------------------|------|------|------|
| $V_{PVD}$                   | Programmable voltage detector level selection | PLS[2:0]=000 (rising edge)  | 2.1                | 2.18 | 2.26 | V    |
|                             |   | PLS[2:0]=000 (falling edge) | 2                  | 2.08 | 2.16 | V    |
|                             |   | PLS[2:0]=001 (rising edge)  | 2.19               | 2.28 | 2.37 | V    |
|                             |   | PLS[2:0]=001 (falling edge) | 2.09               | 2.18 | 2.27 | V    |
|                             |   | PLS[2:0]=010 (rising edge)  | 2.28               | 2.38 | 2.48 | V    |
|                             |   | PLS[2:0]=010 (falling edge) | 2.18               | 2.28 | 2.38 | V    |
|                             |   | PLS[2:0]=011 (rising edge)  | 2.38               | 2.48 | 2.58 | V    |
|                             |   | PLS[2:0]=011 (falling edge) | 2.28               | 2.38 | 2.48 | V    |
|                             |   | PLS[2:0]=100 (rising edge)  | 2.47               | 2.58 | 2.69 | V    |
|                             |   | PLS[2:0]=100 (falling edge) | 2.37               | 2.48 | 2.59 | V    |
|                             |   | PLS[2:0]=101 (rising edge)  | 2.57               | 2.68 | 2.79 | V    |
|                             |   | PLS[2:0]=101 (falling edge) | 2.47               | 2.58 | 2.69 | V    |
|                             |   | PLS[2:0]=110 (rising edge)  | 2.66               | 2.78 | 2.9  | V    |
|                             |   | PLS[2:0]=110 (falling edge) | 2.56               | 2.68 | 2.8  | V    |
|                             |   | PLS[2:0]=111 (rising edge)  | 2.76               | 2.88 | 3    | V    |
| PLS[2:0]=111 (falling edge) | 2.66  | 2.78                        | 2.9                | V    |      |      |
| $V_{PVDhyst}^{(2)}$         | PVD hysteresis                                |                             |                    | 100  |      | mV   |
| $V_{POR/PDR}$               | Power on/power down reset threshold           | Falling edge                | 1.8 <sup>(1)</sup> | 1.88 | 1.96 | V    |
|                             |   | Rising edge                 | 1.84               | 1.92 | 2.0  | V    |
| $V_{PDRhyst}^{(2)}$         | PDR hysteresis                                |                             |                    | 40   |      | mV   |
| $T_{RSTTEMPO}^{(2)}$        | Reset temporization                           |                             | 1                  | 2.5  | 4.5  | ms   |

1. The product behavior is guaranteed by design down to the minimum  $V_{POR/PDR}$  value.

2. Guaranteed by design, not tested in production.

### 5.3.4 Embedded reference voltage

The parameters given in [Table 12](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

**Table 12. Embedded internal reference voltage**

| Symbol                 | Parameter   | Conditions                             | Min  | Typ  | Max                 | Unit   |
|------------------------|---|--|------|------|---------------------|--------|
| $V_{REFINT}$           | Internal reference voltage                                    | $-40\text{ °C} < T_A < +105\text{ °C}$ | 1.16 | 1.20 | 1.26                | V      |
|                        |   | $-40\text{ °C} < T_A < +85\text{ °C}$  | 1.16 | 1.20 | 1.24                | V      |
| $T_{S\_vrefint}^{(1)}$ | ADC sampling time when reading the internal reference voltage |  |      | 5.1  | 17.1 <sup>(2)</sup> | μs     |
| $V_{RERINT}^{(2)}$     | Internal reference voltage spread over the temperature range  | $V_{DD} = 3\text{ V} \pm 10\text{ mV}$ |      |      | 10                  | mV     |
| $T_{Coeff}^{(2)}$      | Temperature coefficient                                       |  |      |      | 100                 | ppm/°C |

1. Shortest sampling time can be determined in the application by multiple iterations.
2. Guaranteed by design, not tested in production.

### 5.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in [Figure 8: Current consumption measurement scheme](#).

All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to Dhrystone 2.1 code.

#### Maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at  $V_{DD}$  or  $V_{SS}$  (no load)
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time is adjusted to the  $f_{HCLK}$  frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above)
- Prefetch in ON (reminder: this bit must be set before clock setting and bus prescaling)
- When the peripherals are enabled  $f_{PCLK1} = f_{HCLK}/2$ ,  $f_{PCLK2} = f_{HCLK}$

The parameters given in [Table 13](#), [Table 14](#) and [Table 15](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

**Table 13. Maximum current consumption in Run mode, code with data processing running from Flash**

| Symbol          | Parameter                  | Conditions   | f <sub>HCLK</sub> | Max <sup>(1)</sup>     |                         | Unit |
|-----------------|----------------------------|--|-------------------|------------------------|-------------------------|------|
|                 |                            |  |                   | T <sub>A</sub> = 85 °C | T <sub>A</sub> = 105 °C |      |
| I <sub>DD</sub> | Supply current in Run mode | External clock <sup>(2)</sup> , all peripherals enabled  | 72 MHz            | 68                     | 68.4                    | mA   |
|                 |                            |  | 48 MHz            | 49                     | 49.2                    |      |
|                 |                            |  | 36 MHz            | 38.7                   | 38.9                    |      |
|                 |                            |  | 24 MHz            | 27.3                   | 27.9                    |      |
|                 |                            |  | 16 MHz            | 20.2                   | 20.5                    |      |
|                 |                            |  | 8 MHz             | 10.2                   | 10.8                    |      |
|                 |                            | External clock <sup>(3)</sup> , all peripherals disabled | 72 MHz            | 32.7                   | 32.9                    |      |
|                 |                            |  | 48 MHz            | 25                     | 25.2                    |      |
|                 |                            |  | 36 MHz            | 20.3                   | 20.6                    |      |
|                 |                            |  | 24 MHz            | 14.8                   | 15.1                    |      |
|                 |                            |  | 16 MHz            | 11.2                   | 11.7                    |      |
|                 |                            |  | 8 MHz             | 6.6                    | 7.2                     |      |

1. Based on characterization, not tested in production.
2. External clock is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

**Table 14. Maximum current consumption in Run mode, code with data processing running from RAM**

| Symbol          | Parameter                  | Conditions   | f <sub>HCLK</sub> | Max <sup>(1)</sup>     |                         | Unit |
|-----------------|----------------------------|--|-------------------|------------------------|-------------------------|------|
|                 |                            |  |                   | T <sub>A</sub> = 85 °C | T <sub>A</sub> = 105 °C |      |
| I <sub>DD</sub> | Supply current in Run mode | External clock <sup>(2)</sup> , all peripherals enabled  | 72 MHz            | 65.5                   | 66                      | mA   |
|                 |                            |  | 48 MHz            | 45.4                   | 46                      |      |
|                 |                            |  | 36 MHz            | 35.5                   | 36.1                    |      |
|                 |                            |  | 24 MHz            | 25.2                   | 25.6                    |      |
|                 |                            |  | 16 MHz            | 18                     | 18.5                    |      |
|                 |                            |  | 8 MHz             | 10.5                   | 11                      |      |
|                 |                            | External clock <sup>(3)</sup> , all peripherals disabled | 72 MHz            | 31.4                   | 31.9                    |      |
|                 |                            |  | 48 MHz            | 27.8                   | 28.2                    |      |
|                 |                            |  | 36 MHz            | 17.6                   | 18.3                    |      |
|                 |                            |  | 24 MHz            | 13.1                   | 13.8                    |      |
|                 |                            |  | 16 MHz            | 10.2                   | 10.9                    |      |
|                 |                            |  | 8 MHz             | 6.1                    | 7.8                     |      |

1. Based on characterization, tested in production at V<sub>DD</sub> max, f<sub>HCLK</sub> max..
2. External clock is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

Table 15. Maximum current consumption in Sleep mode, code running from Flash or RAM

| Symbol          | Parameter                    | Conditions   | f <sub>HCLK</sub> | Max <sup>(1)</sup>     |                         | Unit |
|-----------------|------------------------------|--|-------------------|------------------------|-------------------------|------|
|                 |                              |  |                   | T <sub>A</sub> = 85 °C | T <sub>A</sub> = 105 °C |      |
| I <sub>DD</sub> | Supply current in Sleep mode | External clock <sup>(2)</sup> , all peripherals enabled  | 72 MHz            | 48.4                   | 49                      | mA   |
|                 |                              |  | 48 MHz            | 33.9                   | 34.4                    |      |
|                 |                              |  | 36 MHz            | 26.7                   | 27.2                    |      |
|                 |                              |  | 24 MHz            | 19.3                   | 19.8                    |      |
|                 |                              |  | 16 MHz            | 14.2                   | 14.8                    |      |
|                 |                              |  | 8 MHz             | 8.7                    | 9.1                     |      |
|                 |                              | External clock <sup>(3)</sup> , all peripherals disabled | 72 MHz            | 10.1                   | 10.6                    |      |
|                 |                              |  | 48 MHz            | 8.3                    | 8.75                    |      |
|                 |                              |  | 36 MHz            | 7.5                    | 8                       |      |
|                 |                              |  | 24 MHz            | 6.6                    | 7.1                     |      |
|                 |                              |  | 16 MHz            | 6                      | 6.5                     |      |
|                 |                              |  | 8 MHz             | 2.5                    | 3                       |      |

1. Based on characterization, tested in production at V<sub>DD</sub> max and f<sub>HCLK</sub> max with peripherals enabled.

2. External clock is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

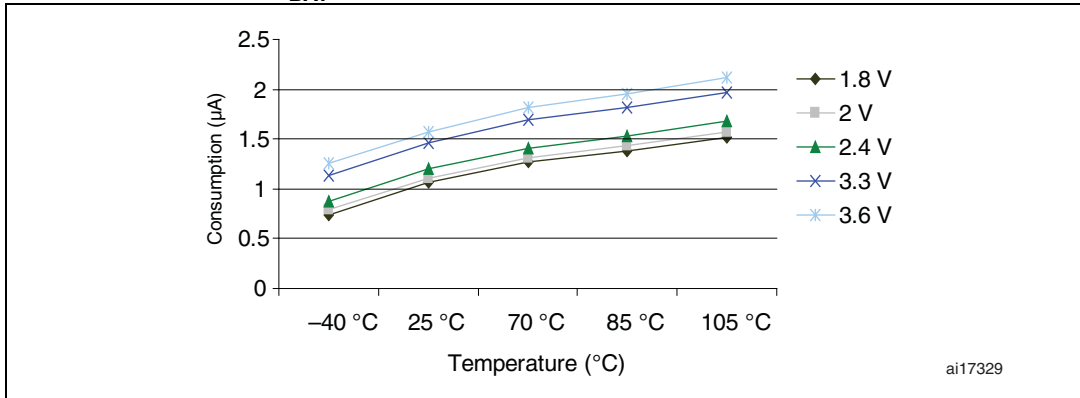
Table 16. Typical and maximum current consumptions in Stop and Standby modes

| Symbol               | Parameter                      | Conditions  | Typ <sup>(1)</sup>                        |   |   | Max                    |                         | Unit |
|----------------------|--------------------------------|---|---|---|---|------------------------|-------------------------|------|
|                      |                                |   | V <sub>DD</sub> /V <sub>BAT</sub> = 2.0 V | V <sub>DD</sub> /V <sub>BAT</sub> = 2.4 V | V <sub>DD</sub> /V <sub>BAT</sub> = 3.3 V | T <sub>A</sub> = 85 °C | T <sub>A</sub> = 105 °C |      |
| I <sub>DD</sub>      | Supply current in Stop mode    | Regulator in Run mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)       |   | 32  | 33  | 600                    | 1300                    | μA   |
|                      |                                | Regulator in Low Power mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog) |   | 25  | 26  | 590                    | 1280                    |      |
|                      | Supply current in Standby mode | Low-speed internal RC oscillator and independent watchdog ON  |   | 3   | 3.8                                       | -                      | -                       |      |
|                      |                                | Low-speed internal RC oscillator ON, independent watchdog OFF   |   | 2.8                                       | 3.6                                       | -                      | -                       |      |
|                      |                                | Low-speed internal RC oscillator and independent watchdog OFF, low-speed oscillator and RTC OFF                                       |   | 1.9                                       | 2.1                                       | 5 <sup>(2)</sup>       | 6.5 <sup>(2)</sup>      |      |
| I <sub>DD_VBAT</sub> | Backup domain supply current   | Low-speed oscillator and RTC ON   | 1.1                                       | 1.2                                       | 1.4                                       | 2.1 <sup>(2)</sup>     | 2.3 <sup>(2)</sup>      |      |

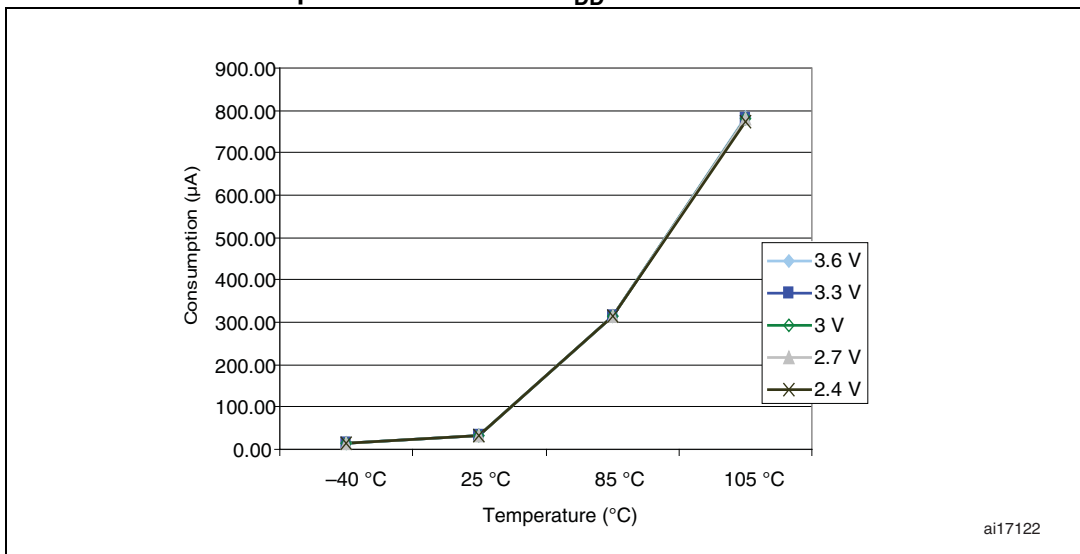
1. Typical values are measured at T<sub>A</sub> = 25 °C.

2. Based on characterization, not tested in production.

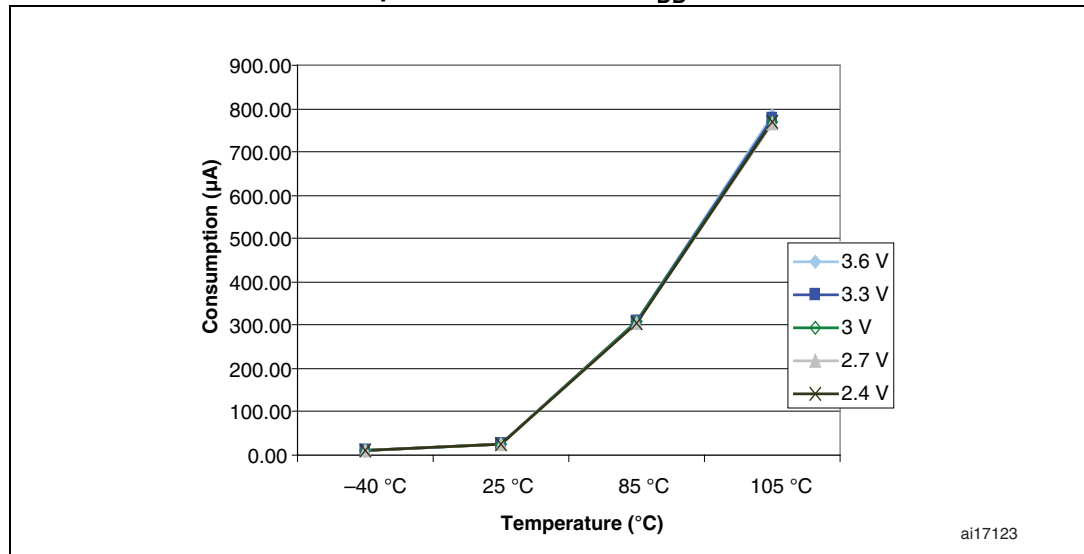
**Figure 9. Typical current consumption on  $V_{BAT}$  with RTC on vs. temperature at different  $V_{BAT}$  values**



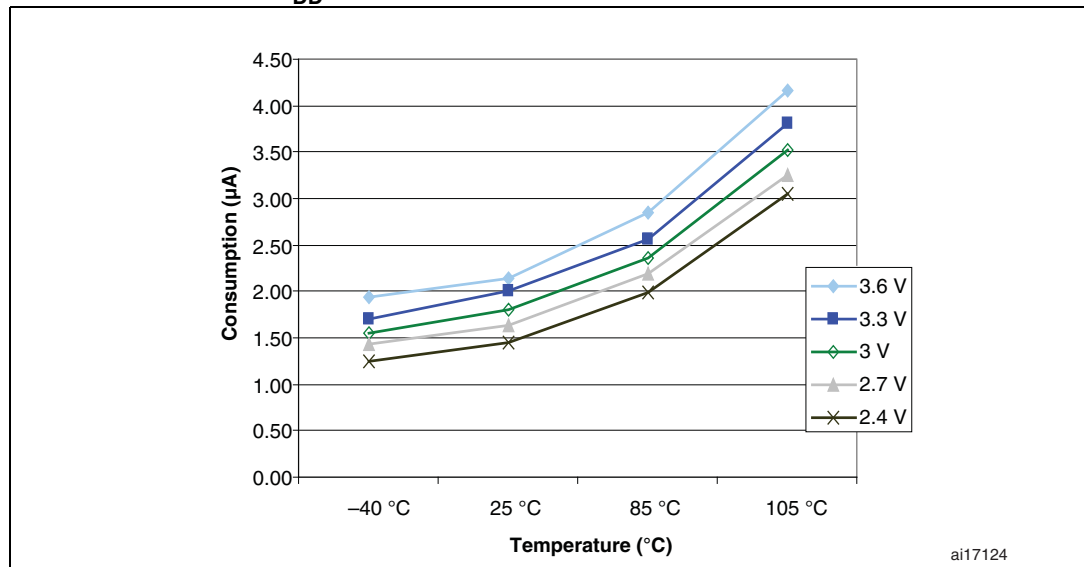
**Figure 10. Typical current consumption in Stop mode with regulator in Run mode versus temperature at different  $V_{DD}$  values**



**Figure 11. Typical current consumption in Stop mode with regulator in Low-power mode versus temperature at different V<sub>DD</sub> values**



**Figure 12. Typical current consumption in Standby mode versus temperature at different V<sub>DD</sub> values**



**Typical current consumption**

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at V<sub>DD</sub> or V<sub>SS</sub> (no load).
- All peripherals are disabled except if it is explicitly mentioned.
- The Flash access time is adjusted to f<sub>HCLK</sub> frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above).
- Ambient temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 9](#).
- Prefetch is ON (Reminder: this bit must be set before clock setting and bus prescaling)

When the peripherals are enabled f<sub>PCLK1</sub> = f<sub>HCLK</sub>/4, f<sub>PCLK2</sub> = f<sub>HCLK</sub>/2, f<sub>ADCCLK</sub> = f<sub>PCLK2</sub>/4



**Table 17. Typical current consumption in Run mode, code with data processing running from Flash**

| Symbol          | Parameter                  | Conditions  | f <sub>HCLK</sub> | Typ <sup>(1)</sup>                     |                          | Unit |
|-----------------|----------------------------|---|-------------------|--|--------------------------|------|
|                 |                            |   |                   | All peripherals enabled <sup>(2)</sup> | All peripherals disabled |      |
| I <sub>DD</sub> | Supply current in Run mode | External clock <sup>(3)</sup>   | 72 MHz            | 47.3                                   | 28.3                     | mA   |
|                 |                            |   | 48 MHz            | 32                                     | 19.6                     |      |
|                 |                            |   | 36 MHz            | 24.6                                   | 15.4                     |      |
|                 |                            |   | 24 MHz            | 16.8                                   | 10.6                     |      |
|                 |                            |   | 16 MHz            | 11.8                                   | 7.4                      |      |
|                 |                            |   | 8 MHz             | 5.9                                    | 3.7                      |      |
|                 |                            |   | 4 MHz             | 3.7                                    | 2.9                      |      |
|                 |                            |   | 2 MHz             | 2.5                                    | 2                        |      |
|                 |                            |   | 1 MHz             | 1.8                                    | 1.53                     |      |
|                 |                            |   | 500 kHz           | 1.5                                    | 1.3                      |      |
|                 |                            | 125 kHz   | 1.3               | 1.2                                    |                          |      |
|                 |                            | Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency | 36 MHz            | 23.9                                   | 14.8                     | mA   |
|                 |                            |   | 24 MHz            | 16.1                                   | 9.7                      |      |
|                 |                            |   | 16 MHz            | 11.1                                   | 6.7                      |      |
|                 |                            |   | 8 MHz             | 5.6                                    | 3.8                      |      |
|                 |                            |   | 4 MHz             | 3.1                                    | 2.1                      |      |
|                 |                            |   | 2 MHz             | 1.8                                    | 1.3                      |      |
|                 |                            |   | 1 MHz             | 1.16                                   | 0.9                      |      |
|                 |                            |   | 500 kHz           | 0.8                                    | 0.67                     |      |
| 125 kHz         | 0.6                        | 0.5   |                   |  |                          |      |

1. Typical values are measures at T<sub>A</sub> = 25 °C, V<sub>DD</sub> = 3.3 V.
2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC\_CR2 register).
3. External clock is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

**Table 18. Typical current consumption in Sleep mode, code running from Flash or RAM**

| Symbol          | Parameter                    | Conditions  | f <sub>HCLK</sub> | Typ <sup>(1)</sup>                     |                          | Unit |
|-----------------|------------------------------|---|-------------------|--|--------------------------|------|
|                 |                              |   |                   | All peripherals enabled <sup>(2)</sup> | All peripherals disabled |      |
| I <sub>DD</sub> | Supply current in Sleep mode | External clock <sup>(3)</sup>   | 72 MHz            | 28.2                                   | 6                        | mA   |
|                 |                              |   | 48 MHz            | 19                                     | 4.2                      |      |
|                 |                              |   | 36 MHz            | 14.7                                   | 3.4                      |      |
|                 |                              |   | 24 MHz            | 10.1                                   | 2.5                      |      |
|                 |                              |   | 16 MHz            | 6.7                                    | 2                        |      |
|                 |                              |   | 8 MHz             | 3.2                                    | 1.3                      |      |
|                 |                              |   | 4 MHz             | 2.3                                    | 1.2                      |      |
|                 |                              |   | 2 MHz             | 1.7                                    | 1.16                     |      |
|                 |                              |   | 1 MHz             | 1.5                                    | 1.1                      |      |
|                 |                              |   | 500 kHz           | 1.3                                    | 1.05                     |      |
|                 |                              | 125 kHz   | 1.2               | 1.05                                   |                          |      |
|                 |                              | Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency | 36 MHz            | 13.7                                   | 2.6                      |      |
|                 |                              |   | 24 MHz            | 9.3                                    | 1.8                      |      |
|                 |                              |   | 16 MHz            | 6.3                                    | 1.3                      |      |
|                 |                              |   | 8 MHz             | 2.7                                    | 0.6                      |      |
|                 |                              |   | 4 MHz             | 1.6                                    | 0.5                      |      |
|                 |                              |   | 2 MHz             | 1                                      | 0.46                     |      |
|                 |                              |   | 1 MHz             | 0.8                                    | 0.44                     |      |
|                 |                              |   | 500 kHz           | 0.6                                    | 0.43                     |      |
| 125 kHz         | 0.5                          | 0.42  |                   |  |                          |      |

1. Typical values are measures at T<sub>A</sub> = 25 °C, V<sub>DD</sub> = 3.3 V.
2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC\_CR2 register).
3. External clock is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

**On-chip peripheral current consumption**

The current consumption of the on-chip peripherals is given in [Table 19](#). The MCU is placed under the following conditions:

- all I/O pins are in input mode with a static value at V<sub>DD</sub> or V<sub>SS</sub> (no load)
- all peripherals are disabled unless otherwise mentioned
- the given value is calculated by measuring the current consumption
  - with all peripherals clocked off
  - with one peripheral clocked on (with only the clock applied)
- ambient operating temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 6](#)



**Table 19. Peripheral current consumption<sup>(1)</sup>**

| Peripheral |                     | Typical consumption at 25 °C | Unit |    |
|------------|---------------------|------------------------------|------|----|
| AHB        | ETH_MAC             | 5.2                          | mA   |    |
|            | OTG_FS              | 7.7                          |      |    |
| APB1       | TIM2                | 1.5                          |      |    |
|            | TIM3                | 1.5                          |      |    |
|            | TIM4                | 1.5                          |      |    |
|            | TIM5                | 1.5                          |      |    |
|            | TIM6                | 0.6                          |      |    |
|            | TIM7                | 0.3                          |      |    |
|            | SPI2                | 0.2                          |      |    |
|            | USART2              | 0.5                          |      |    |
|            | USART3              | 0.5                          |      |    |
|            | UART4               | 0.5                          |      |    |
|            | UART5               | 0.5                          |      |    |
|            | I2C1                | 0.5                          |      |    |
|            | I2C2                | 0.5                          |      |    |
|            | CAN1                | 0.8                          |      |    |
|            | CAN2                | 0.8                          |      |    |
| DAC        | 0.4                 |                              |      |    |
| APB2       | GPIO A              | 0.5                          |      | mA |
|            | GPIO B              | 0.5                          |      |    |
|            | GPIO C              | 0.5                          |      |    |
|            | GPIO D              | 0.5                          |      |    |
|            | GPIO E              | 0.5                          |      |    |
|            | ADC1 <sup>(2)</sup> | 2.1                          |      |    |
|            | ADC2 <sup>(2)</sup> | 2.0                          |      |    |
|            | TIM1                | 1.7                          |      |    |
|            | SPI1                | 0.4                          |      |    |
|            | USART1              | 0.9                          |      |    |

1.  $f_{HCLK} = 72 \text{ MHz}$ ,  $f_{APB1} = f_{HCLK}/2$ ,  $f_{APB2} = f_{HCLK}$ , default prescaler value for each peripheral.
2. Specific conditions for ADC:  $f_{HCLK} = 56 \text{ MHz}$ ,  $f_{APB1} = f_{HCLK}/2$ ,  $f_{APB2} = f_{HCLK}$ ,  $f_{ADCLK} = f_{APB2}/4$ , ADON bit in the ADC\_CR2 register is set to 1.

### 5.3.6 External clock source characteristics

#### High-speed external user clock generated from an external source

The characteristics given in [Table 20](#) result from tests performed using an high-speed external clock source, and under ambient temperature and supply voltage conditions summarized in [Table 9](#).

**Table 20. High-speed external user clock characteristics**

| Symbol                       | Parameter   | Conditions                       | Min         | Typ | Max         | Unit    |
|------------------------------|---|----------------------------------|-------------|-----|-------------|---------|
| $f_{HSE\_ext}$               | External user clock source frequency <sup>(1)</sup> |                                  | 1           | 8   | 50          | MHz     |
| $V_{HSEH}$                   | OSC_IN input pin high level voltage                 |                                  | $0.7V_{DD}$ |     | $V_{DD}$    | V       |
| $V_{HSEL}$                   | OSC_IN input pin low level voltage                  |                                  | $V_{SS}$    |     | $0.3V_{DD}$ |         |
| $t_{w(HSE)}$<br>$t_{w(HSE)}$ | OSC_IN high or low time <sup>(1)</sup>              |                                  | 16          |     |             | ns      |
| $t_{r(HSE)}$<br>$t_{f(HSE)}$ | OSC_IN rise or fall time <sup>(1)</sup>             |                                  |             |     | 20          |         |
| $C_{in(HSE)}$                | OSC_IN input capacitance <sup>(1)</sup>             |                                  |             | 5   |             | pF      |
| $DuCy_{(HSE)}$               | Duty cycle  |                                  | 45          |     | 55          | %       |
| $I_L$                        | OSC_IN Input leakage current                        | $V_{SS} \leq V_{IN} \leq V_{DD}$ |             |     | $\pm 1$     | $\mu A$ |

1. Guaranteed by design, not tested in production.

#### Low-speed external user clock generated from an external source

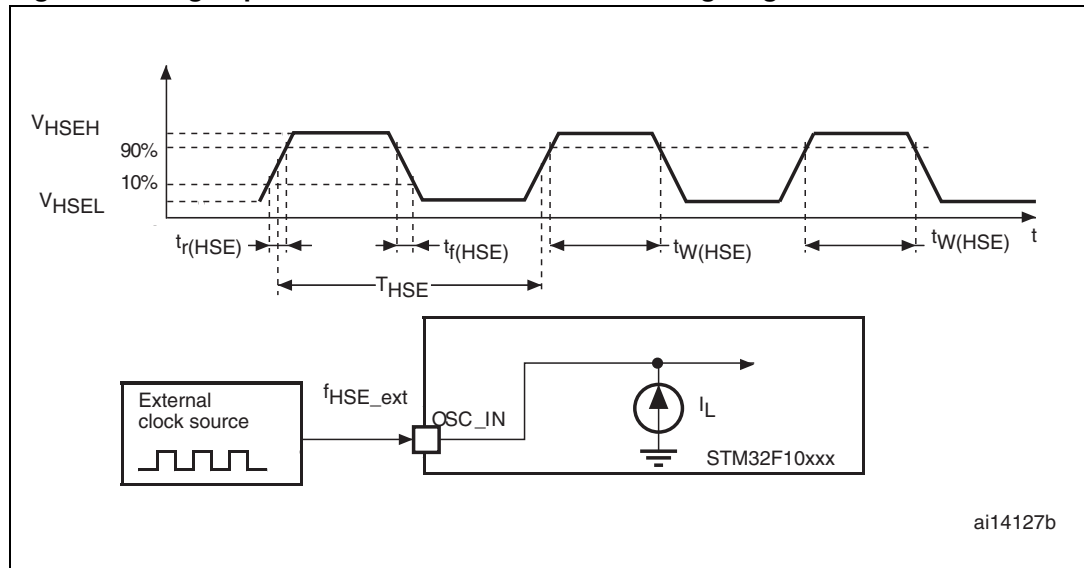
The characteristics given in [Table 21](#) result from tests performed using an low-speed external clock source, and under ambient temperature and supply voltage conditions summarized in [Table 9](#).

**Table 21. Low-speed external user clock characteristics**

| Symbol                       | Parameter   | Conditions                       | Min         | Typ    | Max         | Unit    |
|------------------------------|---|----------------------------------|-------------|--------|-------------|---------|
| $f_{LSE\_ext}$               | User External clock source frequency <sup>(1)</sup> |                                  |             | 32.768 | 1000        | kHz     |
| $V_{LSEH}$                   | OSC32_IN input pin high level voltage               |                                  | $0.7V_{DD}$ |        | $V_{DD}$    | V       |
| $V_{LSEL}$                   | OSC32_IN input pin low level voltage                |                                  | $V_{SS}$    |        | $0.3V_{DD}$ |         |
| $t_{w(LSE)}$<br>$t_{w(LSE)}$ | OSC32_IN high or low time <sup>(1)</sup>            |                                  | 450         |        |             | ns      |
| $t_{r(LSE)}$<br>$t_{f(LSE)}$ | OSC32_IN rise or fall time <sup>(1)</sup>           |                                  |             |        | 50          |         |
| $C_{in(LSE)}$                | OSC32_IN input capacitance <sup>(1)</sup>           |                                  |             | 5      |             | pF      |
| $DuCy_{(LSE)}$               | Duty cycle  |                                  | 30          |        | 70          | %       |
| $I_L$                        | OSC32_IN Input leakage current                      | $V_{SS} \leq V_{IN} \leq V_{DD}$ |             |        | $\pm 1$     | $\mu A$ |

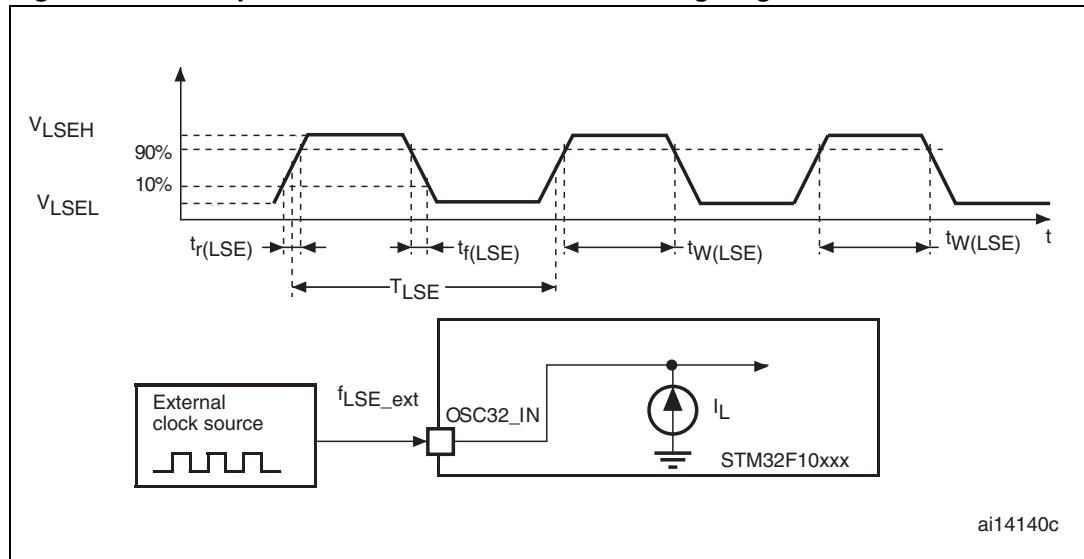
1. Guaranteed by design, not tested in production.

**Figure 13. High-speed external clock source AC timing diagram**



ai14127b

**Figure 14. Low-speed external clock source AC timing diagram**



ai14140c

**High-speed external clock generated from a crystal/ceramic resonator**

The high-speed external (HSE) clock can be supplied with a 3 to 25 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 22](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

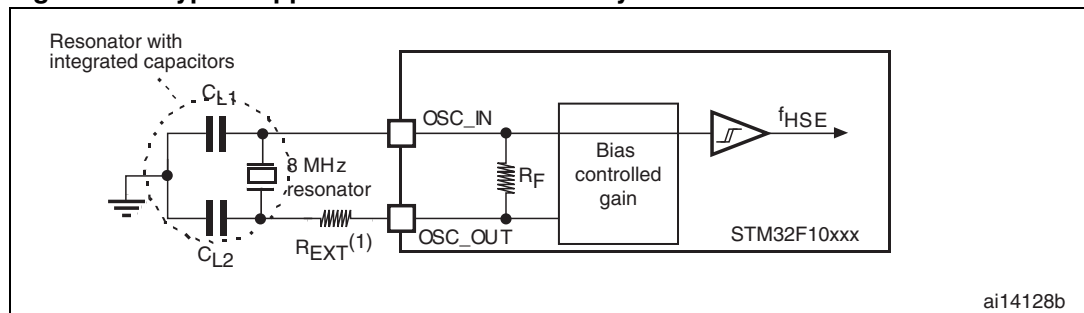
**Table 22. HSE 3-25 MHz oscillator characteristics<sup>(1) (2)</sup>**

| Symbol                       | Parameter  | Conditions  | Min | Typ | Max | Unit       |
|------------------------------|--|---|-----|-----|-----|------------|
| $f_{OSC\_IN}$                | Oscillator frequency   |   | 3   |     | 25  | MHz        |
| $R_F$                        | Feedback resistor  |   |     | 200 |     | k $\Omega$ |
| C                            | Recommended load capacitance versus equivalent serial resistance of the crystal ( $R_S$ ) <sup>(3)</sup> | $R_S = 30 \Omega$                                 |     | 30  |     | pF         |
| $i_2$                        | HSE driving current  | $V_{DD} = 3.3 V, V_{IN} = V_{SS}$ with 30 pF load |     |     | 1   | mA         |
| $g_m$                        | Oscillator transconductance  | Startup   | 25  |     |     | mA/V       |
| $t_{SU(HSE)}$ <sup>(4)</sup> | Startup time   | $V_{DD}$ is stabilized                            |     | 2   |     | ms         |

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Based on characterization, not tested in production.
3. The relatively low value of the RF resistor offers a good protection against issues resulting from use in a humid environment, due to the induced leakage and the bias condition change. However, it is recommended to take this point into account if the MCU is used in tough humidity conditions.
4.  $t_{SU(HSE)}$  is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For  $C_{L1}$  and  $C_{L2}$ , it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see [Figure 15](#)).  $C_{L1}$  and  $C_{L2}$  are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of  $C_{L1}$  and  $C_{L2}$ . PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing  $C_{L1}$  and  $C_{L2}$ . Refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website [www.st.com](http://www.st.com).

**Figure 15. Typical application with an 8 MHz crystal**



1.  $R_{EXT}$  value depends on the crystal characteristics.

**Low-speed external clock generated from a crystal/ceramic resonator**

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 23](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal

resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

**Table 23. LSE oscillator characteristics ( $f_{LSE} = 32.768 \text{ kHz}$ ) (1)**

| Symbol                       | Parameter  | Conditions                                | Min | Typ | Max | Unit            |
|------------------------------|--|---|-----|-----|-----|-----------------|
| $R_F$                        | Feedback resistor  |   |     | 5   |     | $M\Omega$       |
| $C^{(2)}$                    | Recommended load capacitance versus equivalent serial resistance of the crystal ( $R_S$ ) <sup>(3)</sup> | $R_S = 30 \text{ k}\Omega$                |     |     | 15  | pF              |
| $I_2$                        | LSE driving current  | $V_{DD} = 3.3 \text{ V}, V_{IN} = V_{SS}$ |     |     | 1.4 | $\mu\text{A}$   |
| $g_m$                        | Oscillator Transconductance  |   | 5   |     |     | $\mu\text{A/V}$ |
| $t_{SU(LSE)}$ <sup>(4)</sup> | startup time   | $V_{DD}$ is stabilized                    |     | 3   |     | s               |

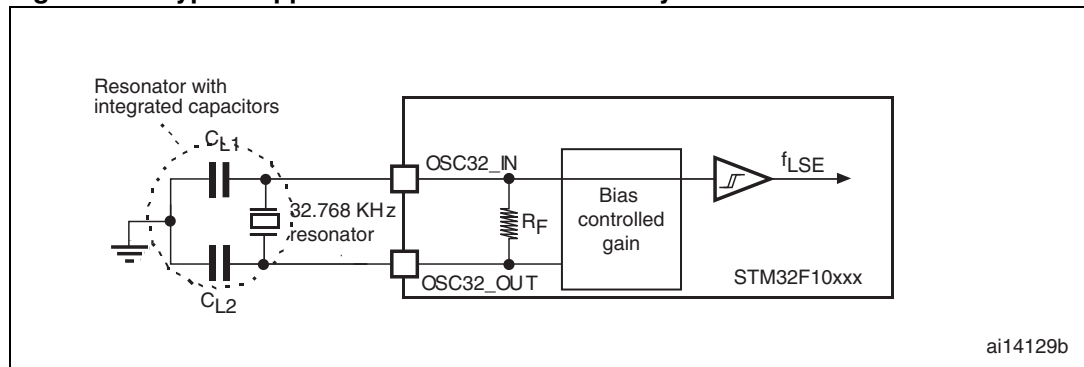
1. Based on characterization, not tested in production.
2. Refer to the note and caution paragraphs below the table, and to the application note AN2867 "Oscillator design guide for ST microcontrollers".
3. The oscillator selection can be optimized in terms of supply current using an high quality resonator with small  $R_S$  value for example MSIV-TIN32.768kHz. Refer to crystal manufacturer for more details
4.  $t_{SU(LSE)}$  is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768 kHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

**Note:** For  $C_{L1}$  and  $C_{L2}$  it is recommended to use high-quality external ceramic capacitors in the 5 pF to 15 pF range selected to match the requirements of the crystal or resonator (see Figure 16).  $C_{L1}$  and  $C_{L2}$ , are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of  $C_{L1}$  and  $C_{L2}$ . Load capacitance  $C_L$  has the following formula:  $C_L = C_{L1} \times C_{L2} / (C_{L1} + C_{L2}) + C_{stray}$  where  $C_{stray}$  is the pin capacitance and board or trace PCB-related capacitance. Typically, it is between 2 pF and 7 pF.

**Caution:** To avoid exceeding the maximum value of  $C_{L1}$  and  $C_{L2}$  (15 pF) it is strongly recommended to use a resonator with a load capacitance  $C_L \leq 7 \text{ pF}$ . Never use a resonator with a load capacitance of 12.5 pF.

**Example:** if you choose a resonator with a load capacitance of  $C_L = 6 \text{ pF}$ , and  $C_{stray} = 2 \text{ pF}$ , then  $C_{L1} = C_{L2} = 8 \text{ pF}$ .

**Figure 16. Typical application with a 32.768 kHz crystal**



### 5.3.7 Internal clock source characteristics

The parameters given in [Table 24](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

#### High-speed internal (HSI) RC oscillator

**Table 24. HSI oscillator characteristics <sup>(1)</sup>**

| Symbol                       | Parameter                        | Conditions   | Min                     | Typ  | Max              | Unit |   |
|------------------------------|----------------------------------|--|-------------------------|------|------------------|------|---|
| $f_{HSI}$                    | Frequency                        |  |                         | 8    |                  | MHz  |   |
| $ACC_{HSI}$                  | Accuracy of the HSI oscillator   | User-trimmed with the RCC_CR register <sup>(2)</sup> |                         |      | 1 <sup>(3)</sup> | %    |   |
|                              |                                  | Factory-calibrated <sup>(4)</sup>                    | $T_A = -40$ to $105$ °C | -2   |                  | 2.5  | % |
|                              |                                  |  | $T_A = -10$ to $85$ °C  | -1.5 |                  | 2.2  | % |
|                              |                                  |  | $T_A = 0$ to $70$ °C    | -1.3 |                  | 2    | % |
|                              | $T_A = 25$ °C                    | -1.1   |                         | 1.8  | %                |      |   |
| $t_{su(HSI)}$ <sup>(4)</sup> | HSI oscillator startup time      |  | 1                       |      | 2                | µs   |   |
| $I_{DD(HSI)}$ <sup>(4)</sup> | HSI oscillator power consumption |  |                         | 80   | 100              | µA   |   |

- $V_{DD} = 3.3$  V,  $T_A = -40$  to  $105$  °C unless otherwise specified.
- Refer to application note AN2868 “STM32F10xxx internal RC oscillator (HSI) calibration” available from the ST website [www.st.com](http://www.st.com).
- Guaranteed by design, not tested in production.
- Based on characterization, not tested in production.

#### Low-speed internal (LSI) RC oscillator

**Table 25. LSI oscillator characteristics <sup>(1)</sup>**

| Symbol                       | Parameter                        | Min | Typ  | Max | Unit |
|------------------------------|----------------------------------|-----|------|-----|------|
| $f_{LSI}$ <sup>(2)</sup>     | Frequency                        | 30  | 40   | 60  | kHz  |
| $t_{su(LSI)}$ <sup>(3)</sup> | LSI oscillator startup time      |     |      | 85  | µs   |
| $I_{DD(LSI)}$ <sup>(3)</sup> | LSI oscillator power consumption |     | 0.65 | 1.2 | µA   |

- $V_{DD} = 3$  V,  $T_A = -40$  to  $105$  °C unless otherwise specified.
- Based on characterization, not tested in production.
- Guaranteed by design, not tested in production.

#### Wakeup time from low-power mode

The wakeup times given in [Table 26](#) is measured on a wakeup phase with a 8-MHz HSI RC oscillator. The clock source used to wake up the device depends from the current operating mode:

- Stop or Standby mode: the clock source is the RC oscillator
- Sleep mode: the clock source is the clock that was set before entering Sleep mode.



All timings are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

**Table 26. Low-power mode wakeup timings**

| Symbol              | Parameter   | Typ | Unit    |
|---------------------|---|-----|---------|
| $t_{WUSLEEP}^{(1)}$ | Wakeup from Sleep mode                              | 1.8 | $\mu s$ |
| $t_{WUSTOP}^{(1)}$  | Wakeup from Stop mode (regulator in run mode)       | 3.6 | $\mu s$ |
|                     | Wakeup from Stop mode (regulator in low power mode) | 5.4 |         |
| $t_{WUSTDBY}^{(1)}$ | Wakeup from Standby mode                            | 50  | $\mu s$ |

1. The wakeup times are measured from the wakeup event to the point in which the user application code reads the first instruction.

### 5.3.8 PLL, PLL2 and PLL3 characteristics

The parameters given in [Table 27](#) and [Table 28](#) are derived from tests performed under temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

**Table 27. PLL characteristics**

| Symbol         | Parameter                      | Min <sup>(1)</sup> | Max <sup>(1)</sup> | Unit    |
|----------------|--------------------------------|--------------------|--------------------|---------|
| $f_{PLL\_IN}$  | PLL input clock <sup>(2)</sup> | 3                  | 12                 | MHz     |
|                | Pulse width at high level      | 30                 |                    | ns      |
| $f_{PLL\_OUT}$ | PLL multiplier output clock    | 18                 | 72                 | MHz     |
| $f_{VCO\_OUT}$ | PLL VCO output                 | 36                 | 144                | MHz     |
| $t_{LOCK}$     | PLL lock time                  |                    | 350                | $\mu s$ |
| Jitter         | Cycle-to-cycle jitter          |                    | 300                | ps      |

1. Based on characterization, not tested in production.
2. Take care of using the appropriate multiplier factors so as to have PLL input clock values compatible with the range defined by  $f_{PLL\_OUT}$ .

**Table 28. PLL2 and PLL3 characteristics**

| Symbol         | Parameter                      | Min <sup>(1)</sup> | Max <sup>(1)</sup> | Unit    |
|----------------|--------------------------------|--------------------|--------------------|---------|
| $f_{PLL\_IN}$  | PLL input clock <sup>(2)</sup> | 3                  | 5                  | MHz     |
|                | Pulse width at high level      | 30                 |                    | ns      |
| $f_{PLL\_OUT}$ | PLL multiplier output clock    | 40                 | 74                 | MHz     |
| $f_{VCO\_OUT}$ | PLL VCO output                 | 80                 | 148                | MHz     |
| $t_{LOCK}$     | PLL lock time                  |                    | 350                | $\mu s$ |
| Jitter         | Cycle-to-cycle jitter          |                    | 400                | ps      |

1. Based on characterization, not tested in production.
2. Take care of using the appropriate multiplier factors so as to have PLL input clock values compatible with the range defined by  $f_{PLL\_OUT}$ .

### 5.3.9 Memory characteristics

#### Flash memory

The characteristics are given at  $T_A = -40$  to  $105$  °C unless otherwise specified.

**Table 29. Flash memory characteristics**

| Symbol      | Parameter               | Conditions  | Min <sup>(1)</sup> | Typ  | Max <sup>(1)</sup> | Unit |
|-------------|-------------------------|---|--------------------|------|--------------------|------|
| $t_{prog}$  | 16-bit programming time | $T_A = -40$ to $+105$ °C  | 40                 | 52.5 | 70                 | µs   |
| $t_{ERASE}$ | Page (1 KB) erase time  | $T_A = -40$ to $+105$ °C  | 20                 |      | 40                 | ms   |
| $t_{ME}$    | Mass erase time         | $T_A = -40$ to $+105$ °C  | 20                 |      | 40                 | ms   |
| $I_{DD}$    | Supply current          | Read mode<br>$f_{HCLK} = 72$ MHz with 2 wait states, $V_{DD} = 3.3$ V |                    |      | 20                 | mA   |
|             |                         | Write / Erase modes<br>$f_{HCLK} = 72$ MHz, $V_{DD} = 3.3$ V          |                    |      | 5                  | mA   |
|             |                         | Power-down mode / Halt,<br>$V_{DD} = 3.0$ to $3.6$ V                  |                    |      | 50                 | µA   |
| $V_{prog}$  | Programming voltage     |   | 2                  |      | 3.6                | V    |

1. Guaranteed by design, not tested in production.

**Table 30. Flash memory endurance and data retention**

| Symbol    | Parameter      | Conditions  | Value              |     |     | Unit    |
|-----------|----------------|---|--------------------|-----|-----|---------|
|           |                |   | Min <sup>(1)</sup> | Typ | Max |         |
| $N_{END}$ | Endurance      | $T_A = -40$ to $+85$ °C (6 suffix versions)<br>$T_A = -40$ to $+105$ °C (7 suffix versions) | 10                 |     |     | kcycles |
| $t_{RET}$ | Data retention | 1 kcycle <sup>(2)</sup> at $T_A = 85$ °C  | 30                 |     |     | Years   |
|           |                | 1 kcycle <sup>(2)</sup> at $T_A = 105$ °C   | 10                 |     |     |         |
|           |                | 10 kcycles <sup>(2)</sup> at $T_A = 55$ °C  | 20                 |     |     |         |

1. Based on characterization, not tested in production.

2. Cycling performed over the whole temperature range.

### 5.3.10 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

**Functional EMS (electromagnetic susceptibility)**

While a simple application is executed on the device (toggling 2 LEDs through I/O ports). the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB:** A burst of fast transient voltage (positive and negative) is applied to  $V_{DD}$  and  $V_{SS}$  through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in [Table 31](#). They are based on the EMS levels and classes defined in application note AN1709.

**Table 31. EMS characteristics**

| Symbol     | Parameter   | Conditions  | Level/Class |
|------------|---|---|-------------|
| $V_{FESD}$ | Voltage limits to be applied on any I/O pin to induce a functional disturbance  | $V_{DD} = 3.3\text{ V}$ , LQFP100, $T_A = +25\text{ °C}$ , $f_{HCLK} = 75\text{ MHz}$ , conforms to IEC 61000-4-2 | 2B          |
| $V_{EFTB}$ | Fast transient voltage burst limits to be applied through 100 pF on $V_{DD}$ and $V_{SS}$ pins to induce a functional disturbance | $V_{DD} = 3.3\text{ V}$ , LQFP100, $T_A = +25\text{ °C}$ , $f_{HCLK} = 75\text{ MHz}$ , conforms to IEC 61000-4-2 | 4A          |

**Designing hardened software to avoid noise problems**

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

**Software recommendations**

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

**Prequalification trials**

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

### Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with SAE IEC61967-2 standard which specifies the test board and the pin loading.

**Table 32. EMI characteristics**

| Symbol           | Parameter  | Conditions   | Monitored frequency band | Max vs. [f <sub>HSE</sub> /f <sub>HCLK</sub> ] |          | Unit |
|------------------|------------|--|--------------------------|--|----------|------|
|                  |            |  |                          | 8/48 MHz                                       | 8/72 MHz |      |
| S <sub>EMI</sub> | Peak level | V <sub>DD</sub> = 3.3 V, T <sub>A</sub> = 25 °C, LQFP100 package compliant with IEC61967-2 | 0.1 to 30 MHz            | 9  | 9        | dBμV |
|                  |            |  | 30 to 130 MHz            | 26   | 13       |      |
|                  |            |  | 130 MHz to 1GHz          | 25   | 31       |      |
|                  |            |  | SAE EMI Level            | 4  | 4        | -    |

### 5.3.11 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

#### Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

**Table 33. ESD absolute maximum ratings**

| Symbol                | Ratings   | Conditions  | Class | Maximum value <sup>(1)</sup> | Unit |
|-----------------------|---|---|-------|------------------------------|------|
| V <sub>ESD(HBM)</sub> | Electrostatic discharge voltage (human body model)    | T <sub>A</sub> = +25 °C conforming to JESD22-A114 | 2     | 2000                         | V    |
| V <sub>ESD(CDM)</sub> | Electrostatic discharge voltage (charge device model) | T <sub>A</sub> = +25 °C conforming to JESD22-C101 | II    | 500                          |      |

1. Based on characterization results, not tested in production.

#### Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

**Table 34. Electrical sensitivities**

| Symbol | Parameter             | Conditions                                     | Class      |
|--------|-----------------------|--|------------|
| LU     | Static latch-up class | T <sub>A</sub> = +105 °C conforming to JESD78A | II level A |

### 5.3.12 I/O port characteristics

#### General input/output characteristics

Unless otherwise specified, the parameters given in [Table 35](#) are derived from tests performed under the conditions summarized in [Table 9](#). All I/Os are CMOS and TTL compliant.

**Table 35. I/O static characteristics**

| Symbol    | Parameter   |                          | Conditions  | Min                         | Typ | Max           | Unit       |
|-----------|---|--------------------------|---|-----------------------------|-----|---------------|------------|
| $V_{IL}$  | Input low level voltage                                       |                          | TTL ports   | -0.5                        |     | 0.8           | V          |
| $V_{IH}$  | Standard IO input high level voltage                          |                          |   | 2                           |     | $V_{DD}+0.5$  |            |
|           | IO FT <sup>(1)</sup> input high level voltage                 |                          |   | 2                           |     | 5.5V          |            |
| $V_{IL}$  | Input low level voltage                                       |                          | CMOS ports  | -0.5                        |     | $0.35 V_{DD}$ | V          |
| $V_{IH}$  | Input high level voltage                                      |                          |   | $0.65 V_{DD}$               |     | $V_{DD}+0.5$  |            |
| $V_{hys}$ | Standard IO Schmitt trigger voltage hysteresis <sup>(2)</sup> |                          |   | 200                         |     |               | mV         |
|           | IO FT Schmitt trigger voltage hysteresis <sup>(2)</sup>       |                          |   | $5\% V_{DD}$ <sup>(3)</sup> |     |               | mV         |
| $I_{Ikg}$ | Input leakage current <sup>(4)</sup>                          |                          | $V_{SS} \leq V_{IN} \leq V_{DD}$<br>Standard I/Os |                             |     | $\pm 1$       | $\mu A$    |
|           |   |                          | $V_{IN} = 5 V, I/O FT$                            |                             |     | 3             |            |
| $R_{PU}$  | Weak pull-up equivalent resistor <sup>(5)</sup>               | All pins except for PA10 | $V_{IN} = V_{SS}$                                 | 30                          | 40  | 50            | k $\Omega$ |
|           |   | PA10                     |   | 8                           | 11  | 15            |            |
| $R_{PD}$  | Weak pull-down equivalent resistor <sup>(5)</sup>             | All pins except for PA10 | $V_{IN} = V_{DD}$                                 | 30                          | 40  | 50            | k $\Omega$ |
|           |   | PA10                     |   | 8                           | 11  | 15            |            |
| $C_{IO}$  | I/O pin capacitance   |                          |   |                             | 5   |               | pF         |

1. FT = Five-volt tolerant.
2. Hysteresis voltage between Schmitt trigger switching levels. Based on characterization, not tested in production.
3. With a minimum of 100 mV.
4. Leakage could be higher than max. if negative current is injected on adjacent pins.
5. Pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This MOS/NMOS contribution to the series resistance is minimum (~10% order).

All I/Os are CMOS and TTL compliant (no software configuration required), their characteristics consider the most strict CMOS-technology or TTL parameters:

- For  $V_{IH}$ :
  - if  $V_{DD}$  is in the [2.00 V - 3.08 V] range: CMOS characteristics but TTL included
  - if  $V_{DD}$  is in the [3.08 V - 3.60 V] range: TTL characteristics but CMOS included
- For  $V_{IL}$ :
  - if  $V_{DD}$  is in the [2.00 V - 2.28 V] range: TTL characteristics but CMOS included
  - if  $V_{DD}$  is in the [2.28 V - 3.60 V] range: CMOS characteristics but TTL included

### Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to +/-8 mA, and sink +20 mA (with a relaxed  $V_{OL}$ ).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 5.2](#):

- The sum of the currents sourced by all the I/Os on  $V_{DD}$ , plus the maximum Run consumption of the MCU sourced on  $V_{DD}$ , cannot exceed the absolute maximum rating  $I_{VDD}$  (see [Table 7](#)).
- The sum of the currents sunk by all the I/Os on  $V_{SS}$  plus the maximum Run consumption of the MCU sunk on  $V_{SS}$  cannot exceed the absolute maximum rating  $I_{VSS}$  (see [Table 7](#)).

### Output voltage levels

Unless otherwise specified, the parameters given in [Table 36](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#). All I/Os are CMOS and TTL compliant.

**Table 36. Output voltage characteristics**

| Symbol            | Parameter   | Conditions  | Min          | Max | Unit |
|-------------------|---|---|--------------|-----|------|
| $V_{OL}^{(1)}$    | Output low level voltage for an I/O pin when 8 pins are sunk at same time     | TTL port<br>$I_{IO} = +8 \text{ mA}$<br>$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$  |              | 0.4 | V    |
| $V_{OH}^{(2)}$    | Output high level voltage for an I/O pin when 8 pins are sourced at same time |   | $V_{DD}-0.4$ |     |      |
| $V_{OL}^{(1)}$    | Output low level voltage for an I/O pin when 8 pins are sunk at same time     | CMOS port<br>$I_{IO} = +8 \text{ mA}$<br>$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$ |              | 0.4 | V    |
| $V_{OH}^{(2)}$    | Output high level voltage for an I/O pin when 8 pins are sourced at same time |   | 2.4          |     |      |
| $V_{OL}^{(1)(3)}$ | Output low level voltage for an I/O pin when 8 pins are sunk at same time     | $I_{IO} = +20 \text{ mA}$<br>$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$             |              | 1.3 | V    |
| $V_{OH}^{(2)(3)}$ | Output high level voltage for an I/O pin when 8 pins are sourced at same time |   | $V_{DD}-1.3$ |     |      |
| $V_{OL}^{(1)(3)}$ | Output low level voltage for an I/O pin when 8 pins are sunk at same time     | $I_{IO} = +6 \text{ mA}$<br>$2 \text{ V} < V_{DD} < 2.7 \text{ V}$                |              | 0.4 | V    |
| $V_{OH}^{(2)(3)}$ | Output high level voltage for an I/O pin when 8 pins are sourced at same time |   | $V_{DD}-0.4$ |     |      |

1. The  $I_{IO}$  current sunk by the device must always respect the absolute maximum rating specified in [Table 7](#) and the sum of  $I_{IO}$  (I/O ports and control pins) must not exceed  $I_{VSS}$ .
2. The  $I_{IO}$  current sourced by the device must always respect the absolute maximum rating specified in [Table 7](#) and the sum of  $I_{IO}$  (I/O ports and control pins) must not exceed  $I_{VDD}$ .
3. Based on characterization data, not tested in production.

**Input/output AC characteristics**

The definition and values of input/output AC characteristics are given in [Figure 17](#) and [Table 37](#), respectively.

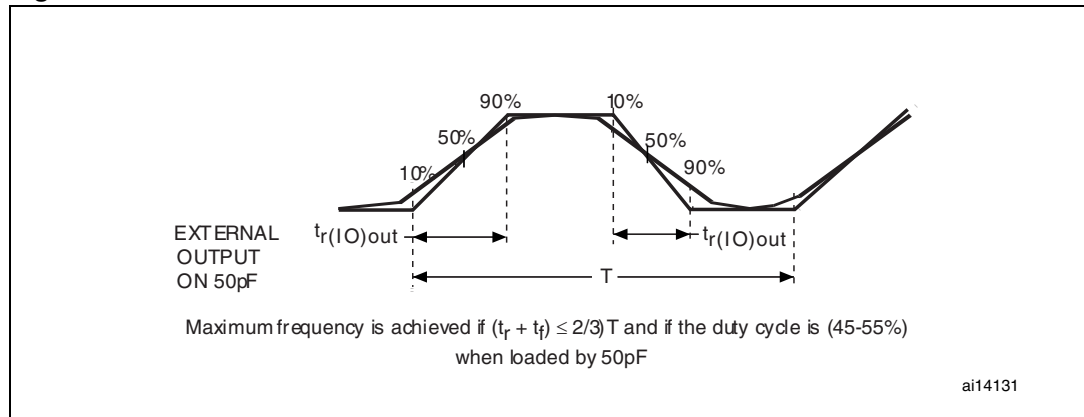
Unless otherwise specified, the parameters given in [Table 37](#) are derived from tests performed under the ambient temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 9](#).

**Table 37. I/O AC characteristics<sup>(1)</sup>**

| MODEx[1:0] bit value <sup>(1)</sup> | Symbol                  | Parameter   | Conditions   | Min | Max                | Unit |
|-------------------------------------|-------------------------|---|--|-----|--------------------|------|
| 10                                  | f <sub>max(IO)out</sub> | Maximum frequency <sup>(2)</sup>                                | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 3.6 V   |     | 2                  | MHz  |
|                                     | t <sub>f(IO)out</sub>   | Output high to low level fall time                              | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 3.6 V   |     | 125 <sup>(3)</sup> | ns   |
|                                     | t <sub>r(IO)out</sub>   | Output low to high level rise time                              |  |     | 125 <sup>(3)</sup> |      |
| 01                                  | f <sub>max(IO)out</sub> | Maximum frequency <sup>(2)</sup>                                | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 3.6 V   |     | 10                 | MHz  |
|                                     | t <sub>f(IO)out</sub>   | Output high to low level fall time                              | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 3.6 V   |     | 25 <sup>(3)</sup>  | ns   |
|                                     | t <sub>r(IO)out</sub>   | Output low to high level rise time                              |  |     | 25 <sup>(3)</sup>  |      |
| 11                                  | F <sub>max(IO)out</sub> | Maximum frequency <sup>(2)</sup>                                | C <sub>L</sub> = 30 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 50                 | MHz  |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 30                 | MHz  |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 2.7 V   |     | 20                 | MHz  |
|                                     | t <sub>f(IO)out</sub>   | Output high to low level fall time                              | C <sub>L</sub> = 30 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 5 <sup>(3)</sup>   | ns   |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 8 <sup>(3)</sup>   |      |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 2.7 V   |     | 12 <sup>(3)</sup>  |      |
|                                     | t <sub>r(IO)out</sub>   | Output low to high level rise time                              | C <sub>L</sub> = 30 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 5 <sup>(3)</sup>   |      |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2.7 V to 3.6 V |     | 8 <sup>(3)</sup>   |      |
|                                     |                         |   | C <sub>L</sub> = 50 pF, V <sub>DD</sub> = 2 V to 2.7 V   |     | 12 <sup>(3)</sup>  |      |
| -                                   | t <sub>EXTIpw</sub>     | Pulse width of external signals detected by the EXTI controller |  | 10  |                    | ns   |

1. The I/O speed is configured using the MODEx[1:0] bits. Refer to the STM32F10xxx reference manual for a description of GPIO Port configuration register.
2. The maximum frequency is defined in [Figure 17](#).
3. Guaranteed by design, not tested in production.

Figure 17. I/O AC characteristics definition



### 5.3.13 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor,  $R_{PU}$  (see [Table 35](#)).

Unless otherwise specified, the parameters given in [Table 38](#) are derived from tests performed under the ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

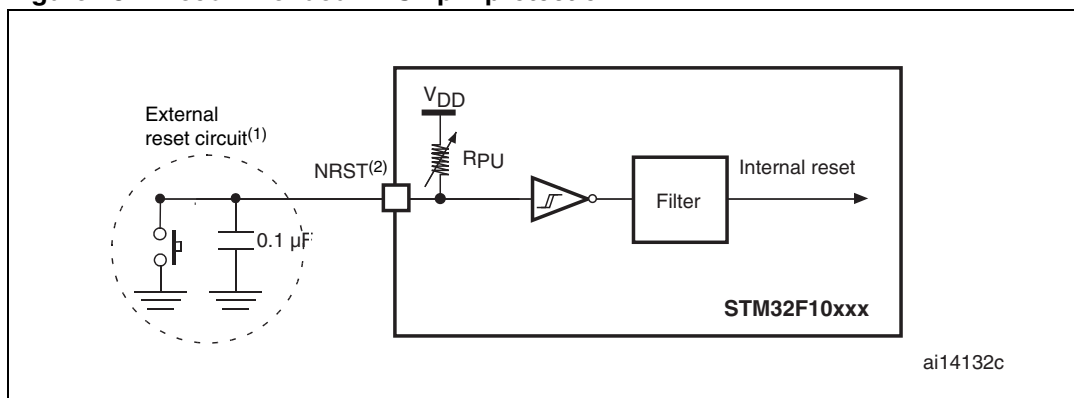
Table 38. NRST pin characteristics

| Symbol               | Parameter                                       | Conditions        | Min  | Typ | Max          | Unit       |
|----------------------|---|-------------------|------|-----|--------------|------------|
| $V_{IL(NRST)}^{(1)}$ | NRST Input low level voltage                    |                   | -0.5 |     | 0.8          | V          |
| $V_{IH(NRST)}^{(1)}$ | NRST Input high level voltage                   |                   | 2    |     | $V_{DD}+0.5$ |            |
| $V_{hys(NRST)}$      | NRST Schmitt trigger voltage hysteresis         |                   |      | 200 |              | mV         |
| $R_{PU}$             | Weak pull-up equivalent resistor <sup>(2)</sup> | $V_{IN} = V_{SS}$ | 30   | 40  | 50           | k $\Omega$ |
| $V_{F(NRST)}^{(1)}$  | NRST Input filtered pulse                       |                   |      |     | 100          | ns         |
| $V_{NF(NRST)}^{(1)}$ | NRST Input not filtered pulse                   | $V_{DD} > 2.7 V$  | 300  |     |              | ns         |

1. Guaranteed by design, not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance must be minimum (~10% order).



Figure 18. Recommended NRST pin protection



2. The reset network protects the device against parasitic resets.
3. The user must ensure that the level on the NRST pin can go below the  $V_{IL(NRST)}$  max level specified in [Table 38](#). Otherwise the reset will not be taken into account by the device.

### 5.3.14 TIM timer characteristics

The parameters given in [Table 39](#) are guaranteed by design.

Refer to [Section 5.3.12: I/O port characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 39. TIMx<sup>(1)</sup> characteristics

| Symbol           | Parameter   | Conditions                     | Min    | Max                  | Unit          |
|------------------|---|--------------------------------|--------|----------------------|---------------|
| $t_{res(TIM)}$   | Timer resolution time                                       |                                | 1      |                      | $t_{TIMxCLK}$ |
|                  |   | $f_{TIMxCLK} = 72 \text{ MHz}$ | 13.9   |                      | ns            |
| $f_{EXT}$        | Timer external clock frequency on CH1 to CH4                |                                | 0      | $f_{TIMxCLK}/2$      | MHz           |
|                  |   | $f_{TIMxCLK} = 72 \text{ MHz}$ | 0      | 36                   | MHz           |
| $Res_{TIM}$      | Timer resolution  |                                |        | 16                   | bit           |
| $t_{COUNTER}$    | 16-bit counter clock period when internal clock is selected |                                | 1      | 65536                | $t_{TIMxCLK}$ |
|                  |   | $f_{TIMxCLK} = 72 \text{ MHz}$ | 0.0139 | 910                  | μs            |
| $t_{MAX\_COUNT}$ | Maximum possible count                                      |                                |        | $65536 \times 65536$ | $t_{TIMxCLK}$ |
|                  |   | $f_{TIMxCLK} = 72 \text{ MHz}$ |        | 59.6                 | s             |

1. TIMx is used as a general term to refer to the TIM1, TIM2, TIM3, TIM4 and TIM5 timers.

### 5.3.15 Communications interfaces

#### I<sup>2</sup>C interface characteristics

Unless otherwise specified, the parameters given in [Table 40](#) are derived from tests performed under the ambient temperature,  $f_{PCLK1}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

The STM32F105xx and STM32F107xx I<sup>2</sup>C interface meets the requirements of the standard I<sup>2</sup>C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and  $V_{DD}$  is disabled, but is still present.

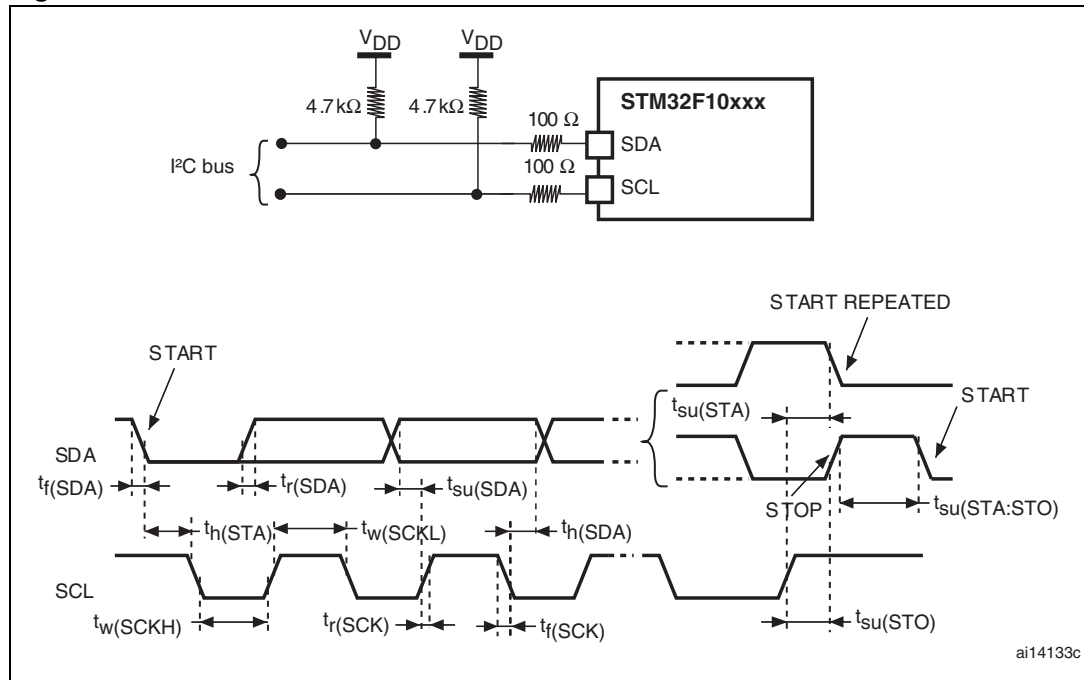
The I<sup>2</sup>C characteristics are described in [Table 40](#). Refer also to [Section 5.3.12: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

**Table 40. I<sup>2</sup>C characteristics**

| Symbol                       | Parameter                               | Standard mode I <sup>2</sup> C <sup>(1)</sup> |      | Fast mode I <sup>2</sup> C <sup>(1)(2)</sup> |                    | Unit    |
|------------------------------|---|---|------|--|--------------------|---------|
|                              |   | Min   | Max  | Min  | Max                |         |
| $t_{w(SCLL)}$                | SCL clock low time                      | 4.7   |      | 1.3  |                    | $\mu$ s |
| $t_{w(SCLH)}$                | SCL clock high time                     | 4.0   |      | 0.6  |                    |         |
| $t_{su(SDA)}$                | SDA setup time                          | 250   |      | 100  |                    | ns      |
| $t_{h(SDA)}$                 | SDA data hold time                      | 0 <sup>(3)</sup>                              |      | 0 <sup>(4)</sup>                             | 900 <sup>(3)</sup> |         |
| $t_{r(SDA)}$<br>$t_{r(SCL)}$ | SDA and SCL rise time                   |   | 1000 | $20 + 0.1C_b$                                | 300                |         |
| $t_{f(SDA)}$<br>$t_{f(SCL)}$ | SDA and SCL fall time                   |   | 300  |  | 300                |         |
| $t_{h(STA)}$                 | Start condition hold time               | 4.0   |      | 0.6  |                    | $\mu$ s |
| $t_{su(STA)}$                | Repeated Start condition setup time     | 4.7   |      | 0.6  |                    |         |
| $t_{su(STO)}$                | Stop condition setup time               | 4.0   |      | 0.6  |                    | $\mu$ s |
| $t_{w(STO:STA)}$             | Stop to Start condition time (bus free) | 4.7   |      | 1.3  |                    | $\mu$ s |
| $C_b$                        | Capacitive load for each bus line       |   | 400  |  | 400                | pF      |

1. Guaranteed by design, not tested in production.
2.  $f_{PCLK1}$  must be higher than 2 MHz to achieve the maximum standard mode I<sup>2</sup>C frequency. It must be higher than 4 MHz to achieve the maximum fast mode I<sup>2</sup>C frequency.
3. The maximum hold time of the Start condition has only to be met if the interface does not stretch the low period of SCL signal.
4. The device must internally provide a hold time of at least 300ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL.

Figure 19. I<sup>2</sup>C bus AC waveforms and measurement circuit



1. Measurement points are done at CMOS levels: 0.3V<sub>DD</sub> and 0.7V<sub>DD</sub>.

Table 41. SCL frequency (f<sub>PCLK1</sub> = 36 MHz, V<sub>DD</sub> = 3.3 V)<sup>(1)(2)</sup>

| f <sub>SCL</sub> (kHz) | I2C_CCR value           |
|------------------------|-------------------------|
|                        | R <sub>p</sub> = 4.7 kΩ |
| 400                    | 0x801E                  |
| 300                    | 0x8028                  |
| 200                    | 0x803C                  |
| 100                    | 0x00B4                  |
| 50                     | 0x0168                  |
| 20                     | 0x0384                  |

1. R<sub>p</sub> = External pull-up resistance, f<sub>SCL</sub> = I<sup>2</sup>C speed,
2. For speeds around 200 kHz, the tolerance on the achieved speed is of ±5%. For other speed ranges, the tolerance on the achieved speed ±2%. These variations depend on the accuracy of the external components used to design the application.

## I<sup>2</sup>S - SPI interface characteristics

Unless otherwise specified, the parameters given in [Table 42](#) for SPI or in [Table 43](#) for I<sup>2</sup>S are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

Refer to [Section 5.3.12: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI and WS, CK, SD for I<sup>2</sup>S).

**Table 42. SPI characteristics<sup>(1)</sup>**

| Symbol                                     | Parameter                        | Conditions                                     | Min          | Max          | Unit |
|--|----------------------------------|--|--------------|--------------|------|
| $f_{SCK}$<br>$1/t_{c(SCK)}$                | SPI clock frequency              | Master mode                                    |              | 18           | MHz  |
|  |                                  | Slave mode                                     |              | 18           |      |
| $t_{r(SCK)}$<br>$t_{f(SCK)}$               | SPI clock rise and fall time     | Capacitive load: C = 30 pF                     |              | 8            | ns   |
| DuCy(SCK)                                  | SPI slave input clock duty cycle | Slave mode                                     | 30           | 70           | %    |
| $t_{su(NSS)}^{(2)}$                        | NSS setup time                   | Slave mode                                     | 4 $t_{PCLK}$ |              | ns   |
| $t_{h(NSS)}^{(2)}$                         | NSS hold time                    | Slave mode                                     | 2 $t_{PCLK}$ |              |      |
| $t_{w(SCKH)}^{(2)}$<br>$t_{w(SCKL)}^{(2)}$ | SCK high and low time            | Master mode, $f_{PCLK} = 36$ MHz,<br>presc = 4 | 50           | 60           |      |
| $t_{su(MI)}^{(2)}$<br>$t_{su(SI)}^{(2)}$   | Data input setup time            | Master mode                                    | 5            |              |      |
|  |                                  | Slave mode                                     | 5            |              |      |
| $t_{h(MI)}^{(2)}$<br>$t_{h(SI)}^{(2)}$     | Data input hold time             | Master mode                                    | 5            |              |      |
|  |                                  | Slave mode                                     | 4            |              |      |
| $t_{a(SO)}^{(2)(3)}$                       | Data output access time          | Slave mode, $f_{PCLK} = 20$ MHz                | 0            | 3 $t_{PCLK}$ |      |
| $t_{dis(SO)}^{(2)(4)}$                     | Data output disable time         | Slave mode                                     | 2            | 10           |      |
| $t_{v(SO)}^{(2)(1)}$                       | Data output valid time           | Slave mode (after enable edge)                 |              | 25           |      |
| $t_{v(MO)}^{(2)(1)}$                       | Data output valid time           | Master mode (after enable edge)                |              | 5            |      |
| $t_{h(SO)}^{(2)}$<br>$t_{h(MO)}^{(2)}$     | Data output hold time            | Slave mode (after enable edge)                 | 15           |              |      |
|  |                                  | Master mode (after enable edge)                | 2            |              |      |

1. Remapped SPI1 characteristics to be determined.
2. Based on characterization, not tested in production.
3. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
4. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z

Figure 20. SPI timing diagram - slave mode and CPHA = 0

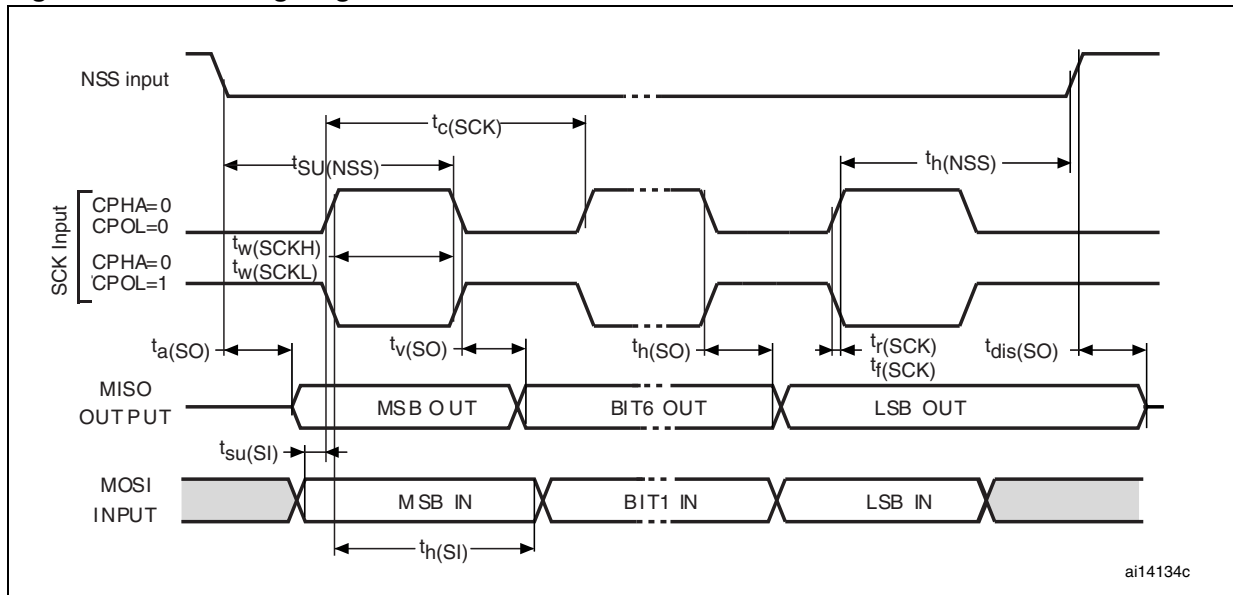
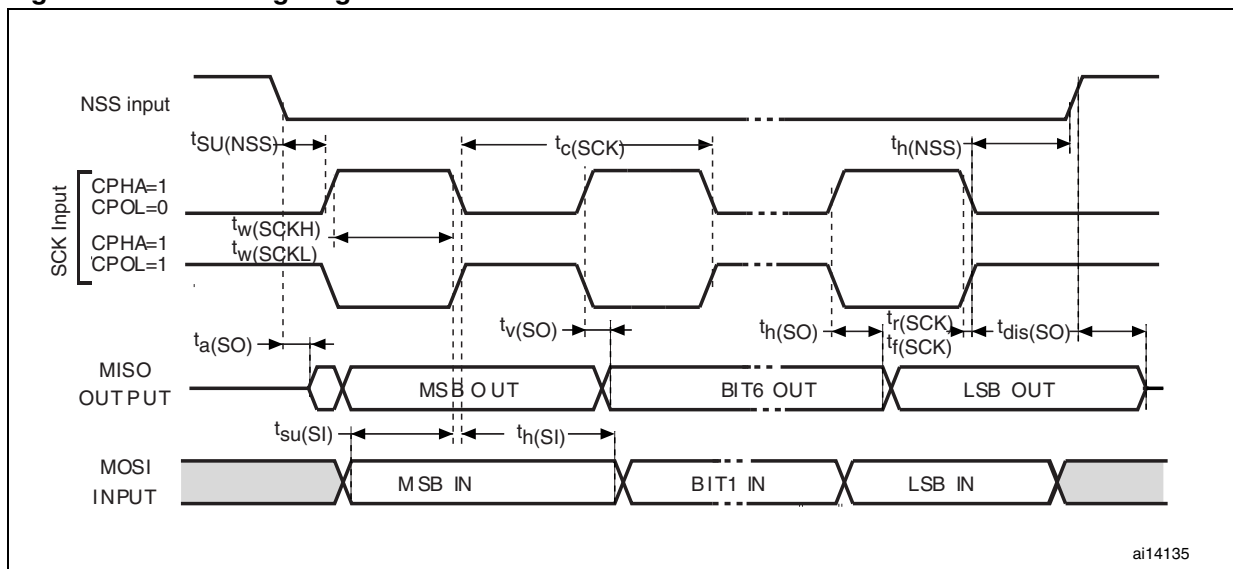
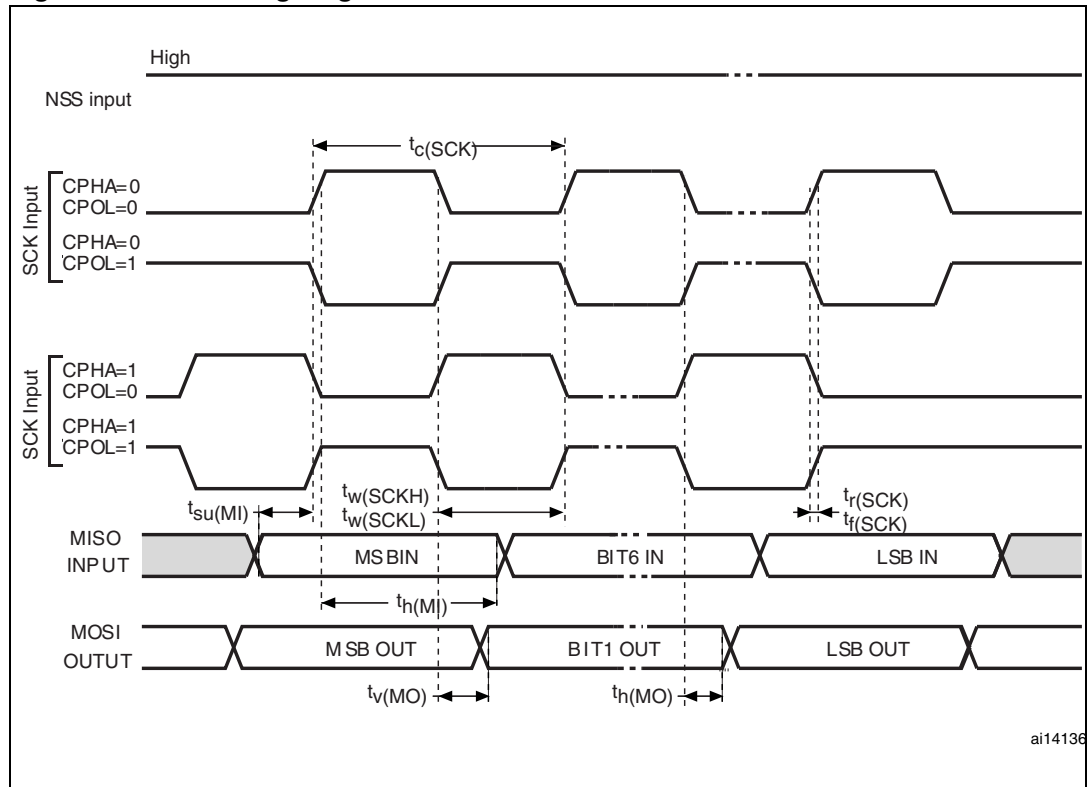


Figure 21. SPI timing diagram - slave mode and CPHA = 1<sup>(1)</sup>



1. Measurement points are done at CMOS levels: 0.3V<sub>DD</sub> and 0.7V<sub>DD</sub>.

Figure 22. SPI timing diagram - master mode<sup>(1)</sup>



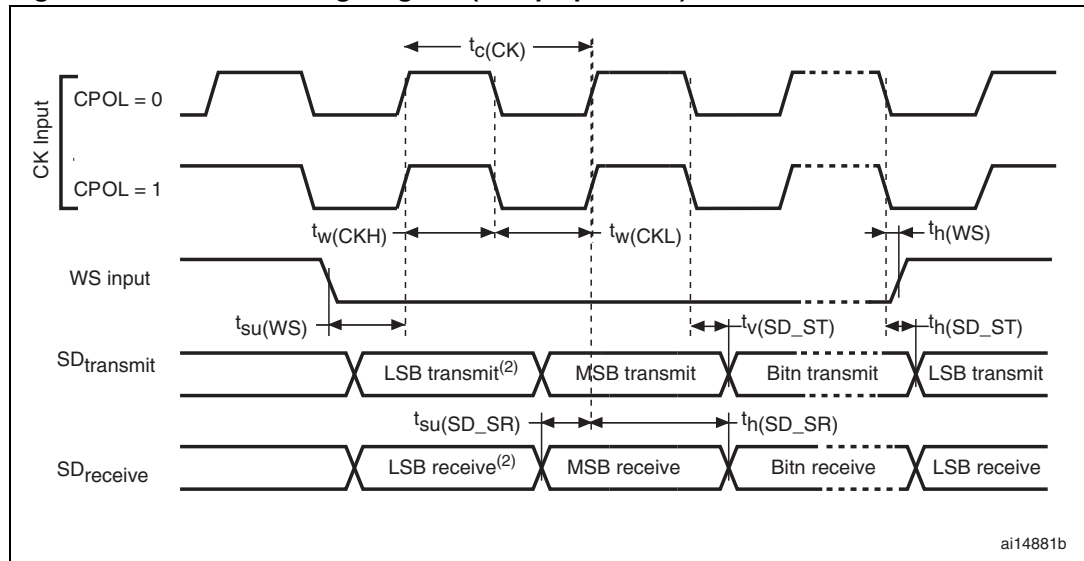
1. Measurement points are done at CMOS levels:  $0.3V_{DD}$  and  $0.7V_{DD}$ .

**Table 43. I<sup>2</sup>S characteristics (1)**

| Symbol   | Parameter                                 | Conditions  | Min        | Max | Unit |
|--|---|---|------------|-----|------|
| f <sub>CK</sub><br>1/t <sub>c(CK)</sub>  | I <sup>2</sup> S clock frequency          | Master  | TBD        | TBD | MHz  |
|  |   | Slave   | 0          | TBD |      |
| t <sub>r(CK)</sub><br>t <sub>f(CK)</sub>   | I <sup>2</sup> S clock rise and fall time | capacitive load<br>C <sub>L</sub> = 50 pF                       |            | TBD | ns   |
| t <sub>v(WS)</sub> <sup>(2)</sup>  | WS valid time                             | Master  | TBD        |     |      |
| t <sub>h(WS)</sub> <sup>(2)</sup>  | WS hold time                              | Master  | TBD        |     |      |
| t <sub>su(WS)</sub> <sup>(2)</sup>   | WS setup time                             | Slave   | TBD        |     |      |
| t <sub>h(WS)</sub> <sup>(2)</sup>  | WS hold time                              | Slave   | TBD        |     |      |
| t <sub>w(CKH)</sub> <sup>(2)</sup><br>t <sub>w(CKL)</sub> <sup>(2)</sup>           | CK high and low time                      | Master f <sub>PCLK</sub> = TBD,<br>presc = TBD                  | TBD        |     |      |
| t <sub>su(SD_MR)</sub> <sup>(2)</sup><br>t <sub>su(SD_SR)</sub> <sup>(2)</sup>     | Data input setup time                     | Master receiver<br>Slave receiver                               | TBD<br>TBD |     |      |
| t <sub>h(SD_MR)</sub> <sup>(2)(3)</sup><br>t <sub>h(SD_SR)</sub> <sup>(2)(3)</sup> | Data input hold time                      | Master receiver<br>Slave receiver                               | TBD<br>TBD |     |      |
| t <sub>h(SD_MR)</sub> <sup>(2)</sup><br>t <sub>h(SD_SR)</sub> <sup>(2)</sup>       | Data input hold time                      | Master f <sub>PCLK</sub> = TBD<br>Slave f <sub>PCLK</sub> = TBD | TBD<br>TBD |     |      |
| t <sub>v(SD_ST)</sub> <sup>(2)(3)</sup>  | Data output valid time                    | Slave transmitter<br>(after enable edge)                        |            | TBD |      |
|  |   | f <sub>PCLK</sub> = TBD   |            | TBD |      |
| t <sub>h(SD_ST)</sub> <sup>(2)</sup>   | Data output hold time                     | Slave transmitter<br>(after enable edge)                        | TBD        |     |      |
| t <sub>v(SD_MT)</sub> <sup>(2)(3)</sup>  | Data output valid time                    | Master transmitter<br>(after enable edge)                       |            | TBD |      |
|  |   | f <sub>PCLK</sub> = TBD   | TBD        | TBD |      |
| t <sub>h(SD_MT)</sub> <sup>(2)</sup>   | Data output hold time                     | Master transmitter<br>(after enable edge)                       | TBD        |     |      |

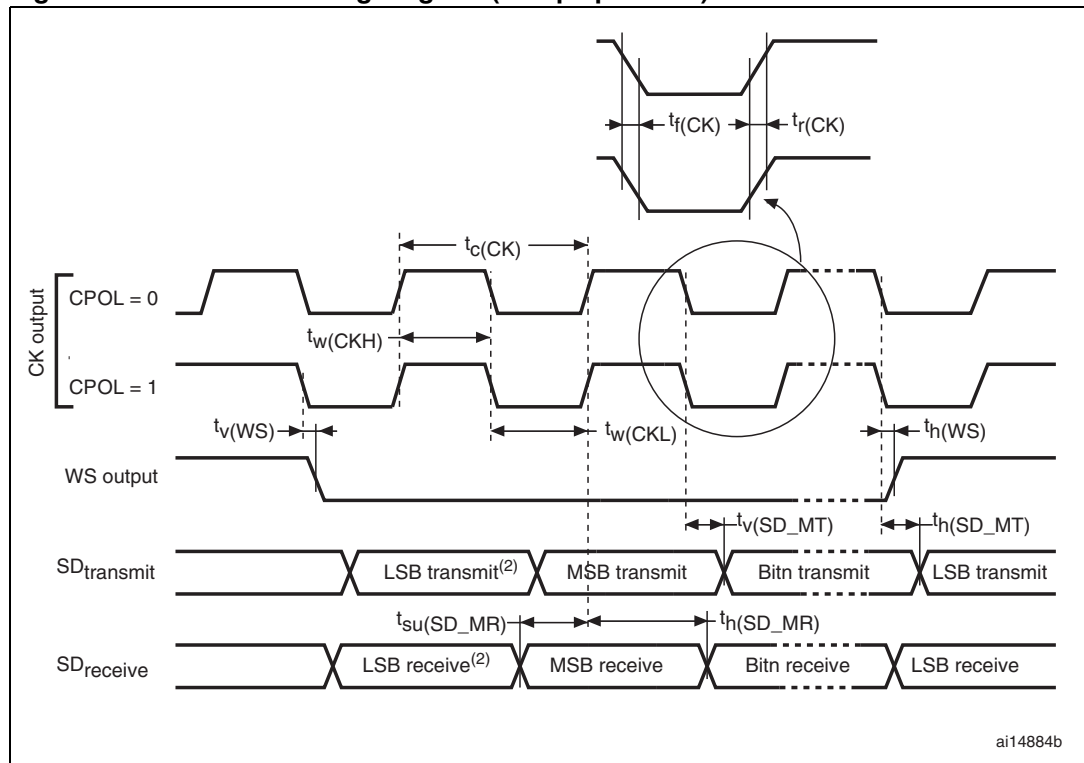
1. TBD = to be determined.
2. Based on design simulation and/or characterization results, not tested in production.
3. Depends on f<sub>PCLK</sub>. For example, if f<sub>PCLK</sub>=8 MHz, then T<sub>PCLK</sub> = 1/f<sub>PCLK</sub> =125 ns.

Figure 23. I<sup>2</sup>S slave timing diagram (Philips protocol)<sup>(1)</sup>



1. Measurement points are done at CMOS levels:  $0.3 \times V_{DD}$  and  $0.7 \times V_{DD}$ .
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

Figure 24. I<sup>2</sup>S master timing diagram (Philips protocol)<sup>(1)</sup>



1. Based on characterization, not tested in production.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.



**USB OTG FS characteristics**

The USB OTG interface is USB-IF certified (Full-Speed).

**Table 44. USB OTG FS startup time**

| Symbol              | Parameter                           | Max | Unit    |
|---------------------|-------------------------------------|-----|---------|
| $t_{STARTUP}^{(1)}$ | USB OTG FS transceiver startup time | 1   | $\mu s$ |

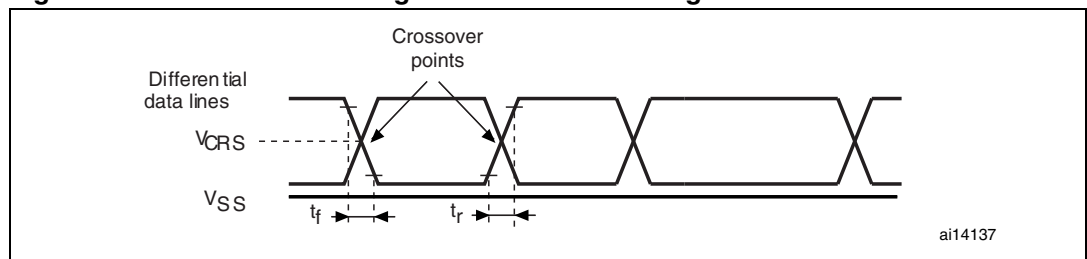
1. Guaranteed by design, not tested in production.

**Table 45. USB OTG FS DC electrical characteristics**

| Symbol        | Parameter                          | Conditions                      | Min. <sup>(1)</sup>                             | Typ. | Max. <sup>(1)</sup> | Unit       |
|---------------|------------------------------------|---------------------------------|---|------|---------------------|------------|
| Input levels  | $V_{DD}$                           | USB OTG FS operating voltage    | 3.0 <sup>(2)</sup>                              |      | 3.6                 | V          |
|               | $V_{DI}^{(3)}$                     | Differential input sensitivity  | I(USBDP, USBDM)                                 | 0.2  |                     | V          |
|               | $V_{CM}^{(3)}$                     | Differential common mode range  | Includes $V_{DI}$ range                         | 0.8  | 2.5                 |            |
|               | $V_{SE}^{(3)}$                     | Single ended receiver threshold |   | 1.3  | 2.0                 |            |
| Output levels | $V_{OL}$                           | Static output level low         | $R_L$ of 1.5 k $\Omega$ to 3.6 V <sup>(4)</sup> |      | 0.3                 | V          |
|               | $V_{OH}$                           | Static output level high        | $R_L$ of 15 k $\Omega$ to $V_{SS}^{(4)}$        | 2.8  | 3.6                 |            |
| $R_{PD}$      | Pull-down resistance on PA11, PA12 | $V_{IN} = V_{DD}$               | 17  | 21   | 24                  | k $\Omega$ |
|               | Pull-down resistance on PA9        |                                 | 0.65  | 1.1  | 2.0                 |            |
| $R_{PU}$      | Pull-up resistance on PA12         | $V_{IN} = V_{SS}$               | 1.5   | 1.8  | 2.1                 |            |
|               | Pull-up resistance on PA9          | $V_{IN} = V_{SS}$               | 0.25  | 0.37 | 0.55                |            |

1. All the voltages are measured from the local ground potential.
2. The STM32F105xx and STM32F107xx USB OTG FS functionality is ensured down to 2.7 V but not the full USB OTG FS electrical characteristics which are degraded in the 2.7-to-3.0 V  $V_{DD}$  voltage range.
3. Guaranteed by design, not tested in production.
4.  $R_L$  is the load connected on the USB OTG FS drivers

**Figure 25. USB OTG FS timings: definition of data signal rise and fall time**



**Table 46. USB OTG FS electrical characteristics<sup>(1)</sup>**

| Driver characteristics |                                 |                       |     |     |      |
|------------------------|---------------------------------|-----------------------|-----|-----|------|
| Symbol                 | Parameter                       | Conditions            | Min | Max | Unit |
| $t_r$                  | Rise time <sup>(2)</sup>        | $C_L = 50 \text{ pF}$ | 4   | 20  | ns   |
| $t_f$                  | Fall time <sup>(2)</sup>        | $C_L = 50 \text{ pF}$ | 4   | 20  | ns   |
| $t_{rfm}$              | Rise/ fall time matching        | $t_r/t_f$             | 90  | 110 | %    |
| $V_{CRS}$              | Output signal crossover voltage |                       | 1.3 | 2.0 | V    |

1. Guaranteed by design, not tested in production.
2. Measured from 10% to 90% of the data signal. For more detailed informations, please refer to USB Specification - Chapter 7 (version 2.0).

**Ethernet characteristics**

Table 47 shows the Ethernet operating voltage.

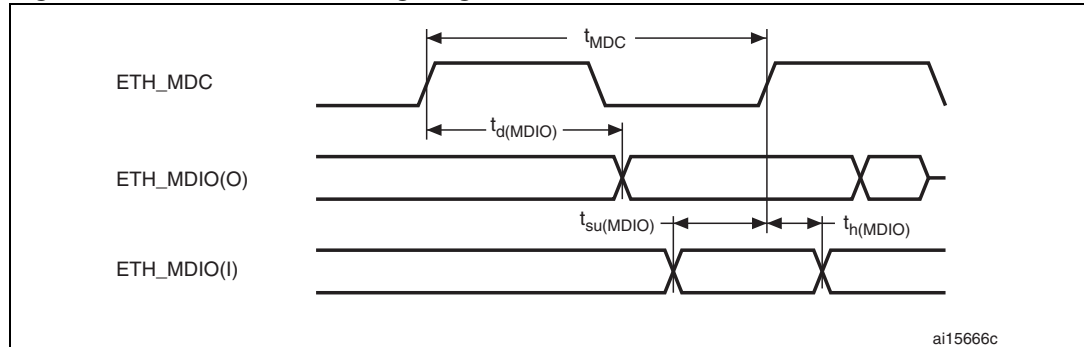
**Table 47. Ethernet DC electrical characteristics**

| Symbol               | Parameter                  | Min. <sup>(1)</sup> | Max. <sup>(1)</sup> | Unit |
|----------------------|----------------------------|---------------------|---------------------|------|
| Input level $V_{DD}$ | Ethernet operating voltage | 3.0                 | 3.6                 | V    |

1. All the voltages are measured from the local ground potential.

Table 48 gives the list of Ethernet MAC signals for the SMI (station management interface) and Figure 26 shows the corresponding timing diagram.

**Figure 26. Ethernet SMI timing diagram**



**Table 48. Dynamics characteristics: Ethernet MAC signals for SMI<sup>(1)</sup>**

| Symbol         | Rating                                  | Min   | Typ   | Max   | Unit |
|----------------|---|-------|-------|-------|------|
| $t_{MDC}$      | MDC cycle time (1.71 MHz, AHB = 72 MHz) | 582.8 | 583.3 | 584   | ns   |
| $t_{d(MDIO)}$  | MDIO write data valid time              | 305.2 | 305.9 | 306.5 | ns   |
| $t_{su(MDIO)}$ | Read data setup time                    | TBD   | TBD   | TBD   | ns   |
| $t_{h(MDIO)}$  | Read data hold time                     | TBD   | TBD   | TBD   | ns   |

1. TBD stands for to be determined.

Table 49 gives the list of Ethernet MAC signals for the RMIi and Figure 27 shows the corresponding timing diagram.

Figure 27. Ethernet RMIi timing diagram

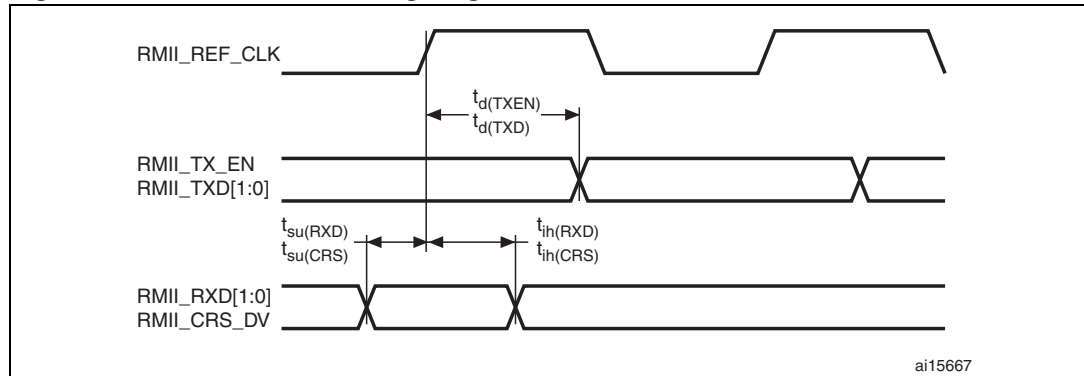


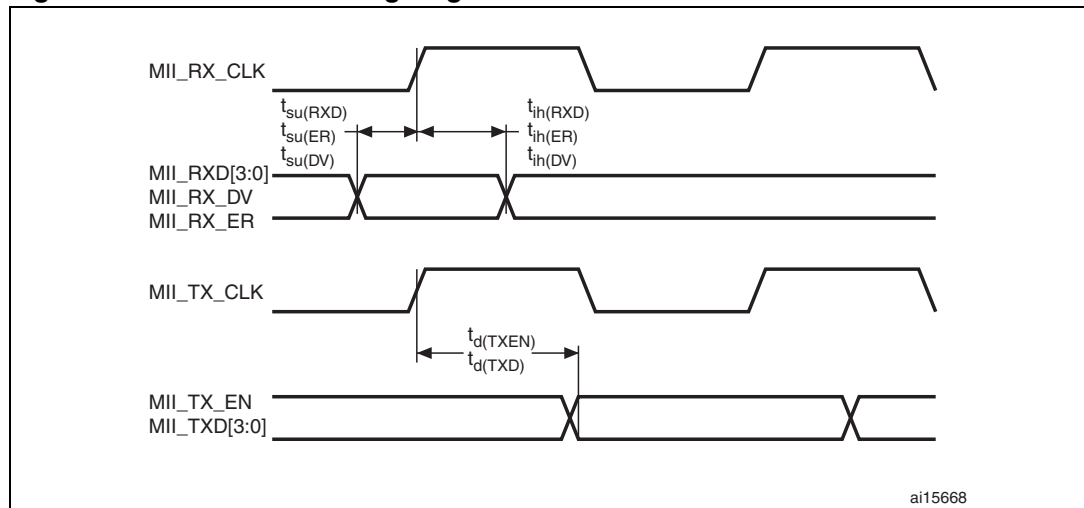
Table 49. Dynamics characteristics: Ethernet MAC signals for RMIi<sup>(1)</sup>

| Symbol        | Rating                           | Min | Typ | Max  | Unit |
|---------------|----------------------------------|-----|-----|------|------|
| $t_{su}(RXD)$ | Receive data setup time          | TBD | TBD | TBD  | ns   |
| $t_{ih}(RXD)$ | Receive data hold time           | TBD | TBD | TBD  | ns   |
| $t_{su}(CRS)$ | Carrier sense set-up time        | TBD | TBD | TBD  | ns   |
| $t_{ih}(CRS)$ | Carrier sense hold time          | TBD | TBD | TBD  | ns   |
| $t_d(TXEN)$   | Transmit enable valid delay time | 0   | 9.6 | 21.9 | ns   |
| $t_d(TXD)$    | Transmit data valid delay time   | 0   | 9.9 | 21   | ns   |

1. TBD stands for to be determined.

Table 50 gives the list of Ethernet MAC signals for MII and Figure 27 shows the corresponding timing diagram.

Figure 28. Ethernet MII timing diagram



**Table 50. Dynamics characteristics: Ethernet MAC signals for MII<sup>(1)</sup>**

| Symbol        | Rating                           | Min  | Typ  | Max  | Unit |
|---------------|----------------------------------|------|------|------|------|
| $t_{su}(RXD)$ | Receive data setup time          | TBD  | TBD  | TBD  | ns   |
| $t_{ih}(RXD)$ | Receive data hold time           | TBD  | TBD  | TBD  | ns   |
| $t_{su}(DV)$  | Data valid setup time            | TBD  | TBD  | TBD  | ns   |
| $t_{ih}(DV)$  | Data valid hold time             | TBD  | TBD  | TBD  | ns   |
| $t_{su}(ER)$  | Error setup time                 | TBD  | TBD  | TBD  | ns   |
| $t_{ih}(ER)$  | Error hold time                  | TBD  | TBD  | TBD  | ns   |
| $t_d(TXEN)$   | Transmit enable valid delay time | 13.4 | 15.5 | 17.7 | ns   |
| $t_d(TXD)$    | Transmit data valid delay time   | 12.9 | 16.1 | 19.4 | ns   |

1. TBD stands for to be determined.

### CAN (controller area network) interface

Refer to [Section 5.3.12: I/O port characteristics](#) for more details on the input/output alternate function characteristics (CANTX and CANRX).

#### 5.3.16 12-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 51](#) are derived from tests performed under the ambient temperature,  $f_{PCLK2}$  frequency and  $V_{DDA}$  supply voltage conditions summarized in [Table 9](#).

*Note:* It is recommended to perform a calibration after each power-up.

**Table 51. ADC characteristics**

| Symbol           | Parameter                               | Conditions  | Min   | Typ                | Max                | Unit        |
|------------------|---|---|---|--------------------|--------------------|-------------|
| $V_{DDA}$        | Power supply                            |   | 2.4   |                    | 3.6                | V           |
| $V_{REF+}$       | Positive reference voltage              |   | 2.4   |                    | $V_{DDA}$          | V           |
| $I_{VREF}$       | Current on the $V_{REF}$ input pin      |   |   | 160 <sup>(1)</sup> | 220 <sup>(1)</sup> | $\mu$ A     |
| $f_{ADC}$        | ADC clock frequency                     |   | 0.6   |                    | 14                 | MHz         |
| $f_S^{(2)}$      | Sampling rate                           |   | 0.05  |                    | 1                  | MHz         |
| $f_{TRIG}^{(2)}$ | External trigger frequency              | $f_{ADC} = 14$ MHz  |   |                    | 823                | kHz         |
|                  |   |   |   |                    | 17                 | $1/f_{ADC}$ |
| $V_{AIN}$        | Conversion voltage range <sup>(3)</sup> |   | 0 ( $V_{SSA}$ or $V_{REF-}$ tied to ground) |                    | $V_{REF+}$         | V           |
| $R_{AIN}^{(2)}$  | External input impedance                | See <a href="#">Equation 1</a> and <a href="#">Table 52</a> for details |   |                    | 50                 | k $\Omega$  |
| $R_{ADC}^{(2)}$  | Sampling switch resistance              |   |   |                    | 1                  | k $\Omega$  |
| $C_{ADC}^{(2)}$  | Internal sample and hold capacitor      |   |   |                    | 8                  | pF          |
| $t_{CAL}^{(2)}$  | Calibration time                        | $f_{ADC} = 14$ MHz  | 5.9   |                    |                    | $\mu$ s     |
|                  |   |   | 83  |                    |                    | $1/f_{ADC}$ |

**Table 51. ADC characteristics (continued)**

| Symbol                           | Parameter                                       | Conditions                | Min  | Typ | Max              | Unit               |
|----------------------------------|---|---------------------------|--|-----|------------------|--------------------|
| t <sub>lat</sub> <sup>(2)</sup>  | Injection trigger conversion latency            | f <sub>ADC</sub> = 14 MHz |  |     | 0.214            | μs                 |
|                                  |   |                           |  |     | 3 <sup>(4)</sup> | 1/f <sub>ADC</sub> |
| t <sub>latr</sub> <sup>(2)</sup> | Regular trigger conversion latency              | f <sub>ADC</sub> = 14 MHz |  |     | 0.143            | μs                 |
|                                  |   |                           |  |     | 2 <sup>(4)</sup> | 1/f <sub>ADC</sub> |
| t <sub>S</sub> <sup>(2)</sup>    | Sampling time                                   | f <sub>ADC</sub> = 14 MHz | 0.107  |     | 17.1             | μs                 |
|                                  |   |                           | 1.5  |     | 239.5            | 1/f <sub>ADC</sub> |
| t <sub>STAB</sub> <sup>(2)</sup> | Power-up time                                   |                           | 0  | 0   | 1                | μs                 |
| t <sub>CONV</sub> <sup>(2)</sup> | Total conversion time (including sampling time) | f <sub>ADC</sub> = 14 MHz | 1  |     | 18               | μs                 |
|                                  |   |                           | 14 to 252 (t <sub>S</sub> for sampling +12.5 for successive approximation) |     |                  | 1/f <sub>ADC</sub> |

1. Based on characterization, not tested in production.
2. Guaranteed by design, not tested in production.
3. V<sub>REF+</sub> is internally connected to V<sub>DDA</sub> and V<sub>REF-</sub> is internally connected to V<sub>SSA</sub>.
4. For external triggers, a delay of 1/f<sub>PCLK2</sub> must be added to the latency specified in [Table 51](#).

**Equation 1: R<sub>AIN</sub> max formula**

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The formula above ([Equation 1](#)) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

**Table 52. R<sub>AIN</sub> max for f<sub>ADC</sub> = 14 MHz<sup>(1)</sup>**

| T <sub>S</sub> (cycles) | t <sub>S</sub> (μs) | R <sub>AIN</sub> max (kΩ) |
|-------------------------|---------------------|---------------------------|
| 1.5                     | 0.11                | 0.4                       |
| 7.5                     | 0.54                | 5.9                       |
| 13.5                    | 0.96                | 11.4                      |
| 28.5                    | 2.04                | 25.2                      |
| 41.5                    | 2.96                | 37.2                      |
| 55.5                    | 3.96                | 50                        |
| 71.5                    | 5.11                | NA                        |
| 239.5                   | 17.1                | NA                        |

1. Based on characterization, not tested in production.

**Table 53. ADC accuracy - limited test conditions<sup>(1)</sup>**

| Symbol | Parameter                    | Test conditions   | Typ       | Max <sup>(2)</sup> | Unit |
|--------|------------------------------|---|-----------|--------------------|------|
| ET     | Total unadjusted error       | $f_{PCLK2} = 56 \text{ MHz}$ ,<br>$f_{ADC} = 14 \text{ MHz}$ , $R_{AIN} < 10 \text{ k}\Omega$ ,<br>$V_{DDA} = 3 \text{ V to } 3.6 \text{ V}$<br>$T_A = 25 \text{ }^\circ\text{C}$<br>Measurements made after<br>ADC calibration | $\pm 1.3$ | $\pm 2$            | LSB  |
| EO     | Offset error                 |   | $\pm 1$   | $\pm 1.5$          |      |
| EG     | Gain error                   |   | $\pm 0.5$ | $\pm 1.5$          |      |
| ED     | Differential linearity error |   | $\pm 0.7$ | $\pm 1$            |      |
| EL     | Integral linearity error     |   | $\pm 0.8$ | $\pm 1.5$          |      |

1. ADC DC accuracy values are measured after internal calibration.
2. Based on characterization, not tested in production.

**Table 54. ADC accuracy<sup>(1) (2)</sup>**

| Symbol | Parameter                    | Test conditions  | Typ       | Max <sup>(3)</sup> | Unit |
|--------|------------------------------|--|-----------|--------------------|------|
| ET     | Total unadjusted error       | $f_{PCLK2} = 56 \text{ MHz}$ ,<br>$f_{ADC} = 14 \text{ MHz}$ , $R_{AIN} < 10 \text{ k}\Omega$ ,<br>$V_{DDA} = 2.4 \text{ V to } 3.6 \text{ V}$<br>Measurements made after<br>ADC calibration | $\pm 2$   | $\pm 5$            | LSB  |
| EO     | Offset error                 |  | $\pm 1.5$ | $\pm 2.5$          |      |
| EG     | Gain error                   |  | $\pm 1.5$ | $\pm 3$            |      |
| ED     | Differential linearity error |  | $\pm 1$   | $\pm 2$            |      |
| EL     | Integral linearity error     |  | $\pm 1.5$ | $\pm 3$            |      |

1. ADC DC accuracy values are measured after internal calibration.
2. Better performance could be achieved in restricted  $V_{DD}$ , frequency and temperature ranges.
3. Based on characterization, not tested in production.

**Note:** ADC accuracy vs. negative injection current: Injecting a negative current on any of the standard (non-robust) analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative currents.  
 Any positive injection current within the limits specified for  $I_{INJ(PIN)}$  and  $\Sigma I_{INJ(PIN)}$  in [Section 5.3.12](#) does not affect the ADC accuracy.

Figure 29. ADC accuracy characteristics

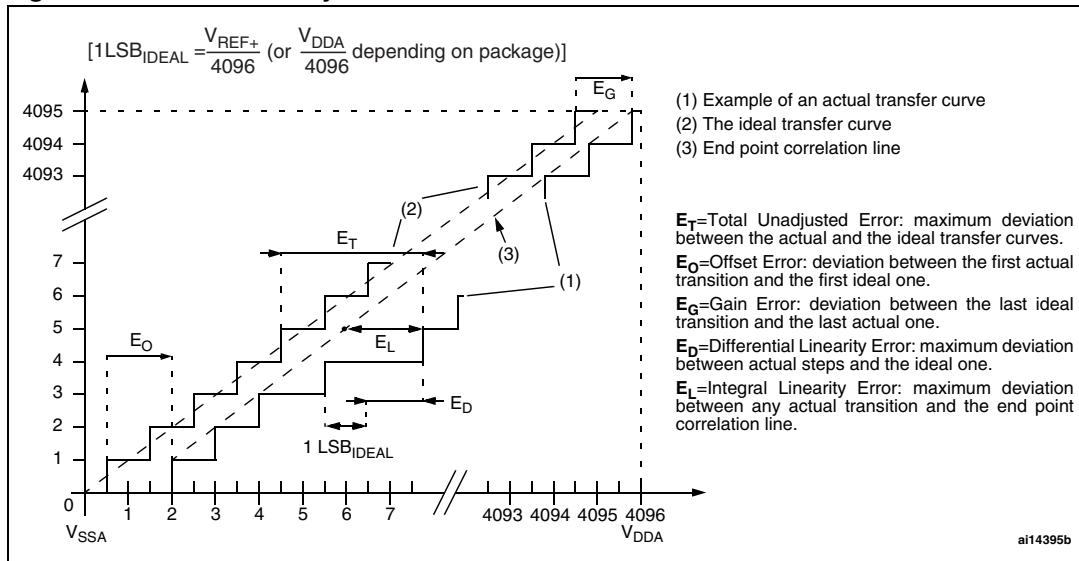
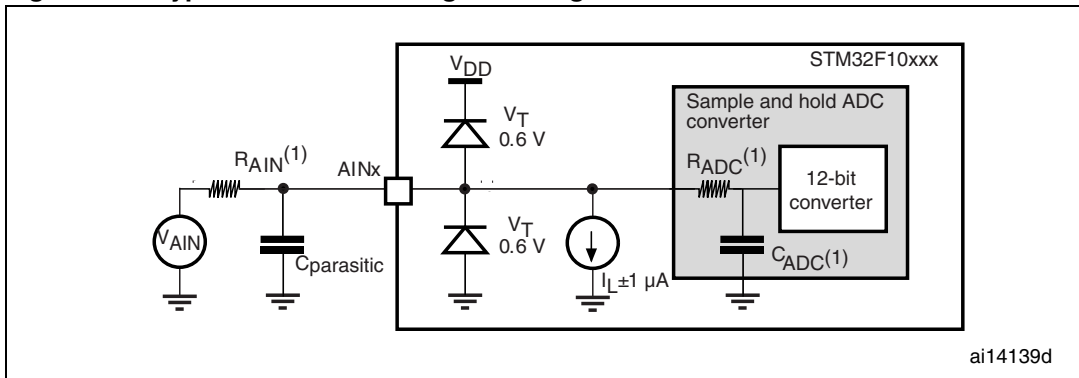


Figure 30. Typical connection diagram using the ADC

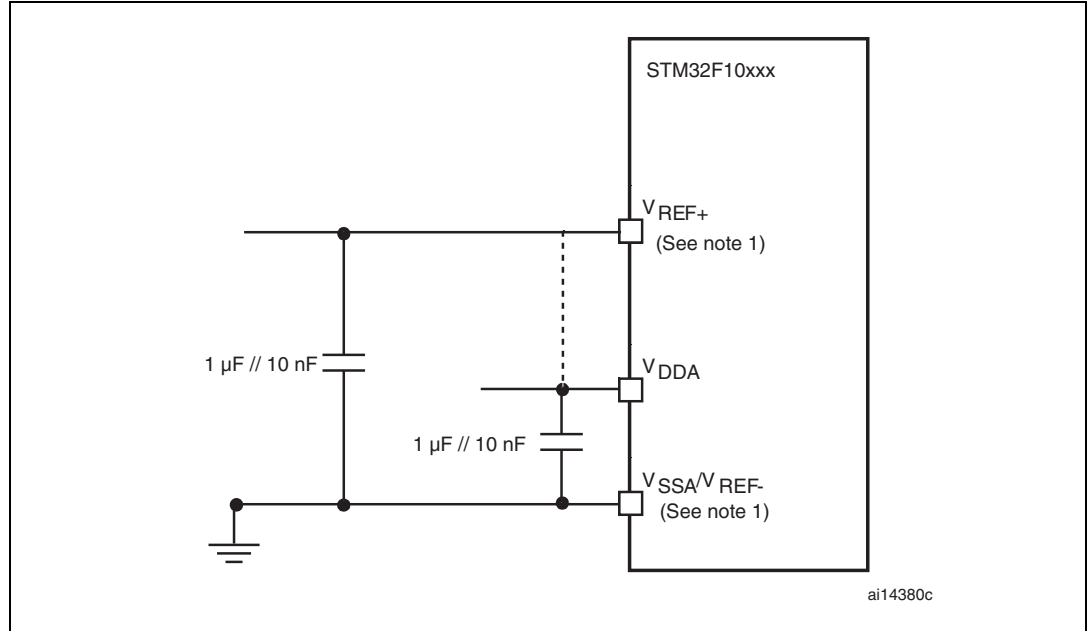


1. Refer to [Table 51](#) for the values of  $R_{\text{AIN}}$ ,  $R_{\text{ADC}}$  and  $C_{\text{ADC}}$ .
2.  $C_{\text{parasitic}}$  represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high  $C_{\text{parasitic}}$  value will downgrade conversion accuracy. To remedy this,  $f_{\text{ADC}}$  should be reduced.

**General PCB design guidelines**

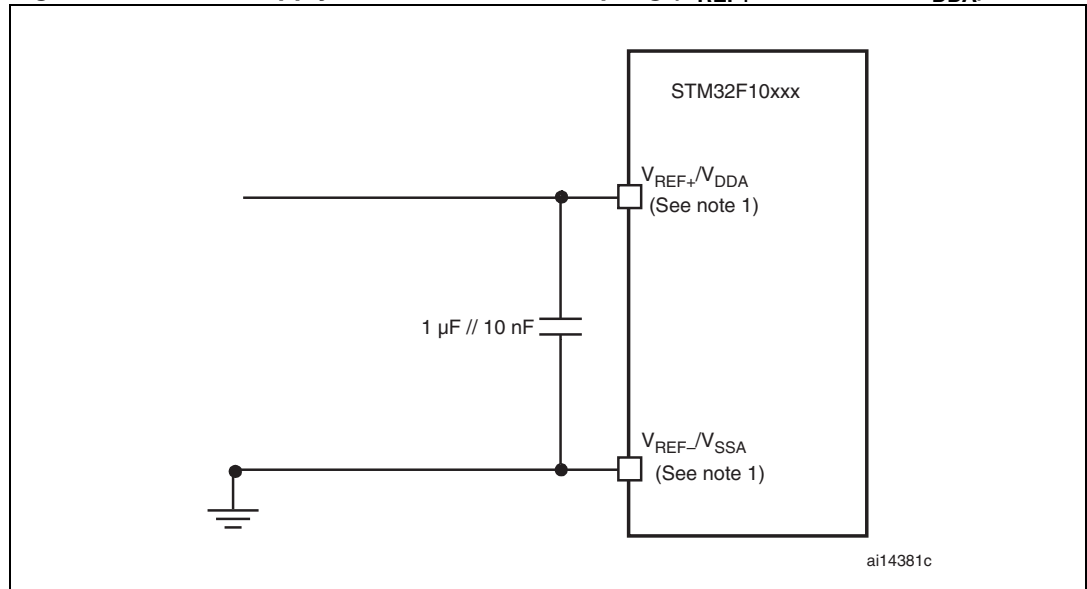
Power supply decoupling should be performed as shown in *Figure 31* or *Figure 32*, depending on whether  $V_{REF+}$  is connected to  $V_{DDA}$  or not. The 10 nF capacitors should be ceramic (good quality). They should be placed them as close as possible to the chip.

**Figure 31. Power supply and reference decoupling ( $V_{REF+}$  not connected to  $V_{DDA}$ )**



1.  $V_{REF+}$  and  $V_{REF-}$  inputs are available only on 100-pin packages.

**Figure 32. Power supply and reference decoupling ( $V_{REF+}$  connected to  $V_{DDA}$ )**



1.  $V_{REF+}$  and  $V_{REF-}$  inputs are available only on 100-pin packages.



5.3.17 DAC electrical specifications

Table 55. DAC characteristics

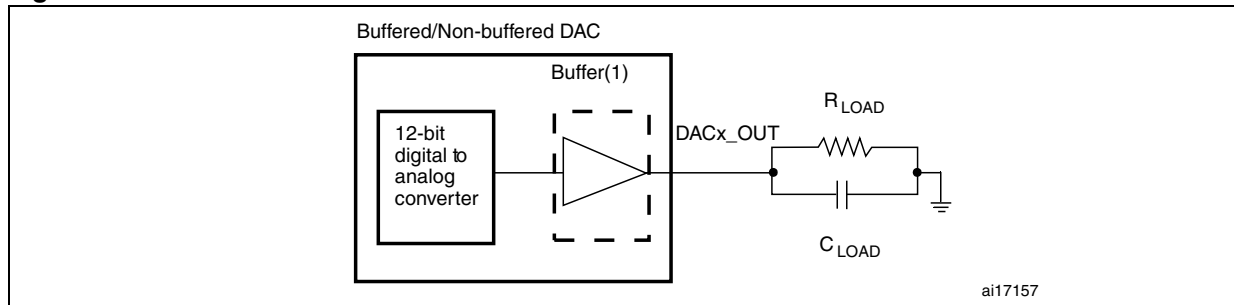
| Symbol                                | Parameter   | Min | Typ | Max                      | Unit | Comments   |
|---------------------------------------|---|-----|-----|--------------------------|------|--|
| V <sub>DDA</sub>                      | Analog supply voltage   | 2.4 |     | 3.6                      | V    |  |
| V <sub>REF+</sub>                     | Reference supply voltage  | 2.4 |     | 3.6                      | V    | V <sub>REF+</sub> must always be below V <sub>DDA</sub>  |
| V <sub>SSA</sub>                      | Ground  | 0   |     | 0                        | V    |  |
| R <sub>LOAD</sub> <sup>(1)</sup>      | Resistive load with buffer ON   | 5   |     |                          | kΩ   |  |
| R <sub>O</sub> <sup>(1)</sup>         | Impedance output with buffer OFF  |     |     | 15                       | kΩ   | When the buffer is OFF, the Minimum resistive load between DAC_OUT and V <sub>SS</sub> to have a 1% accuracy is 1.5 MΩ   |
| C <sub>LOAD</sub> <sup>(1)</sup>      | Capacitive load   |     |     | 50                       | pF   | Maximum capacitive load at DAC_OUT pin (when the buffer is ON).  |
| DAC_OUT <sub>min</sub> <sup>(1)</sup> | Lower DAC_OUT voltage with buffer ON  | 0.2 |     |                          | V    | It gives the maximum output excursion of the DAC.<br>It corresponds to 12-bit input code (0x0E0) to (0xF1C) at V <sub>REF+</sub> = 3.6 V and (0x155) to (0xEAB) at V <sub>REF+</sub> = 2.4 V |
| DAC_OUT <sub>max</sub> <sup>(1)</sup> | Higher DAC_OUT voltage with buffer ON   |     |     | V <sub>DDA</sub> - 0.2   | V    |  |
| DAC_OUT <sub>min</sub> <sup>(1)</sup> | Lower DAC_OUT voltage with buffer OFF   |     | 0.5 |                          | mV   | It gives the maximum output excursion of the DAC.  |
| DAC_OUT <sub>max</sub> <sup>(1)</sup> | Higher DAC_OUT voltage with buffer OFF  |     |     | V <sub>REF+</sub> - 1LSB | V    |  |
| I <sub>DDVREF+</sub>                  | DAC DC current consumption in quiescent mode (Standby mode)   |     |     | 220                      | μA   | With no load, worst code (0xF1C) at V <sub>REF+</sub> = 3.6 V in terms of DC consumption on the inputs   |
| I <sub>DDA</sub>                      | DAC DC current consumption in quiescent mode (Standby mode)   |     |     | 380                      | μA   | With no load, middle code (0x800) on the inputs  |
|                                       |   |     |     | 480                      | μA   | With no load, worst code (0xF1C) at V <sub>REF+</sub> = 3.6 V in terms of DC consumption on the inputs   |
| DNL <sup>(2)</sup>                    | Differential non linearity<br>Difference between two consecutive code-1LSB)   |     |     | ±0.5                     | LSB  | Given for the DAC in 10-bit configuration.   |
|                                       |   |     |     | ±2                       | LSB  | Given for the DAC in 12-bit configuration.   |
| INL <sup>(2)</sup>                    | Integral non linearity<br>(difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023) |     |     | ±1                       | LSB  | Given for the DAC in 10-bit configuration.   |
|                                       |   |     |     | ±4                       | LSB  | Given for the DAC in 12-bit configuration.   |

**Table 55. DAC characteristics (continued)**

| Symbol                     | Parameter  | Min | Typ | Max  | Unit | Comments  |
|----------------------------|--|-----|-----|------|------|---|
| Offset <sup>(2)</sup>      | Offset error (difference between measured value at Code (0x800) and the ideal value = $V_{REF+}/2$ )   |     |     | ±10  | mV   | Given for the DAC in 12-bit configuration   |
|                            |  |     |     | ±3   | LSB  | Given for the DAC in 10-bit at $V_{REF+} = 3.6\text{ V}$  |
|                            |  |     |     | ±12  | LSB  | Given for the DAC in 12-bit at $V_{REF+} = 3.6\text{ V}$  |
| Gain error <sup>(2)</sup>  | Gain error   |     |     | ±0.5 | %    | Given for the DAC in 12bit configuration  |
| $t_{SETTLING}^{(2)}$       | Settling time (full scale: for a 10-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches final value ±1LSB) |     | 3   | 4    | µs   | $C_{LOAD} \leq 50\text{ pF}$ ,<br>$R_{LOAD} \geq 5\text{ k}\Omega$  |
| Update rate <sup>(2)</sup> | Max frequency for a correct DAC_OUT change when small variation in the input code (from code i to i+1LSB)  |     |     | 1    | MS/s | $C_{LOAD} \leq 50\text{ pF}$ ,<br>$R_{LOAD} \geq 5\text{ k}\Omega$  |
| $t_{WAKEUP}^{(2)}$         | Wakeup time from off state (Setting the ENx bit in the DAC Control register)   |     | 6.5 | 10   | µs   | $C_{LOAD} \leq 50\text{ pF}$ , $R_{LOAD} \geq 5\text{ k}\Omega$<br>input code between lowest and highest possible ones. |
| PSRR+ <sup>(1)</sup>       | Power supply rejection ratio (to $V_{DDA}$ ) (static DC measurement)   |     | -67 | -40  | dB   | No $R_{LOAD}$ , $C_{LOAD} = 50\text{ pF}$   |

1. Guaranteed by design, not tested in production.
2. Guaranteed by characterization, not tested in production.

**Figure 33. 12-bit buffered /non-buffered DAC**



1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC\_CR register.

### 5.3.18 Temperature sensor characteristics

**Table 56. TS characteristics**

| Symbol                        | Parameter                                      | Min  | Typ     | Max     | Unit                   |
|-------------------------------|--|------|---------|---------|------------------------|
| $T_L^{(1)}$                   | $V_{SENSE}$ linearity with temperature         |      | $\pm 1$ | $\pm 2$ | $^{\circ}\text{C}$     |
| Avg_Slope <sup>(1)</sup>      | Average slope                                  | 4.0  | 4.3     | 4.6     | mV/ $^{\circ}\text{C}$ |
| $V_{25}^{(1)}$                | Voltage at 25 $^{\circ}\text{C}$               | 1.34 | 1.43    | 1.52    | V                      |
| $t_{\text{START}}^{(2)}$      | Startup time                                   | 4    |         | 10      | $\mu\text{s}$          |
| $T_{\text{S\_temp}}^{(3)(2)}$ | ADC sampling time when reading the temperature |      |         | 17.1    | $\mu\text{s}$          |

1. Based on characterization, not tested in production.
2. Guaranteed by design, not tested in production.
3. Shortest sampling time can be determined in the application by multiple iterations.

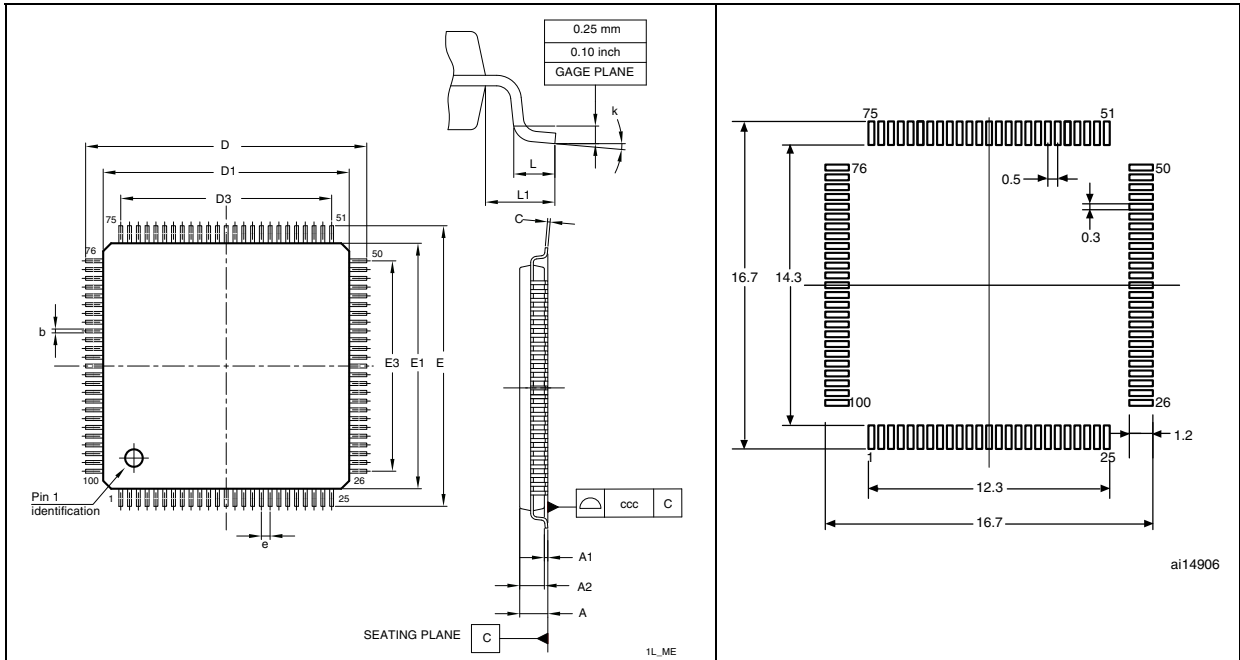
## 6 Package characteristics

### 6.1 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK<sup>®</sup> is an ST trademark.

Figure 34. LQFP100, 100-pin low-profile quad flat package outline<sup>(1)</sup>

Figure 35. Recommended footprint<sup>(1)(2)</sup>



1. Drawing is not to scale.
2. Dimensions are in millimeters.

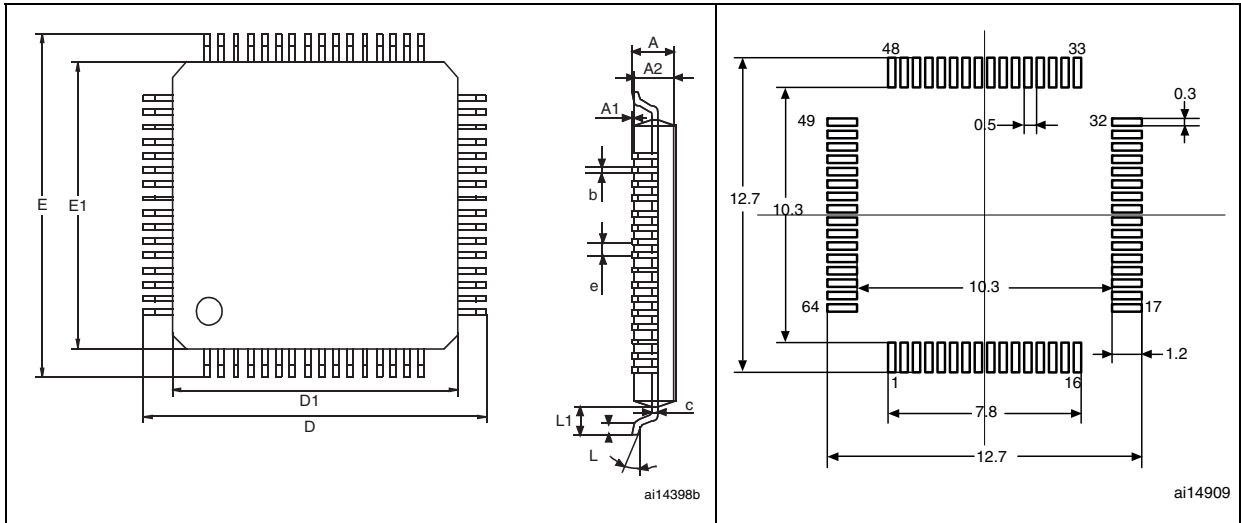
Table 57. LQFP100 – 100-pin low-profile quad flat package mechanical data

| Symbol | millimeters |       |       | inches <sup>(1)</sup> |        |        |
|--------|-------------|-------|-------|-----------------------|--------|--------|
|        | Typ         | Min   | Max   | Typ                   | Min    | Max    |
| A      |             |       | 1.60  |                       |        | 0.063  |
| A1     |             | 0.05  | 0.15  |                       | 0.002  | 0.0059 |
| A2     | 1.40        | 1.35  | 1.45  | 0.0551                | 0.0531 | 0.0571 |
| b      | 0.22        | 0.17  | 0.27  | 0.0087                | 0.0067 | 0.0106 |
| c      |             | 0.09  | 0.20  |                       | 0.0035 | 0.0079 |
| D      | 16.00       | 15.80 | 16.20 | 0.6299                | 0.622  | 0.6378 |
| D1     | 14.00       | 13.80 | 14.20 | 0.5512                | 0.5433 | 0.5591 |
| D3     | 12.00       |       |       | 0.4724                |        |        |
| E      | 16.00       | 15.80 | 16.20 | 0.6299                | 0.622  | 0.6378 |
| E1     | 14.00       | 13.80 | 14.20 | 0.5512                | 0.5433 | 0.5591 |
| E3     | 12.00       |       |       | 0.4724                |        |        |
| e      | 0.50        |       |       | 0.0197                |        |        |
| L      | 0.60        | 0.45  | 0.75  | 0.0236                | 0.0177 | 0.0295 |
| L1     | 1.00        |       |       | 0.0394                |        |        |
| k      | 3.5°        | 0°    | 7°    | 3.5°                  | 0°     | 7°     |
| ccc    |             | 0.08  |       |                       | 0.0031 |        |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 36. LQFP64 – 64 pin low-profile quad flat package outline<sup>(1)</sup>

Figure 37. Recommended footprint<sup>(1)(2)</sup>



1. Drawing is not to scale.
2. Dimensions are in millimeters.

Table 58. LQFP64 – 64 pin low-profile quad flat package mechanical data

| Dim. | mm                    |       |      | inches <sup>(1)</sup> |        |        |
|------|-----------------------|-------|------|-----------------------|--------|--------|
|      | Min                   | Typ   | Max  | Min                   | Typ    | Max    |
| A    |                       |       | 1.60 |                       |        | 0.0630 |
| A1   | 0.05                  |       | 0.15 | 0.0020                |        | 0.0059 |
| A2   | 1.35                  | 1.40  | 1.45 | 0.0531                | 0.0551 | 0.0571 |
| b    | 0.17                  | 0.22  | 0.27 | 0.0067                | 0.0087 | 0.0106 |
| c    | 0.09                  |       | 0.20 | 0.0035                |        | 0.0079 |
| D    |                       | 12.00 |      |                       | 0.4724 |        |
| D1   |                       | 10.00 |      |                       | 0.3937 |        |
| E    |                       | 12.00 |      |                       | 0.4724 |        |
| E1   |                       | 10.00 |      |                       | 0.3937 |        |
| e    |                       | 0.50  |      |                       | 0.0197 |        |
| θ    | 0°                    | 3.5°  | 7°   | 0°                    | 3.5°   | 7°     |
| L    | 0.45                  | 0.60  | 0.75 | 0.0177                | 0.0236 | 0.0295 |
| L1   |                       | 1.00  |      |                       | 0.0394 |        |
| N    | <b>Number of pins</b> |       |      |                       |        |        |
|      | 64                    |       |      |                       |        |        |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

## 6.2 Thermal characteristics

The maximum chip junction temperature ( $T_J$ max) must never exceed the values given in [Table 9: General operating conditions on page 34](#).

The maximum chip-junction temperature,  $T_J$  max, in degrees Celsius, may be calculated using the following equation:

$$T_J \text{ max} = T_A \text{ max} + (P_D \text{ max} \times \Theta_{JA})$$

Where:

- $T_A$  max is the maximum ambient temperature in °C,
- $\Theta_{JA}$  is the package junction-to-ambient thermal resistance, in °C/W,
- $P_D$  max is the sum of  $P_{INT}$  max and  $P_{I/O}$  max ( $P_D$  max =  $P_{INT}$  max +  $P_{I/O}$ max),
- $P_{INT}$  max is the product of  $I_{DD}$  and  $V_{DD}$ , expressed in Watts. This is the maximum chip internal power.

$P_{I/O}$  max represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \Sigma (V_{OL} \times I_{OL}) + \Sigma ((V_{DD} - V_{OH}) \times I_{OH}),$$

taking into account the actual  $V_{OL} / I_{OL}$  and  $V_{OH} / I_{OH}$  of the I/Os at low and high level in the application.

**Table 59. Package thermal characteristics**

| Symbol        | Parameter  | Value | Unit |
|---------------|--|-------|------|
| $\Theta_{JA}$ | Thermal resistance junction-ambient<br>LQFP100 - 14 × 14 mm / 0.5 mm pitch | 46    | °C/W |
|               | Thermal resistance junction-ambient<br>LQFP64 - 10 × 10 mm / 0.5 mm pitch  | 45    |      |

### 6.2.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from [www.jedec.org](http://www.jedec.org).

## 6.2.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the ordering information scheme shown in [Table 60: Ordering information scheme](#).

Each temperature range suffix corresponds to a specific guaranteed ambient temperature at maximum dissipation and, to a specific maximum junction temperature.

As applications do not commonly use the STM32F103xx at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

### Example 1: High-performance application

Assuming the following application conditions:

Maximum ambient temperature  $T_{Amax} = 82\text{ °C}$  (measured according to JESD51-2),  
 $I_{DDmax} = 50\text{ mA}$ ,  $V_{DD} = 3.5\text{ V}$ , maximum 20 I/Os used at the same time in output at low level with  $I_{OL} = 8\text{ mA}$ ,  $V_{OL} = 0.4\text{ V}$  and maximum 8 I/Os used at the same time in output at low level with  $I_{OL} = 20\text{ mA}$ ,  $V_{OL} = 1.3\text{ V}$

$$P_{INTmax} = 50\text{ mA} \times 3.5\text{ V} = 175\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} + 8 \times 20\text{ mA} \times 1.3\text{ V} = 272\text{ mW}$$

This gives:  $P_{INTmax} = 175\text{ mW}$  and  $P_{IOmax} = 272\text{ mW}$ :

$$P_{Dmax} = 175 + 272 = 447\text{ mW}$$

Thus:  $P_{Dmax} = 447\text{ mW}$

Using the values obtained in [Table 59](#)  $T_{Jmax}$  is calculated as follows:

– For LQFP100,  $46\text{ °C/W}$

$$T_{Jmax} = 82\text{ °C} + (46\text{ °C/W} \times 447\text{ mW}) = 82\text{ °C} + 20.6\text{ °C} = 102.6\text{ °C}$$

This is within the range of the suffix 6 version parts ( $-40 < T_J < 105\text{ °C}$ ).

In this case, parts must be ordered at least with the temperature range suffix 6 (see [Table 60: Ordering information scheme](#)).

### Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high ambient temperatures with a low dissipation, as long as junction temperature  $T_J$  remains within the specified range.

Assuming the following application conditions:

Maximum ambient temperature  $T_{Amax} = 115\text{ °C}$  (measured according to JESD51-2),  
 $I_{DDmax} = 20\text{ mA}$ ,  $V_{DD} = 3.5\text{ V}$ , maximum 20 I/Os used at the same time in output at low level with  $I_{OL} = 8\text{ mA}$ ,  $V_{OL} = 0.4\text{ V}$

$$P_{INTmax} = 20\text{ mA} \times 3.5\text{ V} = 70\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} = 64\text{ mW}$$

This gives:  $P_{INTmax} = 70\text{ mW}$  and  $P_{IOmax} = 64\text{ mW}$ :

$$P_{Dmax} = 70 + 64 = 134\text{ mW}$$

Thus:  $P_{Dmax} = 134\text{ mW}$



Using the values obtained in [Table 59](#)  $T_{Jmax}$  is calculated as follows:

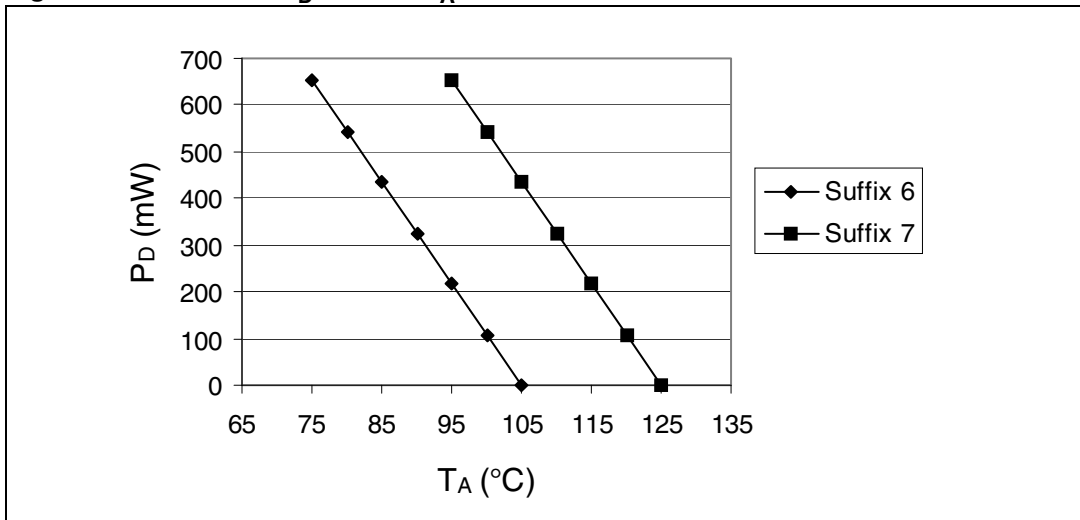
– For LQFP100, 46 °C/W

$$T_{Jmax} = 115\text{ °C} + (46\text{ °C/W} \times 134\text{ mW}) = 115\text{ °C} + 6.2\text{ °C} = 121.2\text{ °C}$$

This is within the range of the suffix 7 version parts ( $-40 < T_J < 125\text{ °C}$ ).

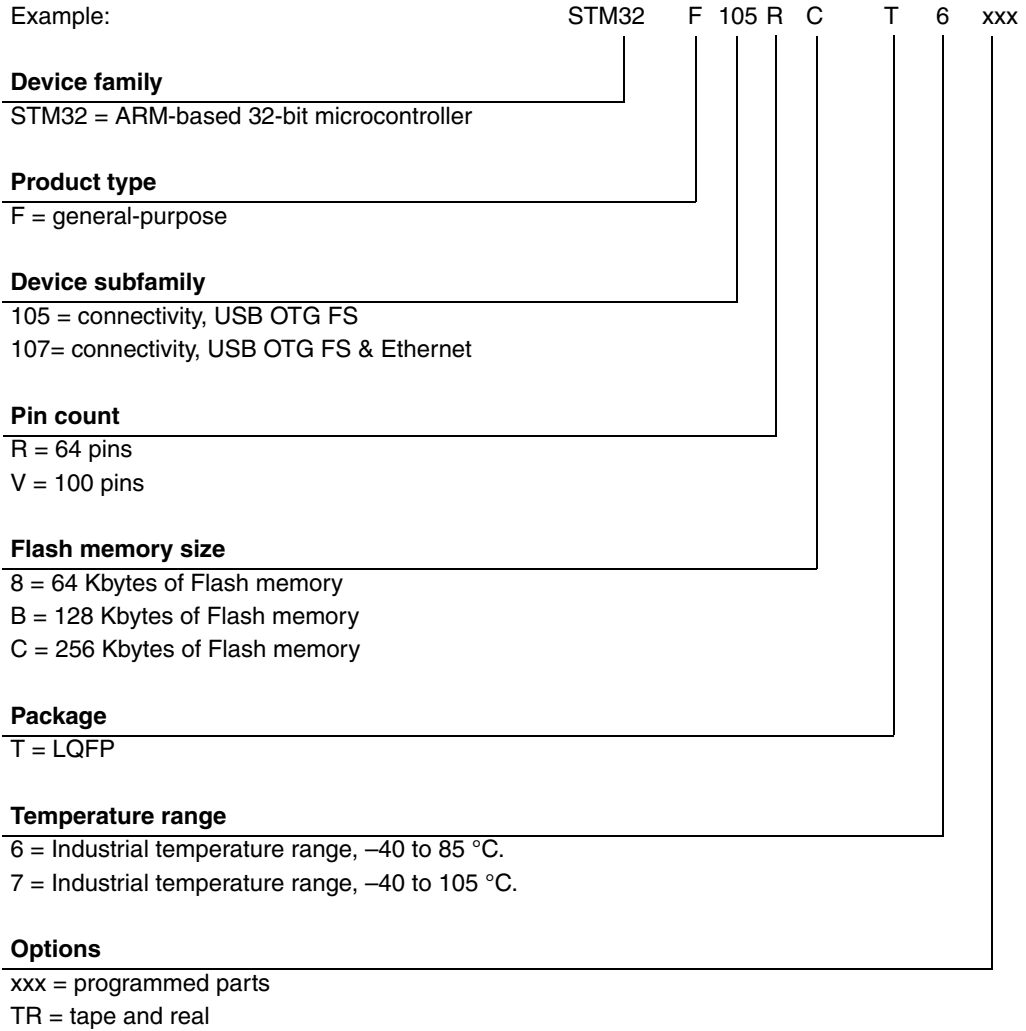
In this case, parts must be ordered at least with the temperature range suffix 7 (see [Table 60: Ordering information scheme](#)).

**Figure 38. LQFP100  $P_D$  max vs.  $T_A$**



# 7 Part numbering

**Table 60. Ordering information scheme**

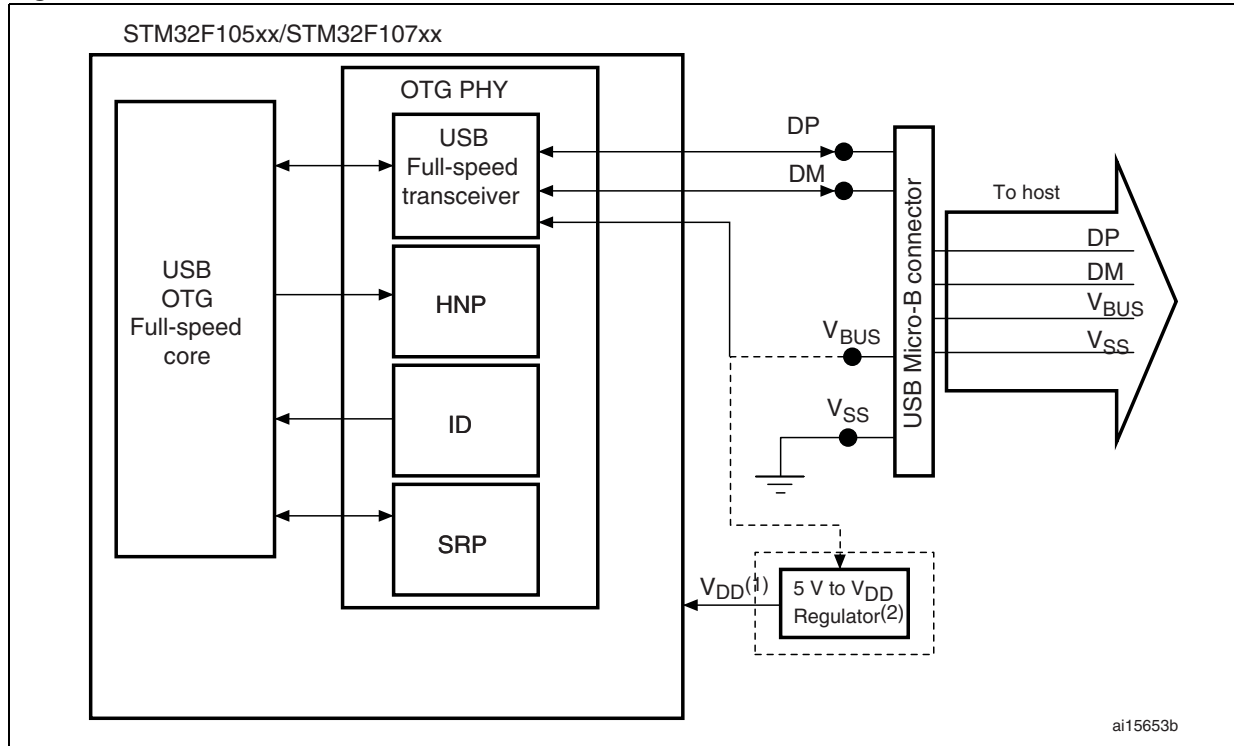


For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest ST sales office.

## Appendix A Applicative block diagrams

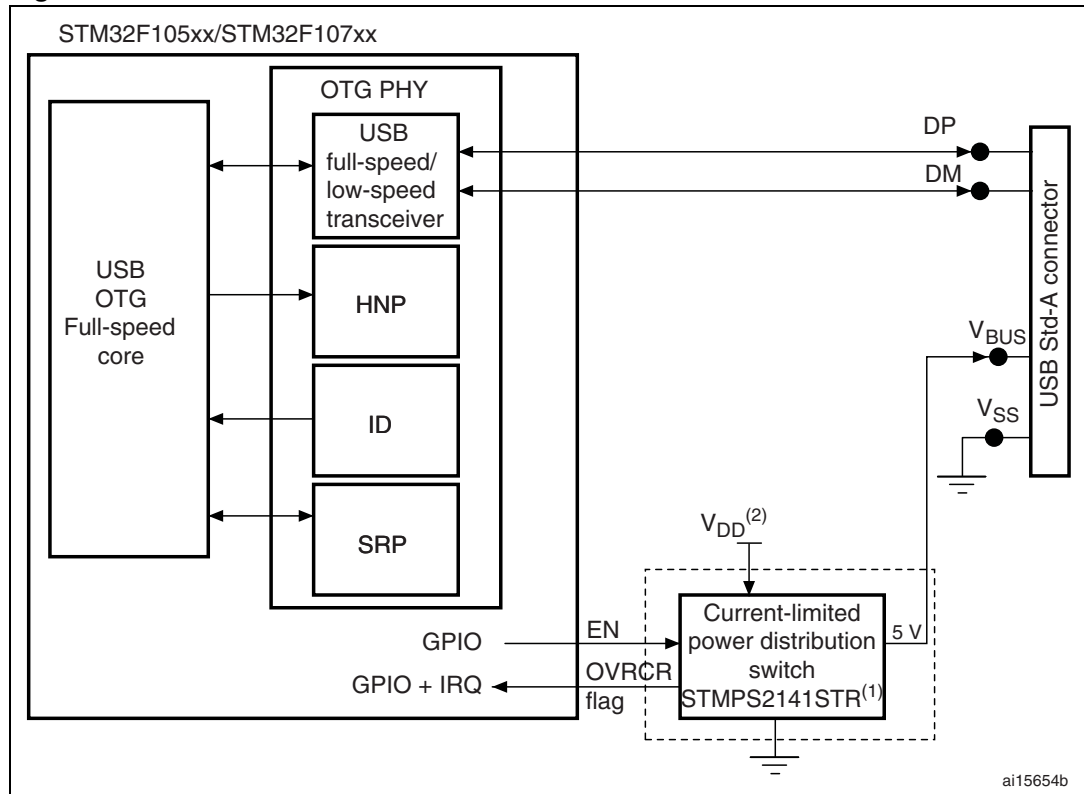
### A.1 USB OTG FS interface solutions

Figure 39. USB OTG FS device mode



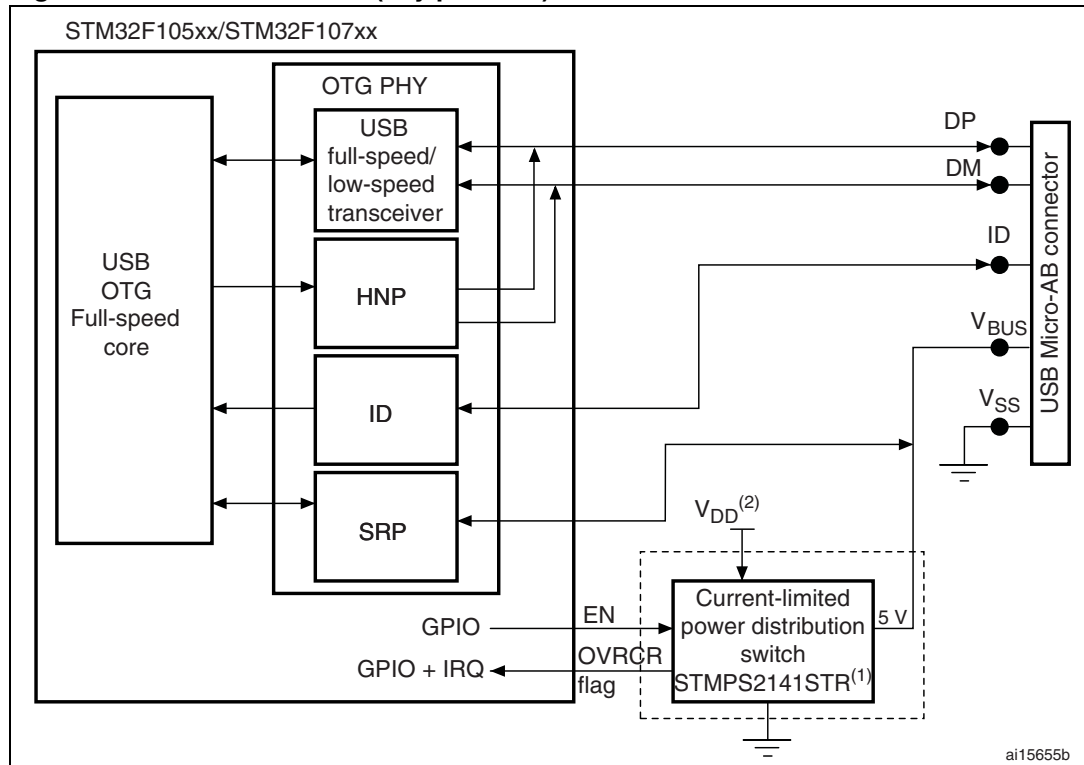
1.  $V_{DD}$  ranges between 2 V and 3.6 V.
2. Use a regulator if you want to build a bus-powered device.

Figure 40. Host connection



1. STMP2141STR needed only if the application has to support bus-powered devices.
2.  $V_{DD}$  ranges between 2 V and 3.6 V.

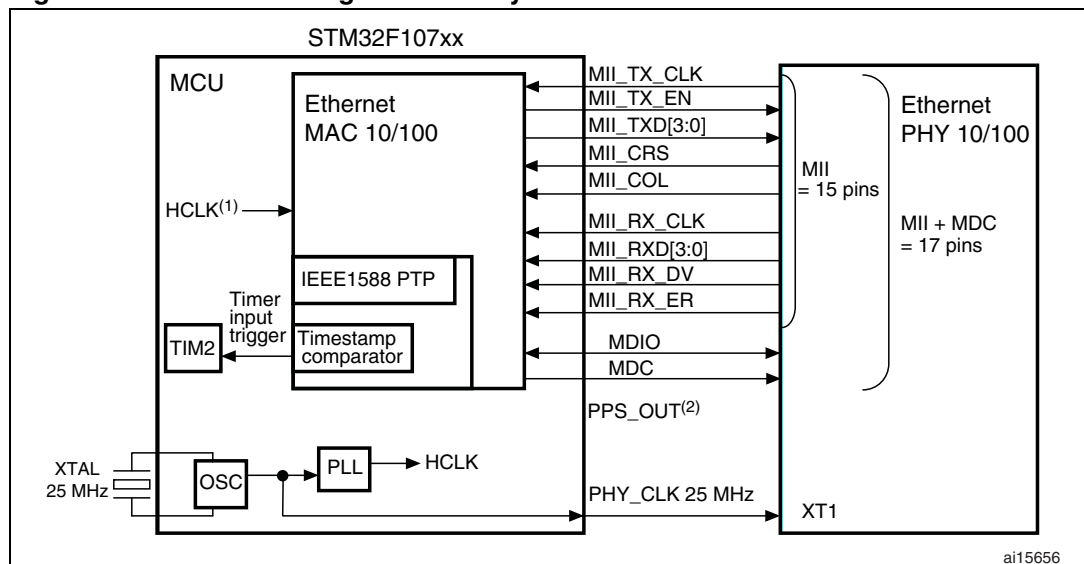
Figure 41. OTG connection (any protocol)



1. STMPS2141STR needed only if the application has to support bus-powered devices.
2.  $V_{DD}$  ranges between 2 V and 3.6 V.

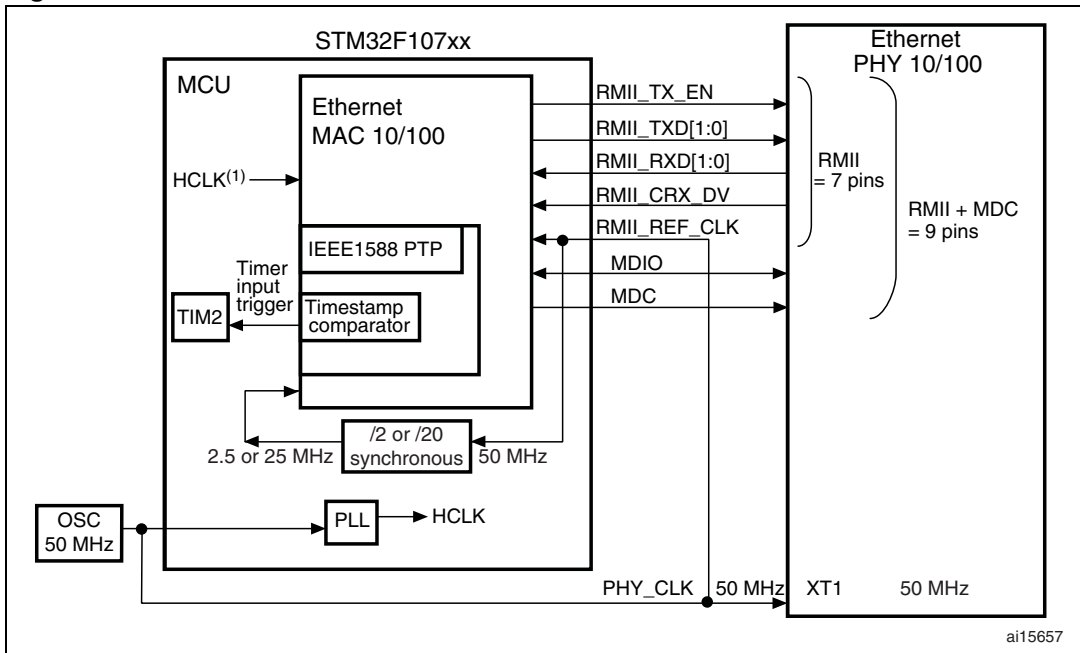
## A.2 Ethernet interface solutions

Figure 42. MII mode using a 25 MHz crystal



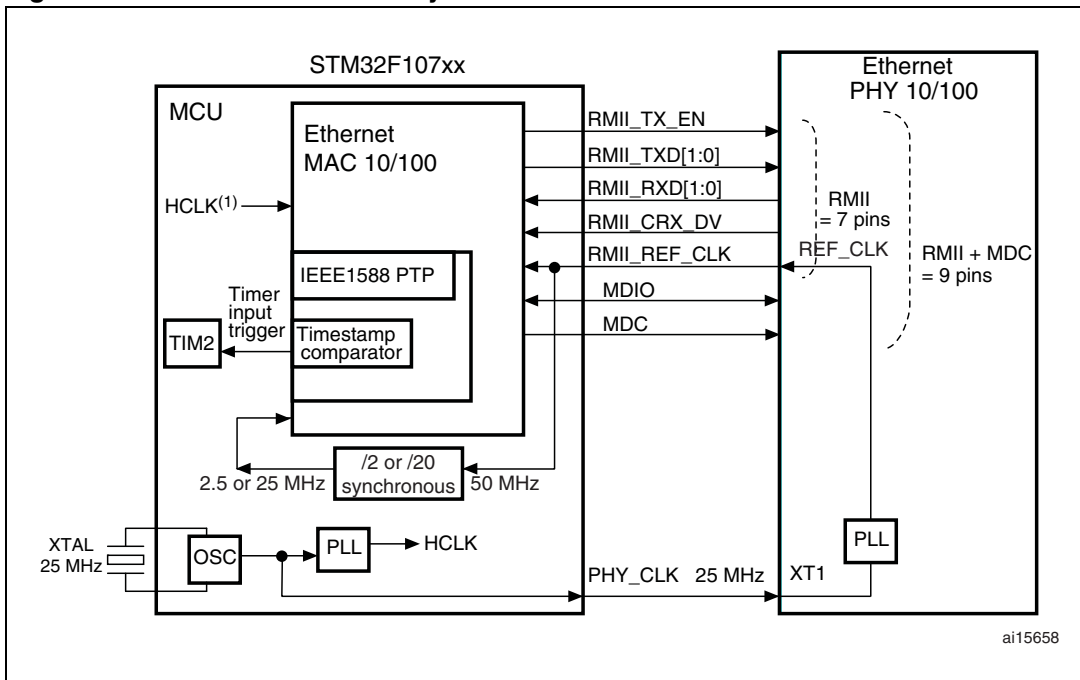
1. HCLK must be greater than 25 MHz.
2. Pulse per second when using IEEE1588 PTP, optional signal.

Figure 43. RMIi with a 50 MHz oscillator



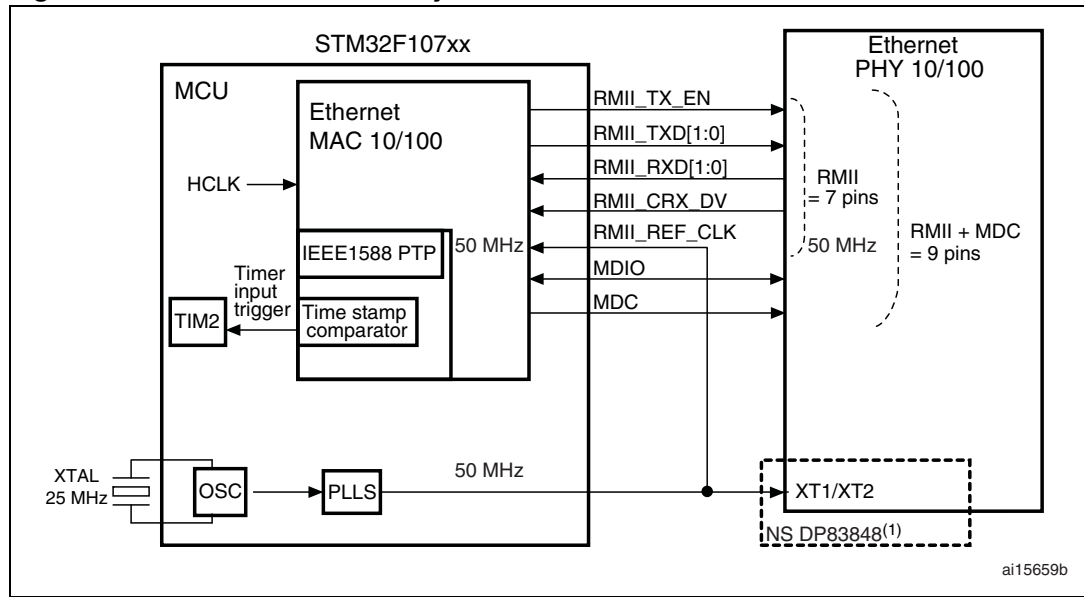
1. HCLK must be greater than 25 MHz.

Figure 44. RMIi with a 25 MHz crystal and PHY with PLL



1. HCLK must be greater than 25 MHz.

Figure 45. RMIi with a 25 MHz crystal



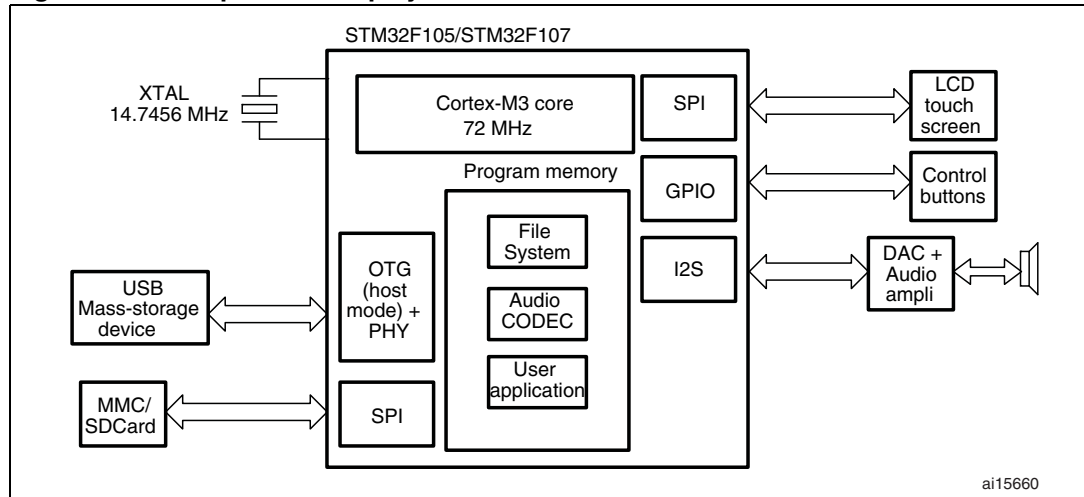
1. The NS DP83848 is recommended as the input jitter requirement of this PHY. It is compliant with the output jitter specification of the MCU.

### A.3 Complete audio player solutions

Two solutions are offered, illustrated in *Figure 46* and *Figure 47*.

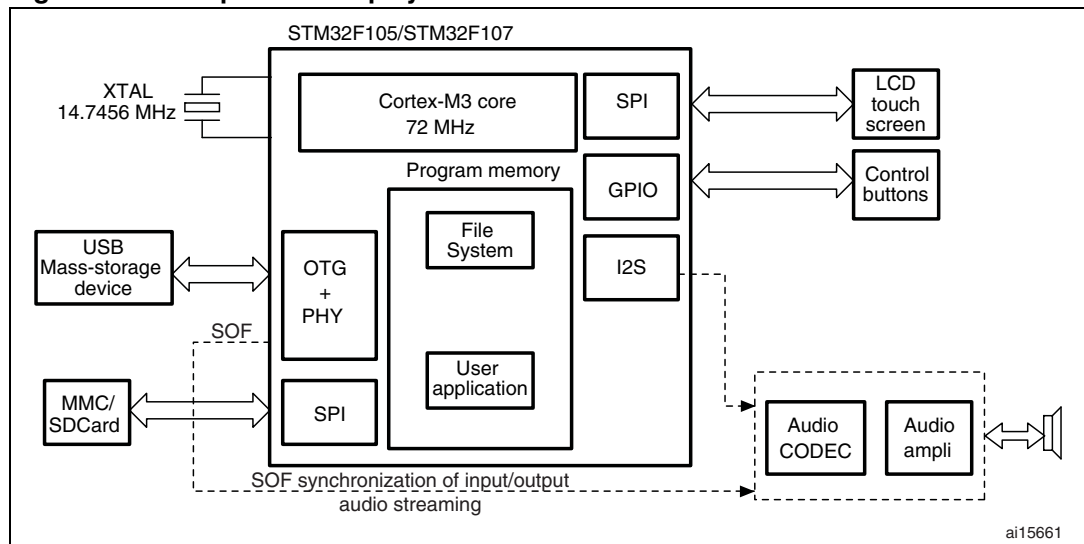
*Figure 46* shows storage media to audio DAC/amplifier streaming using a software Codec. This solution implements an audio crystal to provide audio class I<sup>2</sup>S accuracy on the master clock (0.5% error maximum, see the Serial peripheral interface section in the reference manual for details).

**Figure 46. Complete audio player solution 1**



*Figure 47* shows storage media to audio Codec/amplifier streaming with SOF synchronization of input/output audio streaming using a hardware Codec.

**Figure 47. Complete audio player solution 2**

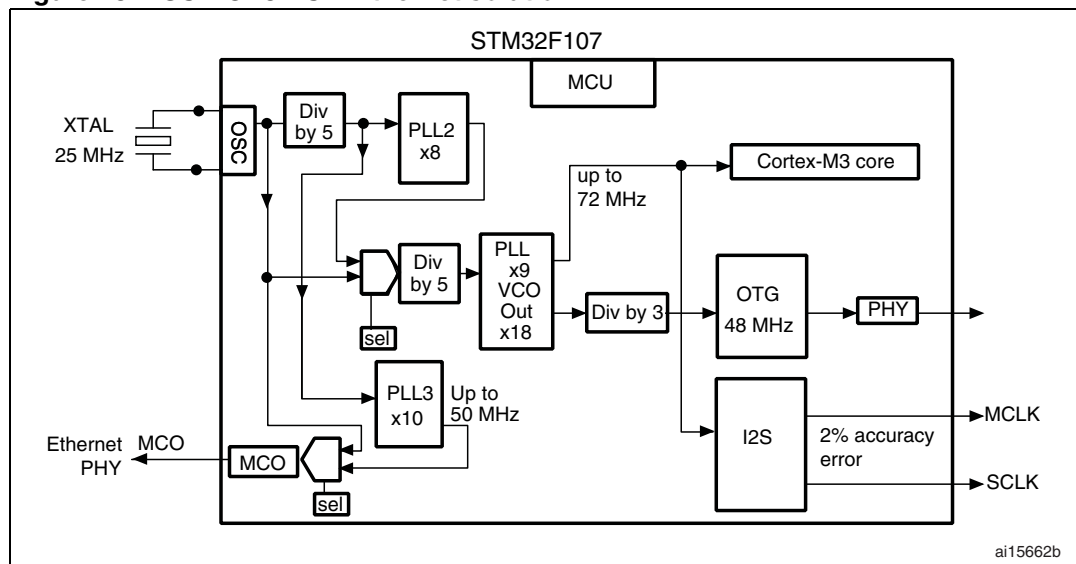




### A.4 USB OTG FS interface + Ethernet/I<sup>2</sup>S interface solutions

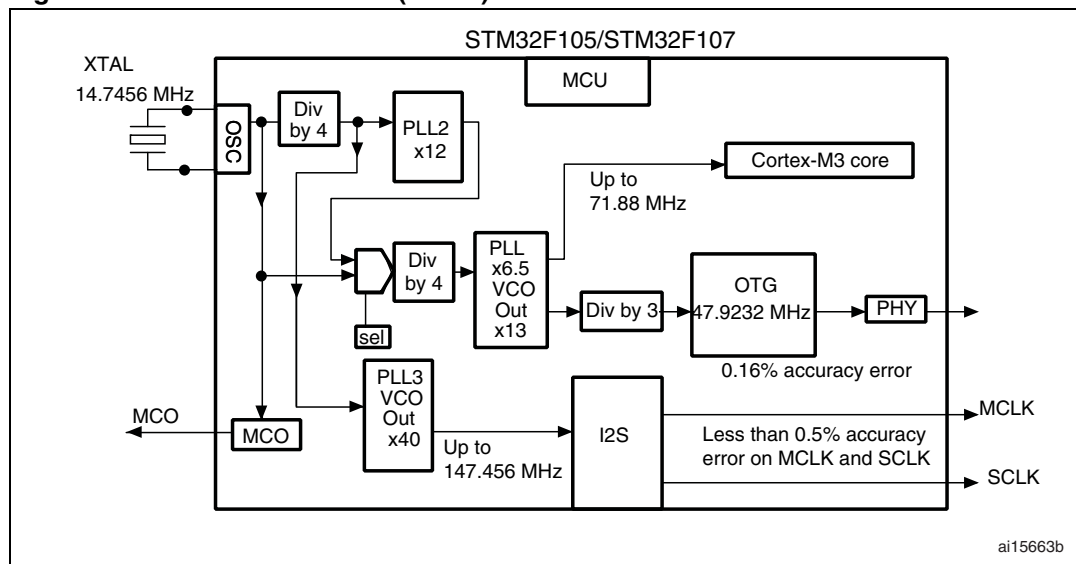
With the clock tree implemented on the STM32F107xx, only one crystal is required to work with both the USB (host/device/OTG) and the Ethernet (MII/RMII) interfaces. *Figure 48* illustrate the solution.

**Figure 48. USB OTG FS + Ethernet solution**



With the clock tree implemented on the STM32F107xx, only one crystal is required to work with both the USB (host/device/OTG) and the I<sup>2</sup>S (Audio) interfaces. *Figure 49* illustrate the solution.

**Figure 49. USB OTG FS + I<sup>2</sup>S (Audio) solution**



**Table 61. PLL configurations**

| Application  | Crystal value in MHz (XT1) | PREDIV2 | PLL2MUL    | PLLSRC | PREDIV1 | PLLMUL     | USB prescaler (PLLVCO output) | PLL3MUL    | I2Sn clock input | MCO (main clock output)                |
|--|----------------------------|---------|------------|--------|---------|------------|-------------------------------|------------|------------------|--|
| Ethernet only  | 25                         | /5      | PLL2ON x8  | PLL2   | /5      | PLLON x9   | NA                            | PLL3ON x10 | NA               | XT1 (MII)<br>PLL3 (RMII)               |
| Ethernet + OTG   | 25                         | /5      | PLL2ON x8  | PLL2   | /5      | PLLON x9   | /3                            | PLL3ON x10 | NA               | XT1 (MII)<br>PLL3 (RMII)               |
| Ethernet + OTG + basic audio                                 | 25                         | /5      | PLL2ON x8  | PLL2   | /5      | PLLON x9   | /3                            | PLL3ON x10 | PLL              | XT1 (MII)<br>PLL3 (RMII)               |
| Ethernet + OTG + Audio class I <sup>2</sup> S <sup>(1)</sup> | 14.7456                    | /4      | PLL2ON x12 | PLL2   | /4      | PLLON x6.5 | /3                            | PLL3ON x20 | PLL3 VCO Out     | NA<br>ETH PHY must use its own crystal |
| OTG only   | 8                          | NA      | PLL2OFF    | XT1    | /1      | PLLON x9   | /3                            | PLL3OFF    | NA               | NA                                     |
| OTG + basic audio  | 8                          | NA      | PLL2OFF    | XT1    | /1      | PLLON x9   | /3                            | PLL3OFF    | PLL              | NA                                     |
| OTG + Audio class I <sup>2</sup> S <sup>(1)</sup>            | 14.7456                    | /4      | PLL2ON x12 | PLL2   | /4      | PLLON x6.5 | /3                            | PLL3ON x20 | PLL3 VCO Out     | NA                                     |
| Audio class I <sup>2</sup> S only <sup>(1)</sup>             | 14.7456                    | /4      | PLL2ON x12 | PLL2   | /4      | PLLON x6.5 | NA                            | PLL3ON x20 | PLL3 VCO out     | NA                                     |

1. SYSCLK is set to be at 72 MHz except in this case where SYSCLK is at 71.88 MHz.

[Table 62](#) give the I<sub>DD</sub> run mode values that correspond to the conditions specified in [Table 61](#).

**Table 62. Applicative current consumption in Run mode, code with data processing running from Flash**

| Symbol          | parameter                  | Conditions <sup>(1)</sup>  | Typ <sup>(2)</sup> | Max <sup>(2)</sup> |        | Unit |
|-----------------|----------------------------|--|--------------------|--------------------|--------|------|
|                 |                            |  |                    | 85 °C              | 105 °C |      |
| I <sub>DD</sub> | Supply current in run mode | External clock, all peripherals enabled except ethernet, HSE = 8 MHz, f <sub>HCLK</sub> = 72 MHz, no MCO     | 57                 | 63                 | 64     | mA   |
|                 |                            | External clock, all peripherals enabled except ethernet, HSE = 14.74 MHz, f <sub>HCLK</sub> = 72 MHz, no MCO | 60.5               | 67                 | 68     |      |
|                 |                            | External clock, all peripherals enabled except OTG, HSE = 25 MHz, f <sub>HCLK</sub> = 72 MHz, MCO = 25 MHz   | 53                 | 60.7               | 61     |      |
|                 |                            | External clock, all peripherals enabled, HSE = 25 MHz, f <sub>HCLK</sub> = 72 MHz, MCO = 25 MHz              | 60.5               | 65.5               | 66     |      |
|                 |                            | External clock, all peripherals enabled, HSE = 25 MHz, f <sub>HCLK</sub> = 72 MHz, MCO = 50 MHz              | 64                 | 69.7               | 70     |      |
|                 |                            | External clock, all peripherals enabled, HSE = 50 MHz <sup>(3)</sup> , f <sub>HCLK</sub> = 72 MHz, no MCO    | 62.5               | 67.5               | 68     |      |
|                 |                            | External clock, only OTG enabled, HSE = 8 MHz, f <sub>HCLK</sub> = 48 MHz, no MCO                            | 26.7               | None               | None   |      |
|                 |                            | External clock, only ethernet enabled, HSE = 25 MHz, f <sub>HCLK</sub> = 25 MHz, MCO = 25 MHz                | 14.3               | None               | None   |      |

1. V<sub>DD</sub> = 3.3 V.
2. Based on characterization, not tested in production.
3. External oscillator.

## Revision history

**Table 63. Document revision history**

| Date        | Revision | Changes  |
|-------------|----------|--|
| 18-Dec-2008 | 1        | Initial release.   |
| 20-Feb-2009 | 2        | <p>I/O information clarified <i>on page 1. Figure 4: STM32F105xxx and STM32F107xxx connectivity line BGA100 ballout top view</i> corrected.</p> <p><i>Section 2.3.8: Boot modes</i> updated.</p> <p>PB4, PB13, PB14, PB15, PB3/TRACESWO moved from Default column to Remap column, plus small additional changes in <i>Table 5: Pin definitions</i>.</p> <p>Consumption values modified in <i>Section 5.3.5: Supply current characteristics</i>.</p> <p>Note modified in <i>Table 13: Maximum current consumption in Run mode, code with data processing running from Flash</i> and <i>Table 15: Maximum current consumption in Sleep mode, code running from Flash or RAM</i>.</p> <p><i>Table 20: High-speed external user clock characteristics</i> and <i>Table 21: Low-speed external user clock characteristics</i> modified.</p> <p><i>Table 27: PLL characteristics</i> modified and <i>Table 28: PLL2 and PLL3 characteristics</i> added.</p> |

**Table 63. Document revision history (continued)**

| Date        | Revision | Changes   |
|-------------|----------|---|
| 19-Jun-2009 | 3        | <p><i>Section 2.3.8: Boot modes</i> and <i>Section 2.3.20: Ethernet MAC interface with dedicated DMA and IEEE 1588 support</i> updated.</p> <p><i>Section 2.3.24: Remap capability</i> added.</p> <p><i>Figure 1: STM32F105xx and STM32F107xx connectivity line block diagram</i> and <i>Figure 4: Memory map</i> updated.</p> <p>In <i>Table 5: Pin definitions</i>:</p> <ul style="list-style-type: none"> <li>– I2S3_WS, I2S3_CK and I2S3_SD default alternate functions added</li> <li>– small changes in signal names</li> <li>– <i>Note 5</i> modified</li> <li>– ETH_MII_PPS_OUT and ETH_RMII_PPS_OUT replaced by ETH_PPS_OUT</li> <li>– ETH_MII_MDIO and ETH_RMII_MDIO replaced by ETH_MDIO</li> <li>– ETH_MII_MDC and ETH_RMII_MDC replaced by ETH_MDC</li> </ul> <p>Figures: <i>Typical current consumption in Run mode versus frequency (at 3.6 V) - code with data processing running from RAM, peripherals enabled</i> and <i>Typical current consumption in Run mode versus frequency (at 3.6 V) - code with data processing running from RAM, peripherals disabled</i> removed.</p> <p><i>Table 13: Maximum current consumption in Run mode, code with data processing running from Flash</i>, <i>Table 14: Maximum current consumption in Run mode, code with data processing running from RAM</i> and <i>Table 15: Maximum current consumption in Sleep mode, code running from Flash or RAM</i> are to be determined.</p> <p><i>Figure 11</i> and <i>Figure 12</i> show typical curves. PLL1 renamed to PLL.</p> <p>I<sub>DD</sub> supply current in Stop mode modified in <i>Table 16: Typical and maximum current consumptions in Stop and Standby modes</i>.</p> <p><i>Figure 10: Typical current consumption in Stop mode with regulator in Run mode versus temperature at different V<sub>DD</sub> values</i>, <i>Figure 12: Typical current consumption in Standby mode versus temperature at different V<sub>DD</sub> values</i> and <i>Figure 12: Typical current consumption in Standby mode versus temperature at different V<sub>DD</sub> values</i> updated.</p> <p><i>Table 17: Typical current consumption in Run mode, code with data processing running from Flash</i>, <i>Table 18: Typical current consumption in Sleep mode, code running from Flash or RAM</i> and <i>Table 19: Peripheral current consumption</i> updated.</p> <p>f<sub>HSE_ext</sub> modified in <i>Table 20: High-speed external user clock characteristics</i>.</p> <p>Min PLL input clock (f<sub>PLL_IN</sub>), f<sub>PLL_OUT</sub> min and f<sub>PLL_VCO</sub> min modified in <i>Table 27: PLL characteristics</i>.</p> <p>ACC<sub>HSI</sub> max values modified in <i>Table 24: HSI oscillator characteristics</i>. <i>Table 31: EMS characteristics</i> and <i>Table 32: EMI characteristics</i> updated. <i>Table 42: SPI characteristics</i> updated.</p> <p>Modified: <i>Figure 23: I<sup>2</sup>S slave timing diagram (Philips protocol)<sup>(1)</sup></i>, <i>Figure 24: I<sup>2</sup>S master timing diagram (Philips protocol)<sup>(1)</sup></i> and <i>Figure 26: Ethernet SMI timing diagram</i>.</p> <p>BGA100 package removed.</p> <p><i>Section 6.2: Thermal characteristics</i> added. Small text changes.</p> |

Table 63. Document revision history (continued)

| Date        | Revision | Changes  |
|-------------|----------|--|
| 14-Sep-2009 | 4        | <p>Document status promoted from Preliminary data to full datasheet.</p> <p>Number of DACs corrected in <a href="#">Table 3: STM32F105xx and STM32F107xx family versus STM32F103xx family</a>.</p> <p><a href="#">Note 4</a> added in <a href="#">Table 5: Pin definitions</a>.</p> <p><math>V_{\text{RERINT}}</math> and <math>T_{\text{Coff}}</math> added to <a href="#">Table 12: Embedded internal reference voltage</a>.</p> <p>Values added to <a href="#">Table 13: Maximum current consumption in Run mode, code with data processing running from Flash</a>, <a href="#">Table 14: Maximum current consumption in Run mode, code with data processing running from RAM</a> and <a href="#">Table 15: Maximum current consumption in Sleep mode, code running from Flash or RAM</a>.</p> <p>Typical <math>I_{\text{DD\_VBAT}}</math> value added in <a href="#">Table 16: Typical and maximum current consumptions in Stop and Standby modes</a>.</p> <p><a href="#">Figure 9: Typical current consumption on <math>V_{\text{BAT}}</math> with RTC on vs. temperature at different <math>V_{\text{BAT}}</math> values</a> added.</p> <p>Values modified in <a href="#">Table 17: Typical current consumption in Run mode, code with data processing running from Flash</a> and <a href="#">Table 18: Typical current consumption in Sleep mode, code running from Flash or RAM</a>.</p> <p><math>f_{\text{HSE\_ext}}</math> min modified in <a href="#">Table 20: High-speed external user clock characteristics</a>.</p> <p><math>C_{\text{L1}}</math> and <math>C_{\text{L2}}</math> replaced by C in <a href="#">Table 22: HSE 3-25 MHz oscillator characteristics</a> and <a href="#">Table 23: LSE oscillator characteristics (<math>f_{\text{LSE}} = 32.768</math> kHz)</a>, notes modified and moved below the tables. <a href="#">Note 1</a> modified below <a href="#">Figure 15: Typical application with an 8 MHz crystal</a>.</p> <p>Conditions removed from <a href="#">Table 26: Low-power mode wakeup timings</a>.</p> <p>Standards modified in <a href="#">Section 5.3.10: EMC characteristics on page 50</a>, conditions modified in <a href="#">Table 31: EMS characteristics</a>.</p> <p>Jitter maximum values added to <a href="#">Table 27: PLL characteristics</a> and <a href="#">Table 28: PLL2 and PLL3 characteristics</a>.</p> <p><math>R_{\text{PU}}</math> and <math>R_{\text{PD}}</math> modified in <a href="#">Table 35: I/O static characteristics</a>.</p> <p>Condition added for <math>V_{\text{NF(NRST)}}</math> parameter in <a href="#">Table 38: NRST pin characteristics</a>. Note removed and <math>R_{\text{PD}}</math>, <math>R_{\text{PU}}</math> values added in <a href="#">Table 45: USB OTG FS DC electrical characteristics</a>.</p> <p><a href="#">Table 47: Ethernet DC electrical characteristics</a> added.</p> <p>Parameter values added to <a href="#">Table 48: Dynamics characteristics: Ethernet MAC signals for SMI</a>, <a href="#">Table 49: Dynamics characteristics: Ethernet MAC signals for RMII</a> and <a href="#">Table 50: Dynamics characteristics: Ethernet MAC signals for MII</a>.</p> <p><math>C_{\text{ADC}}</math> and <math>R_{\text{AIN}}</math> parameters modified in <a href="#">Table 51: ADC characteristics</a>. <math>R_{\text{AIN}}</math> max values modified in <a href="#">Table 52: <math>R_{\text{AIN}}</math> max for <math>f_{\text{ADC}} = 14</math> MHz</a>.</p> <p><a href="#">Table 55: DAC characteristics</a> modified. <a href="#">Figure 33: 12-bit buffered /non-buffered DAC</a> added.</p> <p><a href="#">Table 62: Applicative current consumption in Run mode, code with data processing running from Flash</a> added.</p> <p>Small text changes.</p> |

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